IDA MEMORANDUM REPORT M-424

EXCHANGE STANDARDS FOR ELECTRONIC PRODUCT DATA

ML Brei

October 1988

Prepared for
Office of the Assistant Secretary of Defense
(Producton and Logistics)

INSTITUTE FOR DEFENSE ANALYSES
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**EXCHANGE STANDARDS FOR ELECTRONIC PRODUCT DATA**

**ABSTRACT**

This report addresses the issue of whether or not a family of existing data exchange formats for electronics engineering data is sufficient to achieve integrated engineering environments for electronics design. Three formats, the Institute for Interconnecting and Packaging Electronic Circuits D-25x series (IPC-D-35x); the Initial Graphics Exchange Specification (IGES); and the Electronic Design Interchange Format (EDIF); one design language, the VHSIC Hardware Description Language (VHDL); and one proposed format, the Product Data Exchange Specification (PDES) are reviewed. The author concludes that there is a very real need for each of these formats for distinct applications. Overlaps among the formats do exist. These overlaps, however, do not pose a serious impediment to exchanging engineering data.

A clear understanding of the informational content of each of the formats is needed. This cannot be achieved, however, until basic research questions regarding data modeling methodologies for engineering design data have been resolved.
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ML Brei

October 1988

INSTITUTE FOR DEFENSE ANALYSES
Contract MDA 903 84 C 0031
Task T-B6-455
PREFACE

The work presented in this memorandum report is part of the project undertaken by the Institute for Defense Analyses (IDA) in response to Task Order T-B6-455, Technical Support for the RAMCAD Software Development Program (defined in PRDA #86-16-PMRS), under contract number MDA 903 84 C 0031.

The basic work reported here was completed in June 1987 and represents the state of the world at that time.

This report was reviewed by Mr. David A. Dierolf and Dr. Karen J. Richter of IDA and by Mr. Donald Hall with the DoD Weapons Support Improvement and Analysis Office.
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<td>Air Force Logistics Command</td>
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<td>ANSC</td>
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<tr>
<td>ANSI</td>
<td>American National Standards Institute</td>
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<tr>
<td>ASME</td>
<td>American Society of Mechanical Engineers</td>
</tr>
<tr>
<td>ATF</td>
<td>Advanced Tactical Fighter</td>
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<tr>
<td>B-REP</td>
<td>Boundary Representation Solids Model</td>
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<td>CAD</td>
<td>Computer-Aided Design</td>
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<td>CAE</td>
<td>Computer-Aided Engineering</td>
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<tr>
<td>CAI</td>
<td>Computer-Aided Instruction</td>
</tr>
<tr>
<td>Cal Poly</td>
<td>California State Polytechnic University at Pomona</td>
</tr>
<tr>
<td>CALS</td>
<td>Computer-Aided Acquisition and Logistics Support System</td>
</tr>
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<td>CAM</td>
<td>Computer-Aided Manufacturing</td>
</tr>
<tr>
<td>CAM-I</td>
<td>Computer-Aided Manufacturing - International</td>
</tr>
<tr>
<td>CASE</td>
<td>Computer-Aided Software Engineering</td>
</tr>
<tr>
<td>CAT</td>
<td>Computer-Aided Technology</td>
</tr>
<tr>
<td>CIDF</td>
<td>Common Interchange Description Language</td>
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<tr>
<td>CIIN</td>
<td>CAD/CAM Integrated Information Network</td>
</tr>
<tr>
<td>CLSI</td>
<td>CAD Language Systems, Inc.</td>
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<tr>
<td>CSG</td>
<td>Constructive Solid Geometry</td>
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<td>DASS</td>
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</tr>
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<td>DoD</td>
<td>Department of Defense</td>
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<tr>
<td>EAC</td>
<td>IGES Electrical Applications Committee</td>
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<td>EDA</td>
<td>Electronic Design Automation</td>
</tr>
<tr>
<td>EDIF</td>
<td>Electronic Design Interchange Format</td>
</tr>
<tr>
<td>EIA</td>
<td>Electronics Industry Association</td>
</tr>
<tr>
<td>EIS</td>
<td>Engineering Information System</td>
</tr>
<tr>
<td>Acronym</td>
<td>Full Name</td>
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<td>---------</td>
<td>-----------</td>
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<tr>
<td>FEM</td>
<td>Finite Element Analysis</td>
</tr>
<tr>
<td>GAIL</td>
<td>Gate Array Interface Language (Daisy)</td>
</tr>
<tr>
<td>ICAM</td>
<td>Integrated Computer-Aided Manufacturing</td>
</tr>
<tr>
<td>IDA</td>
<td>Institute for Defense Analyses</td>
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<td>IDEF1-x</td>
<td>ICAM Definition Language Extended</td>
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<td>IDL</td>
<td>Interface Description Language</td>
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<td>IEEE</td>
<td>Institute for Electronics and Electrical Engineers</td>
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<td>IEEE/CS</td>
<td>IEEE Computer Society</td>
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<td>IGES</td>
<td>Initial Graphics Exchange Specification</td>
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<td>IMAR</td>
<td>Institute for Manufacturing and Automation Research</td>
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<tr>
<td>IPC</td>
<td>Institute for Interconnecting and Packaging Electronic Circuits (formally Institute for Printed Circuits)</td>
</tr>
<tr>
<td>ISO</td>
<td>International Standards Organization</td>
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<td>NSIA</td>
<td>National Security Industrial Association</td>
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<td>OSD</td>
<td>Office of the Secretary of Defense</td>
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<tr>
<td>PDES</td>
<td>Product Data Exchange Specification</td>
</tr>
<tr>
<td>RAMCAD</td>
<td>Reliability, Availability, and Maintainability in Computer-Aided Design</td>
</tr>
<tr>
<td>R,M&amp;S</td>
<td>Reliability, Maintainability, and Supportability</td>
</tr>
<tr>
<td>RTI</td>
<td>Research Triangle Institute</td>
</tr>
<tr>
<td>SAE</td>
<td>Society of Automotive Engineers</td>
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<tr>
<td>SCRA</td>
<td>South Carolina Research Authority</td>
</tr>
<tr>
<td>SET</td>
<td>Standard D'Échange et de Transfert</td>
</tr>
<tr>
<td>STEP</td>
<td>Standard for the Exchange of Product Data</td>
</tr>
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<td>TDF</td>
<td>Technology Description File (Motorola)</td>
</tr>
<tr>
<td>TIDAL</td>
<td>Transportable Integrated Design Automation Language (Texas Instruments)</td>
</tr>
<tr>
<td>TISSS</td>
<td>Tester Independent Software Support System</td>
</tr>
<tr>
<td>ULCE</td>
<td>Unified Life Cycle Engineering</td>
</tr>
<tr>
<td>VASG</td>
<td>VHDL Analysis and Standardization Group</td>
</tr>
<tr>
<td>VHDL</td>
<td>VHSIC Hardware Description Language</td>
</tr>
<tr>
<td>VHSIC</td>
<td>Very High Speed Integrated Circuit</td>
</tr>
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</table>
EXECUTIVE SUMMARY

To share information among automated engineering design tools, a basis for the creation and use of data interfaces is required. One segment of the community interested in building integrated design environments, the electronics industry, has responded to this need by developing neutral exchange standards for electronic product data. Currently, there are four established standards, each distinct from the others, which can be used to transfer data among automated tools for designing and fabricating electronic products. These standards, the Institute for Interconnecting and Packaging Electronic Circuits D-35x series (IPC-D-35x); the Initial Graphics Exchange Specification (IGES); the Electronic Design Interchange Format (EDIF); the VHSIC Hardware Description Language (VHDL); and the proposed Product Data Exchange Specification (PDES) have been developed or are under development by independent groups to achieve data interface standards for distinct applications. As each of these standards evolves, however, the users of the standards demand extensions which go beyond the original domains of the standards. As a result of a lack of communication among these independent efforts, the domains of these standards now overlap.

DoD, IEEE, ANSI, and EIA representatives recognize the need for cooperation among these standards groups to resolve the overlap issue. Efforts to coordinate the evolution of the standards are underway. Effective coordination will depend on a clear understanding of the technical and political problems.

Until coordination is achieved, designers of integrated design engineering environments will continue to choose which standard or set of standards is the most appropriate for their integration needs. This choice is not simple. All of the standards represent some subset of product data. To rigorously define these subsets, a thorough analysis of the representational capabilities of the standards is needed. To achieve this understanding, the informational context of each standard in question needs to be modeled. There are not, however, at the present time adequate methodologies to fully model engineering product data. Current information modeling techniques have been derived from business applications and are severely limited in their capability to represent the
complex and ambiguous data that is generated throughout the life cycle of product development.

Fundamental research questions regarding the representation of engineering product data must be resolved.
Figure ES-1. Timeline of CAE Standards Milestones
I. INTRODUCTION

Much work has been accomplished in the last several years toward the development of exchange formats for electronic product data. There are currently four industry formats in use today. Although the data formats are designed to serve as interfaces among application-specific automated design tools and data bases, they are not consistent with one another. Now that these formats have been accepted to some degree by the electronics industry, many questions remain regarding the adequacy and application of these standards. The basic issue addressed in this report is whether this family of standards is sufficient to support open architectures for automated design environments.

A. PURPOSE

The Institute for Defense Analyses (IDA) recognized the need for a global and unbiased assessment of the current state of Computer-Aided Engineering (CAE) exchange standards to achieve integrated environments for CAE. This document is the result of a year-long study, conducted by IDA during fiscal year 1987. This study focused on determining whether or not the emerging CAE data exchange formats will support the integration needs of the Air Force's Unified Life Cycle Engineering (ULCE) program and the Reliability, Availability, and Maintainability in Computer-Aided Design (RAMCAD) program.

The opinions expressed in this report have been formed after extensive discussions with many of the key people who are involved in standards activities. The opinions do not necessarily reflect, however, those of the Air Force, IDA, or any of the various organizations cited in this report.

The information in this report reflects the state of the world as of June 1987.
B. THE NEED FOR EXCHANGE FORMAT ANALYSIS

Both programs, ULCE and RAMCAD, concern the development of design engineering environments which integrate automated tools to improve the quality of a product throughout its life cycle. The objective of the ULCE program is to develop, demonstrate, and transfer to applications the techniques and technologies needed to provide advantageous, computerized integration of the procedures dealing with designing for producibility and designing for supportability with those dealing with designing for performance, cost, and schedule. (Implementation Plan for ULCE, February 1987)

The ULCE concept represents the future design environment.

The overall objective of RAMCAD is to unify reliability, maintainability, and supportability (R,M&S) aspects of the design early in the design cycle. It is a foundation of ULCE and supports the first Computer-Aided Acquisition and Logistics Support System (CALS) objective to integrate supportability analyses into the design process.

To understand why a comprehensive analysis of data exchange formats is needed to implement ULCE and RAMCAD concepts, several elements of CAE integration technology must be understood. These elements include open architectures, neutral exchange formats, product data, and format implementation considerations.

1. Open Architectures

Achieving RAMCAD and ULCE depends on technical and non-technical factors. A key technical problem is the design and implementation of open architectures (or "open systems") for design engineering environments.

Open architectures, in their fullest sense, provide a framework for integrating heterogeneous design tools and data bases in a cohesive environment. The key to open architectures are well-defined interfaces among the various elements of the environment. Basic elements of open architectures include:

(1) procedural access to databases and/or binary design files,
(2) documented ASCII design files,
(3) standard update and query facilities,
(4) distributed processing and data access facilities,
(5) design and file management facilities,
(6) process control,
version control, and
standard user interfaces.

A conceptual model of information requirements serves as the foundation for the open architecture by providing a precise, complete, and consistent definition of the information requirements. By correlating the data represented by neutral exchange formats with definitions of the conceptual schema, neutral exchange formats tie the basic elements of the open architecture together.

The CAE/CAD/CAM vendor community has been exploring the concept of open architectures for the past few years. Specific products which claim to provide open architecture engineering environments are being promoted in technical literature on a regular basis. For the most part, however, these products have a limited concept of open architectures. Usually this definition refers to the use of standard operating systems and standard platforms; limited support for neutral exchange formats; and the availability of database access routines and ASCII design files. Instead of providing mechanisms which make it possible to truly integrate (not simply attach) foreign tools into the system, these products offer front-to-back (functions for conceptual design through release to manufacturing) proprietary design and analysis tools in an "integrated" environment with some hooks to link the proprietary tools to outside systems. An exception to this is a set of products recently released by a new silicon valley company, EDA Systems. Their products are described as "a tool kit for people to build CAD systems." (Richard Goering, "CAE Start-Up Focuses on Data Base Management") The utilities provided in this tool kit include distributed data base management, design management and version control, a graphics user-interface, and a generic electronic data base. Neither interface or data base translation tools, however, are provided. This product is a close approximation to the concept of a generic "shell" for integrating disparate design tools in a distributed environment. As such, it may represent a new direction that industry is taking to provide open architecture environments.

2. Neutral Exchange Formats

Neutral exchange formats serve a vital role in open architecture environments. They are physical descriptions of the information required for, or produced by, a particular application, thereby allowing automated tools to share data. Such formats, by definition, are not based on any specific tool or database. They are not proprietary, and they are
designed, developed, and supported by various segments of the user and vendor communities in the public domain.

To select the most appropriate neutral exchange format or set of formats for an open system, a comprehensive understanding of the representational capabilities and limitations of each exchange format is necessary. In other words, the "content" or the semantics of the format must be well understood. After identifying candidate formats for a particular set of tools, for example, one must determine what information the formats can handle, what information cannot be represented, what overlaps exist among the formats, what usability conventions exist, and what extensions are proposed for the format.

3. Product Data

Comparing and contrasting the semantics of data formats would be straightforward if all design data formats were based on a common definition of product data. Product data is all of the data necessary to describe a product throughout its entire life cycle. According to Bradford Smith in US and International Efforts in Product Data Exchange, it includes the geometry, topology, relationships, tolerances, attributes, and features necessary to completely define a component part or an assembly of parts for the purposes of design, analysis, manufacture, test, and inspection.

A recent statement in the Development Plan for a Product Data Exchange Specification (by D. Appleton Co.) describes product data as: "Limited to data that describe the functional and physical characteristics of each unit of a product throughout its life from requirements at inception to its configuration at time of retirement." The vernacular underlying each format, however, is unique to the community responsible for the development of the format. A "signal" in the VHSIC Hardware Description Language (VHDL), for example, has a different meaning than a "signal" in the Electronic Design Interchange Format (EDIF).

Figure I-1 is an illustration of the relationship between a common definition of product data and data exchange formats. This chart was developed to explain the role of a conceptual schema for shared product data. A conceptual schema, in theory, provides the meanings with which facts are interpreted. For instance, if the fact, "8506," is associated with the meaning "house number," then a datum has been established. That datum, associated with a specific need, can be considered information. This issue is described in further detail in Chapter IV.
4. Format Implementation Considerations

To assess the practicality of implementing a particular neutral exchange format, several important considerations must be made. First, it is necessary to understand the "packaging details" of the format. The term "packaging details" refers to the syntax of the format, or the way in which the data is structured. Typically the syntax of a format reflects the programming paradigm at the time the format was conceptualized. For instance, the IPC-D-350 format was designed when data was structured for storage on card images. Consequently, the IPC-D-350 format matches the ASCII fixed field card image. Syntax impacts the following characteristics of the format:

1. the amount of redundant data maintained in each design file,
2. the size of the design files,
3. the lexical flexibility of the format (the complexity of processing necessary to parse [read] and produce a design file),
4. the extensibility of the format (the extent to which new semantic concepts be incorporated into the format without jeopardizing upward compatibility),
5. the ability to verify data consistency,
6. the ability to read and/or manually edit the data, and
7. the ability to store incomplete design data.
Other considerations impacting the practicality of a format are based on prospects for the ongoing support and/or evolution of the format. It is not reasonable to implement a neutral format for open system environments which may be abandoned by industry after a short lifetime. Indicators to monitor include:

1. the extent and nature of user support,
2. the extent and nature of vendor support,
3. ongoing activities of the development group,
4. international support (European and Japanese)
5. the existence of test and validation plans,
6. the availability and quality of documentation and user implementation guidelines,
7. the organizational structure and procedures for managing the evolution of the format,
8. national and international standardization activities (such as IEEE, ANSI, EIA, ISO, and IEC), and
9. the extent of DoD support (directly in terms of funding and manpower, and indirectly in terms of contractual requirements).

Chapter II compares these and other features of the leading CAE data exchange formats.

C. THE STUDY METHODOLOGY

There are many categories of standards necessary for the full implementation of ULCE, RAMCAD, CALS, and other programs dedicated to the development of integrated design environments. For instance, the technical standards for the CALS Core Requirements Specifications are grouped into five major categories: media, communications, transaction management, data management, and interface (see Figure 1-2). Other examples of standards classifications are provided in Figures 1-3 through 1-5.

The focus of this study is on neutral exchange formats for electronic product design data (also referred to as electronics data exchange standards). These standards are a subset of product data standards. In CALS documents, it is a subcategory under the interface category. Although this group of standards is less mature than others, it is critical to CAE/CAD integration. The type of information incorporated into these formats include all of the data contained on a circuit schematic and the corresponding physical layout.
Figure I-2. Technical Standards for the CALS Core Requirements Specifications


Figure I-3. An Early Classification Scheme for CALS Standards
### Figure I-4. Another Early View of the Standards Required for CALS

<table>
<thead>
<tr>
<th>Database Stds</th>
<th>Data Dictionary</th>
<th>Distributed DB Architectures</th>
</tr>
</thead>
<tbody>
<tr>
<td>Communication Stds</td>
<td>ISO OSI Implementation Stds</td>
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<tr>
<td>Product Definition Stds</td>
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<td>Graphics Stds</td>
<td>Image Archival Stds</td>
<td>NAPLPS</td>
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### Figure I-5. A Working Classification of the CALS Standards

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<th>Product Data</th>
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<th>EDIF</th>
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<td>SGML</td>
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</tr>
<tr>
<td>Data Management</td>
<td>SOL</td>
<td>NDL</td>
<td></td>
</tr>
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<td></td>
<td>IRDS</td>
<td>DDF</td>
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<td></td>
<td>ASN.1</td>
<td></td>
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</tr>
<tr>
<td>Communications</td>
<td>GOSIP</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Raster</td>
<td>CCITT Recommendation T.6</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

Source: "NBS Plan for Validation of Computer Products in Support of the CALS Program," 2 Jun 87, Edited by Sharon J. Kemmerer, NBS
The first task of the study was to identify the leading data exchange formats for electronic design data. Three existing formats, one emerging format, and one design language were identified: the Electronic Design Interchange Format (EDIF), the Initial Graphics Exchange Specification (IGES), the Institute for Interconnecting and Packaging Electronic Circuits (IPC) D35x series, the Product Data Exchange Specification (PDES), and the VHSIC Hardware Design Language (VHDL), respectively.

After contacts were established with the key figures involved in the development of these formats and participation on various key committees, it became possible to track the progress of each development effort. These contacts provided historical perspectives as well as current assessments of industry’s views regarding: (1) the current and future viability of these formats, (2) the technical functionality of the formats, and (3) new approaches to integrating heterogeneous design tools.

Early in the investigation, the criticality of the interoperability/overlap issue became apparent. Although each of the formats named above was developed for a very specific application or set of applications, subsequent enhancements have led to overlaps in the representational capabilities among these formats. There are no established procedures for using these formats together or resolving these overlaps. This has resulted in much debate regarding whether these formats are competing or complementary.

There are many potential solutions to the overlap controversy. One solution is to secure an agreement among all involved in the development, standardization, and promulgation of the formats to define and adhere to specific scope boundaries for each of the formats. Another solution is to define interfaces among the formats without a rigorous definition of the commonalities among these formats. A third solution is to develop one standard suitable for all applications to replace the existing standards. Finally, after precisely defining areas of overlap, these overlaps could be used as bridges from one format to the next. Each of these possible solutions has a different implementation timetable and different probability of success. These factors are discussed in Chapter III, Section D.

The investigation led to the discovery of three independent efforts in which attempts are being made to coordinate the interoperability of the standards. These coordination efforts are driven by the assumption that these formats are complementary (not competing) and are seeking solutions to ensure their coexistence. Although the efforts are in the information-gathering/planning stage, it appears as though each effort will be formulating a
unique approach to solve the problem. These coordination efforts are described in Chapter III.

Chapter IV expands on the role of data modeling in the analysis of the semantic content of the exchange formats, and describes the manner in which two modeling projects tested these ideas. By participating on a modeling team which was attempting to develop a conceptual model for electronic product data, an in-depth understanding of a popular modeling methodology and the actual model under production was attained. This participation provided the background necessary to assess the future uses of the model and the applicability of the modeling methodology to engineering design data and CAE exchange formats.

This study was necessary to tie together the various goals and perspectives of diverse groups involved in developing solutions to the CAE/CAD data exchange problem. The results lay a foundation upon which an understanding of the critical issues can be based and solutions can be proposed.

Throughout this study, numerous documents and articles were collected. A listing of this library of Supporting Material appears at the end of Chapter IV.

The appendices and supporting materials listed in this document are meant for supplementary purposes only. The appendices and supporting materials are trip reports, meeting reports, memorandums, briefings, and other related materials delivered to the Institute for Defense Analyses in support of this project.

D. TERMINOLOGY

The Computer-Aided Engineering (CAE) formats described in this study are guidelines for exchanging data. These guidelines consist of a defined syntax (rules for the formulation of sentences or statements in the language) and semantics (meanings ascribed to statements in the language). They do not necessarily impose constraints on the design of the interface. In other words, they do not provide detailed specifications of what needs to be done to build an interface.

The words "format," "standard," "specification," and "guideline" are given many interpretations. This is a terminology problem. Throughout this document, "format" denotes a static data structure definition. Formats are guidelines for structuring or representing information. Guidelines provide very general directions for representing data. Formats which have been in use for an adequate period of time, have been accepted by a
wide range of users, and have been proven to be relatively stable are referred to as "standards." Standards are less general than guidelines and provide more detailed recommendations for creating the representation for a particular application. A "specification" is a detailed procedure which defines what needs to be done to create an interface using standards (or formats). Specifications provide precise definitions of the nuts and bolts required to get the job done.

A "language" defines both a dynamic and static syntax and semantics with which procedural descriptions may be written. The dynamic language constructs (statements) are executable. The static language constructs are comparable to a format.

Other terms will be defined as they are used.
II. A COMPARISON OF THE CAE EXCHANGE FORMATS

This section contains descriptions and comparisons of the leading exchange formats for electronic product data. The formats under comparison are:

1. the Institute for Interconnecting and Packaging Electronic Circuits (IPC) D-35x Series
2. the Initial Graphics Exchange Specification (IGES),
3. the Electronic Design Interchange Format (EDIF),
4. the VHSIC Hardware Description Language (VHDL), and
5. the Product Data Exchange Specification (PDES).

Comparisons will include purpose, history, goals, application areas, information coverage, funding source, industry support, file format, and future prospects. The purpose of this section is to set forth generalizations about the similarities and differences among these formats. This is not a tutorial on the technical aspects of the formats. Throughout this section, references will be made to sources which provide technical details. Appendix L, "CAE Standards Coordination Meeting Report," discusses the individual standards from the perspective of the leaders of each of the efforts. The information in this section serves as background material for the remaining sections. Table II-1 is a summary of the basic information.

A. PURPOSE

Each standard under comparison was designed to solve a particular problem, and the original scopes of each addresses a specific need. As the standards have matured, however, these domains of applicability have grown beyond the original scopes.

The IPC-D-35x series is a set of neutral exchange formats to transmit printed board descriptions between designers and manufacturers. The original purpose of the project was to "develop a replacement for the document known as the Master Drawing with a magnetic tape that had all the same information." (Dieter Bergman, "Long Range Plan for an Electrical Computer Format Standardization Effort") The range of data represented has
<table>
<thead>
<tr>
<th></th>
<th>EDIF 2.0</th>
<th>IGES 3.0</th>
<th>IPC-D-35X</th>
<th>PDES</th>
<th>VHDL</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Purpose</strong></td>
<td>IC Design Data Exchange</td>
<td>Graphical and Product Def. Data Exchange</td>
<td>Printed Board Description Data Exchange</td>
<td>Product Data Exchange</td>
<td>Digital Design Data Exchange and System Behavioral Description</td>
</tr>
<tr>
<td><strong>Founders</strong></td>
<td>Motorola, T.I., Daisy, Mentor, Nat. Semiconductor, Berkeley, Tektronix</td>
<td>Boeing, NBS, G.E.</td>
<td>IPC Member Companies</td>
<td>IGES Members</td>
<td>USAF VHSIC Contractors Intermetrics, IBM, T.I.</td>
</tr>
<tr>
<td><strong>Precursors</strong></td>
<td>CIDF, GAIL, TDF, TIDAL</td>
<td>Boeing CIIIN; G.E. Neutral Database</td>
<td>IGES, ANSI-SPARC 3-SCHEMA Concept, PDDI, SET, VDAFS</td>
<td>Ada and Existing HDL</td>
<td></td>
</tr>
<tr>
<td><strong>Application Area</strong></td>
<td>IC and PCB Design, Manufacturing and Testing</td>
<td>Drafting; Mechanical Design; FEM; PCB Design Man. and Test; Architecture, Engin. and Cons.</td>
<td>PCB Design, Manufacture and Test</td>
<td>Mechanical and Electrical Products; Distribution System; FEM; Solids Modeling; Curve and Surface Model</td>
<td>System Design, Circuit and Physical Design, Test Description, Unit Under Test</td>
</tr>
<tr>
<td><strong>Funding Source</strong></td>
<td>Consortium of Founders</td>
<td>USAF ICAM Pgm</td>
<td>IPC</td>
<td>IGES Organization</td>
<td>USAF VHSIC Program</td>
</tr>
</tbody>
</table>
been subsequently broadened to include electrical documentation, electrical associativity, numerical control formats, and standard test data formatting. The D-35x formats are functionally-oriented, rendering them both human-readable and machine-processable.

IGES is a neutral, device-independent data format for the exchange of graphical and other product definition data among present-day CAD systems. Initially, IGES was used to transfer the "graphical representation of engineering drawings between disparate CAD systems." (Peter Wilson, "A View of PDES") This involved definitions for geometric, annotation, and structural data. The meaning of the data depended completely on human interpretation. The current version of IGES reflects substantial enhancements made to the capabilities of the format. These enhancements "reflect a desire to expand the specification's capability to communicate a wider range of product data developed and used by computer-aided design and manufacturing systems." (Bradford Smith, "U.S. and International Efforts in Product Data Exchange") The major capabilities of Version 3.0 still involve geometric models and drawings, although properties and associativities can now be used for product definition data to a limited extent. (W. C. Burkett, "Fast, Good, Cheap")

EDIF is a neutral, public domain, and machine-readable exchange format. The original purpose of EDIF was to provide a mechanism for exchanging integrated circuit (IC) data for semi-custom design between designers and gate-array foundries. The current version of EDIF, however, can be used for "information transfer at all levels of electronic design...from design capture and verification through layout, manufacture, and test of printed circuit boards and application-specific integrated circuits." (Henry Alward, "Latest EDIF Version Marks a Milestone for CAE/CAD")

VHDL is a language which supports the design, documentation, and simulation of digital circuits from the system level down to the gate level. Its purpose is twofold. First, it can serve as an interface among design tools by supporting the transmittal of digital design data among hardware component vendors, design engineers, and manufacturers. Secondly, it can document digital designs by providing the means "to unambiguously describe requirements and systems themselves in terms of behavior and structure." (Hal Carter, "Computer-Aided Design of Integrated Circuits") As a design language, it allows effective communication between a designer and a design tool. As a description language, it allows effective communication among design environments, both inter- and intra-company. (Ron Waxman, "The Many Faces of Electronic Computer-Aided Design")
PDES is a long-range concept. As of this writing, it is a volunteer research and development activity under the purview of the NBS IGES organization. Some believe it is also a standardization activity. The objective of this concept is to develop a neutral exchange capability for all product data between CAD/CAE/CAM/CAI systems. This capability has not been well-defined, but will probably consist of two components: "an information model which defines and explains how the data elements transmitted are to be interpreted and used...and the exchange format specification itself." (W. C. Burkett, "Good, Fast, Cheap") The prevailing goal of this project is to produce a representation of product data with adequate explicit meaning to allow complete interpretation of the data by the design system. In other words, "the results of this work will be a roadmap for building exchange standards which are easy to implement, precise, less ambiguous, and easily testable." (ML Brei, "CAE Standards Coordination Meeting Report")

All of the standards covered in this study share the following characteristics:

(1) the scope broadens as the format matures
(2) all were designed to be neutral, non-proprietary standards
(3) all represent some form of product data

The basic differences of these standards include:

(1) some require interpretation
(2) others are directly processable by design automation tests. Each was designed with a distinct application in mind.

B. HISTORY

It is important to have a basic understanding of the history of the standards development organizations. Knowledge of the forces driving the development of the formats, how the organizations were formed, and who was involved in the initial design activities provide insights into the nature of the format and future viability.

In 1967, the IPC formed a committee to "establish a digital language for describing the characteristics of a printed wiring board" (Bergman, "Long Range Plan for an Electrical Computer Format Standardization Effort") as a replacement for the master drawing. This was in response to a need expressed by military contractors. The first draft, D-350, was approved in 1972. Revision A of D-350 was released in February 1975 and approved as an ANSI standard in May 1975. Over 20 principle contributors were involved in the development and subsequent enhancements of this specification. The committee developed
supplemental specifications (351, 352, 353, and 354) to handle additional data requested by government representatives without breaking a commitment to freeze D-350 for five years. The current draft of D-350 is Revision C, released in July 1986. Both D-351 and D-352 were adopted in September 1985 and approved for use by DoD. The specifications D-353 and D-354 were released in draft form in 1986. The subcommittee on "IPC-D-350 Development," under the Committee on Computer-Aided Technology (CAT), is currently responsible for the development and maintenance of the D-35x specifications.

The IGES organization was founded at a meeting held on October 11, 1979, in response to a recommendation made by the DoD Manufacturing Technology Advisory Group. The meeting was convened by the Air Force, Army, Navy, NASA, and NBS at the National Academy of Sciences to discuss data exchange problems. The original Technical Committee, a small group from Boeing, General Electric, and the National Bureau of Standards, was formed at this meeting. The Technical Committee borrowed heavily from two projects: the Boeing CAD/CAM Integrated Information Network (CIIN) format and the General Electric Neutral Database project. Three months after the formation of the Technical Committee (January 1980), the first version of IGES was published by the National Bureau of Standards. In September 1981 it was approved as an ANSI standard by the ASME Committee Y14.26. After the publication of the first version, additional committees were formed and the IGES organization took shape. IGES 3.0 is in the final stages of approval by Y14.26 as an ANSI standard.

The IGES Electrical Applications Committee (EAC) was formed in January 1983. The purpose of the EAC was to recommend format extensions to handle integrated circuit applications (the design, engineering, manufacturing, and testing of both individual parts and the packaging of parts into a product). After creating an IDEF1-x data model of electrical connectivity, the EAC developed a physical implementation and presented it to the general assembly. These enhancements were accepted and incorporated in IGES version 3.0. (IGES 3.0, Electrical Application Guide)

The EDIF organization was formed in November 1983 as the result of general dissatisfaction with existing formats for IC design data. The founders of EDIF were from Texas Instruments, National Semiconductor, Motorola, the University of California at Berkeley, Tektronix, Daisy Systems, and Mentor Graphics. The founders had contributed toward the development of previous exchange formats and decided to leverage as much knowledge and experience as possible from those activities. Consequently, EDIF was based on concepts from CIDL (Common Interchange Description Language), GAIL
(Daisy's Gate Array Interface Language, TDF (Motorola's Technology Description File), and TIDAL (Texas Instruments' Transportable Integrated Design Automation Language). The founders identified four general problems with the existing formats. Each:

1. addresses a narrow focus,
2. is proprietary,
3. is difficult to implement, and
4. is difficult to extend.

An initial draft version, 0.8, was completed in March 1984. Subsequent versions (1.0 in March 1985; 1.10 in November 1985) have led to the release of the current version, 2.0, in July 1987. Version 2.0 is published by the Electronics Industries Association as an Interim Specification.

The Air Force Very High Speed Integrated Circuit (VHSIC) Program Office developed VHDL in response to a "need for a standard means of communication to streamline advanced digital design and documentation." (Dewey and Gadient, "VHDL Motivation") A team from Intermetrics, IBM, and Texas Instruments was formed to identify language requirements and to develop the language (from 1981 to 1983). This effort was directed by a VHDL Tri-Service Committee. After developing requirements for the language, the team was responsible for developing the language, providing a support environment, and providing software tools (a compiler, a reverse analyzer, a simplifier, and a simulator). The program was organized in four teams: the Requirements Analysis Team, the Definition Team, the Review Team, and the Scenarios and Benchmark Team. A draft of the VHDL was presented to potential users in February 1984. After revisions were made by an IEEE VHDL Analysis and Standardization Group (VASG), Draft 1076/B was approved by ballot in July 1987. The final approval from IEEE was established in December 1987. The programming language, Ada, had a significant impact on the language design, intermediate form, and support environment architecture. The VHDL Language Requirements document states "where the semantics of a VHDL construct match the semantics of an Ada construct then Ada syntax should be used." (pp. 5-6)

After recognizing that a non-upward compatible format was necessary to address the inherent problems limiting IGES, members of the IGES organization initiated the PDES Project. In April 1984, an ad hoc subcommittee was chartered to examine issues for an upcoming version of IGES. The committee recommended the development of a non-upward compatible version of IGES. In November 1984, the Ad Hoc Committee released
a report suggesting content and development methodology for the new format. The development methodology was based on a three-layer architecture (similar but not identical to database architectures), reference models (for each application), format definition languages, and a minimally redundant entity set.

A PDES proof-of-concept effort, the Initiation Activities, began in early 1985. This activity concentrated on validating the concepts and proposed methodology. It resulted in *A Reporting of the Initiation Activities*, released in May 1986, containing a "Plan for PDES Version 1.0," "Logical Layer Committee Report," "Physical File Structure Task Report," critiques, minority reports, and technical appendices. After the release of the *Reporting of the Initiation Activities*, PDES subcommittees continued working on reference models, the physical file structure, and other related projects. The work accomplished during this period can best be characterized as intense, yet unfocused. The *PDES Testing Draft*, released in February 1987, is evidence of the lack of a well-defined PDES strategy. The PDES Testing Draft consists of a set of four integrated reference models in the Express language. It is up to the reader of the document to determine what to do with the integrated model. Many problems with the organization of the PDES volunteer project have become apparent to both observers and participants of the effort, and the project is currently undergoing a major reorganization. A PDES Industry Cooperative (PDES, Inc.) is being organized to lead an accelerated development of PDES. This effort is being driven by the DoD CALS OSD Policy Office. The relationship between the volunteer effort, PDES, Inc., and other competing efforts is as of yet undetermined.

The timeline in Figure II-1 provides a reference for tracking the histories of the development of each of these standards. IPC-D-35x has been evolving for about 20 years. PDES, at the other extreme, is a three-year old effort. Similarities among the development efforts not recorded in the timeline include:

1. All sought extensive public comment/review
2. All have been or are in the process of being approved by a standardization body.
Figure II-1. Timeline of CAE Standards Organizations Milestones
Differences include:

(1) All but IPC were clearly leveraged from existing formats

(2) IGES, VHDL, and PDES were led by government agencies, whereas EDIF was initiated by an ad hoc industry consortium, and IPC-D-35x was a response to user needs.

The chart in Table II-2 summarizes the formation activities of the standards development groups.

Table II-2. The Formation of the Development Groups

<table>
<thead>
<tr>
<th></th>
<th>IPC-D-35X</th>
<th>IGES</th>
<th>EDIF</th>
<th>VHDL</th>
<th>PDES</th>
</tr>
</thead>
<tbody>
<tr>
<td>Founders</td>
<td>IPC Committee</td>
<td>Boeing, NBS, G.E. in response to DoD Mantech Advisory Group</td>
<td>Motorola, T.I., Daisy, Mentor, National Semiconductor, Tektronics, UC at Berkeley</td>
<td>USAF VHSIC Program; Contractors Intermetrics, IBM, T.I.</td>
<td>IGES ad hoc Committee</td>
</tr>
<tr>
<td>Precursors</td>
<td>?</td>
<td>Boeing CIIN G.E. Neutral Database</td>
<td>CIDF, GAIL, TDF, TIDAL</td>
<td>Ada and existing HDLs</td>
<td>IGES, SET, PDDI, VDAFS, CAD*I</td>
</tr>
</tbody>
</table>

C. DESIGN GOALS

All of these development efforts have been guided by a set of goals and/or guidelines. Some of these guidelines have been documented in project reports, others have been implied in articles written by principle contributors to the projects. These guidelines are outlined in this section.

IPC-D-35x Series

Early requirements (implied):

(1) The format must allow manual preparation of the data as well as CAD preparation.

(2) Establish a generic format "transparent to the various numerical control machines used in the development of artwork tooling, or for drilling and routing printed boards." ("Report of IPC Electronic Design Data Description Seminar," October 1985)
Development guidelines (implied):
(1) Maintain similarity among the D-35x series (modularity).
(2) Handle complete and partial design data.

**IGES**

Goals of the initial effort:
(1) Publish something by early 1980.
(2) Completeness: enable complete data exchange among computer-based drafting systems.
(3) Extensibility: allow for extensions to the format.
(4) Processor compatibility: allow for the use of existing translation techniques to process the format.
(5) Obtain and incorporate as much input as possible from the user community.

Principles guiding the ongoing development:
(1) Maintain upward compatibility.
(2) Ensure non-redundant entity sets (define an entity in one way).
(3) "Serve as a common format to drive internal manufacturing cycle, and external customers/vendors/suppliers."
(4) "In place, functioning, and usable (not blue sky)."  (*IGES Electrical Application Guide*)

**EDIF**

(1) Produce a standard within five years.
(2) Minimize talk, maximize work.
(3) Keep the syntax simple, consistent, unambiguous, and extensible.
(4) Maintain upward compatibility between releases.
(5) Do not make it a design language.
(6) EDIF will become a standard by use, not by edict.
(7) Keep the standard neutral and in the public domain.
(8) Handle partial and complete design data.
**VHDL**

Global contract objectives:

1. "The VHDL shall be capable of fully documenting digital hardware...ranging from entire systems to logical gates."
2. "...the VHDL will be used as a design and documentation tool."
3. "...the complexity of the language must be controlled...."

Design objectives (M. Shahdad, "An Overview of VHDL Language and Technology"):

4. Semantic precision
5. Methodology independence
6. Hierarchical description
7. Support for digital modeling techniques
8. Support for approaches to timing
9. Support for hardware technologies
10. Support for styles of description
11. Support for design automation tools.

**PDES**

Objectives defined by the Ad Hoc Committee:

1. Support both state-of-the-art and leading edge CAD/CAM environments.
2. Provide a clear and unambiguous specification.
3. Ensure the standard can be and is implemented.
4. Minimize the cost of building and using PDES processors.
5. Ensure that the transfer process is reliable and predictable.
6. Provide migration path from IGES to PDES.

A few of the requirements:

1. Minimize file size and processing time.
2. Accommodate functional capabilities of IGES 3.0.
3. Provide complete representation of product data.
4. Exchange and archive data in a computer recognizable form.

(P. Wilson, "A View of PDES")
Common development activity criteria includes:

1. extensibility,
2. upward compatibility,
3. machine processable systems,
4. human readable systems,
5. neutral, and
6. public domain.

These goals are very important; they flavor the evolution of the formats and have a tremendous impact on the success of the formats (both technically and politically). The extensibility design criterion ensures that mechanisms for expanding the format are in place to keep pace with technology advances. The upward-compatibility design criterion ensures that investments made in early versions of the format will not be lost. The machine-processable syntax design criterion ensures that writing translators to read and write the format will not require excessive effort. The human readable syntax criterion ensures that the data will always be accessible to human beings without computerized tools. The neutrality design criterion ensures that the standard is applicable for any appropriate tool and design environment. Finally, the public domain design criterion ensures the non-proprietary nature of the format.

D. APPLICATION AREAS

Table II-3 illustrates the application areas for which the standards are designed to be used.

E. INFORMATION COVERAGE

The following lists of information covered by each of the standards were composed after reviewing technical documents and other literature. The lists are generalized. The terms are not necessarily consistent among the formats. For example, an EDIF schematic is different from an IPC-D-35x schematic. It is impossible at this point to establish consistent lists because industry-accepted (standard) definitions of the information required and generated by CAE/CAD systems do not exist. A comprehensive comparison of the information coverage of these formats is impossible until such an information model is developed and accepted by the CAE/CAD industry.
<table>
<thead>
<tr>
<th>Application Areas</th>
<th>IPC-D-35X</th>
<th>IGES</th>
<th>EDIF</th>
<th>VHDL</th>
<th>PDES</th>
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<td>IC Design</td>
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<td>X</td>
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<tr>
<td>IC Testing</td>
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<td></td>
<td></td>
<td>X</td>
</tr>
<tr>
<td>IC Manufacturing</td>
<td></td>
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<tr>
<td>Printed Board Design</td>
<td>X</td>
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<tr>
<td>Printed Board Testing</td>
<td>X</td>
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<tr>
<td>Printed Board Manufacturing</td>
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<td>System Level Testing</td>
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<td>X</td>
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<td>System Level Manufacturing</td>
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<td>ELECTRICAL/MECHANICAL</td>
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<td>Component Design</td>
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<td>Component Manufacture</td>
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<td>MECHANICAL</td>
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<td>Part Design</td>
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<td>X</td>
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<td>Part Analysis</td>
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<td>Solids Modeling</td>
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<td>X</td>
</tr>
</tbody>
</table>

**IPC-D-351-352, 353, 354, 355**

- PCB artwork
- PCB Board descriptions
- Schematics
- Master drawings
- Assembly drawings
- Part drawings
- Netlists
- Parts definitions
- Design rules
- Test data
- Library information
- Mechanical tooling

**IGES 3.0**

- Netlist
- IC symbolic layout
- PCB layout
Schematics
Mechanical drawings (2- and 3-D wireframe)
Mechanical tooling
Photoplot
Process flowsheets
Finite element models
Tabular data

**EDIF 2.0**

Netlist
IC symbolic layout
PCB layout
Schematic
Simulation models
Timing information
Test patterns
Documentation
Hierarchical structure
Physical design rules

**VHDL 1076/B**

Behavioral description
Architectural description
Structural descriptions (hierarchical)
Timing data
Environmental data
Physical attribute data (placement, timing, power)
Schematic data (no semantics)
Layout data (no semantics)

According to these lists, the IPC-D-35x series and IGES appear to handle very similar data. The critical difference between IGES data and IPC-D-35x data is that IGES data basically consists of geometrical primitives which require interpretation, whereas IPC-D-35x data consists of functional primitives oriented toward the end-product, the printed circuit board.

The same difference exists between EDIF and IGES and between VHDL and EDIF with respect to schematic and layout data. In addition to the powerful constructs to describe behavior, VHDL provides some constructs for describing geometry. The meaning of the geometry, however, must be interpreted by the tools which process the data. The
constructs for this information in EDIF, however, are functional primitives oriented toward IC and PCB layout concepts.

The EDIF organization does not plan to incorporate all aspects of design. In particular, it will not represent 3-D mechanical drawings and analyses, nor will it represent system manufacturing level information and other system design language functions.

F. FUNDING SOURCES

The IPC-D-35x series are developed and supported by representatives from IPC member companies. IPC is a non-profit trade association with about 1,400 member companies, many of which are aerospace companies. The purpose of IPC is to develop standards and technical documentation for the electronic packaging industry.

IGES is a project of the Air Force Integrated Computer-Aided Manufacturing (ICAM) Program. Funds are provided to the National Bureau of Standards by the Air Force, Army, Navy, and NASA. The funds are used to manage the IGES organization.

EDIF does not have an official funding source other than the ad hoc consortium of founding companies which form the Steering Committee.

VHDL is a project of the Air Force VHSIC Program. A contract was awarded to a team from Intermetrics, IBM, and Texas Instruments for the initial development of the language. Subsequent funds were provided to CAD Language Systems, Inc. (CLSI) for administrative support of the IEEE/DASS standardization process, and to develop additional documentation. Documents and training are available from CLSI. Funds have been provided to various organizations for verification and validation support (the National Bureau of Standards, the United Technologies Microelectronics Center, and Digital Equipment Corporation.

PDES is an IGES project and receives funds accordingly. If PDES, Inc., is successful, then funding and manpower will be supplied by the 15-20 member companies of the Cooperative. The PDES Cooperative will be administered through a "host" contractor. Potential candidates for this task include Computer-Aided Manufacturing International (CAM-I), the South Carolina Research Authority (SCRA), Battelle, and the Institute for Manufacturing and Automation Research (IMAR). ("Draft Prospectus for an Industry/Government PDES Cooperative Project")
G. INDUSTRY SUPPORT

This section describes who is supporting the standards and the extent of that support. In many cases, it is difficult to assess the strength of the support claimed by the organizations. The chart in Table II-4 summarizes the international support, Department of Defense support, and the funding sources for each of the standards.

<table>
<thead>
<tr>
<th>International Support</th>
<th>IPC-D-350</th>
<th>IGES</th>
<th>EDIF</th>
<th>VHDL</th>
<th>PDES</th>
</tr>
</thead>
<tbody>
<tr>
<td>European Member Companies</td>
<td>Limited due to competition with the French SET and West German VDAFS</td>
<td>Extensive User Groups in Britain, West Germany, and Japan</td>
<td>Hindered by ITAR; Projects underway in Sweden, Canada, and England</td>
<td>ISO/STEP TC 184SC4 (members include Belgium, France, Canada, Japan, Poland, US, and West Germany)</td>
<td></td>
</tr>
<tr>
<td>DoD Support</td>
<td>Strong in Isolated Cases (NSA)</td>
<td>Strong</td>
<td>Pending: DoD CALS Policy Office has expressed interest</td>
<td>Strong</td>
<td>Strong</td>
</tr>
<tr>
<td>Funding Source</td>
<td>IPC Member Companies</td>
<td>USAF ICAM program funds provided by AF, Army, Navy, and NASA</td>
<td>Founding Companies; E1A Member Companies (Pending)</td>
<td>USAF VHSIC Program</td>
<td>Industry Cooperative (Pending)</td>
</tr>
</tbody>
</table>

The IPC-D-350 specifications are developed and supported by representatives from member companies, both U.S. and European. The principle user and force behind enhancements to the formats is the National Security Agency. These formats are more mature than the others covered in this report. Vendor implementations include Calay, Cadnetix, and Racal Redac. Current plans are to increase vendor support of the specifications. Although the specifications have been required on government contracts, printed board CAD vendors are not anticipating a large demand for the formats. Large aerospace companies, however, may request IPC-D-350 implementations in the near future. A user group was formed in 1986 to bring industry people together to discuss implementation, software, test and verification issues and vendor plans for support (William Lange, "IPC-350 Specifications")

The IGES organization is a voluntary body of representatives from the user community (for the most part) and the CAD community. The user community includes:
aerospace companies:
McDonnell Douglas, Boeing, Hughes, General Dynamics, Lockheed, Rockwell, Allied Bendix, LTV Aerospace, Northrop, Ford Aerospace;

automotive companies:
Ford Motor, GM, BMW;

equipment manufacturers:
IBM, DEC, Caterpillar, Westinghouse, Eastman Kodak, Hewlett Packard;

national laboratories:
Sandia, Lawrence Livermore;

academia:
MIT, California State University, University of Michigan, Duke; and the

military services.

Members from CAD vendors include Computervision, Applicon, Tektronix, Daisy, Ontologic, Scientific Calculations, Cadnetix, Calma, Intergraph, and Cognition. Most major CAD/CAM companies support some level of IGES. In a 1987 survey by CAD/CIM about 35 vendors reported some support for subsets of IGES entities. Only two vendors (CALMA and Summa Graphics) claimed to support the electrical entities. Most of those surveyed support the geometric entities. None of the vendors claimed to support all IGES entities. As of spring 1987, there were 628 members listed on the general membership roster and about 40 members on the Steering Committee. Of the 628 members, 8 percent are foreign, 26 percent are vendors, and 2 percent are from academia. Over 260 companies are represented. The number of attendees at quarterly meetings range from 200 to 250. European support for IGES has been severely hindered by the French acceptance of SET (a streamlined version IGES) and the German acceptance of VDAFS (another derivative of IGES).

The EDIF organization is composed of volunteers from the

CAE/CAD vendor community:
Daisy, Mentor, Valid, Tektronix, Cadnetix, Viewlogic, Racal Redac, Calma, Computervision, SDA Systems, Futurenet, Xerox, and Hewlett Packard;
IC design and manufacturing community:
Motorola, National Semiconductor, Intel, Texas Instruments, and T&T Bell Laboratories, IBM; and

academia:
the University of California at Berkeley, the University of Arizona, the University of Manchester, and the University of Waterloo.

Several EDIF user groups have been formed in the last year (in the United States, Britain, West Germany, and Japan). Approximately 200 people attend the general user group meetings held at the ICCAD conferences in the fall and the Design Automation Conferences held in the spring. Over 2,000 names are on the EDIF mailing list, 500 of which are from Europe or Japan. There are currently 11 U.S. technical subcommittees with active memberships ranging from 6 to 20 people. DoD is beginning to show interest in the format. The OSD CALS Policy Office is considering the inclusion of EDIF in the Core Requirements Specifications.

A number of trial implementations of subsets of EDIF have been available since the release of version 1.0. At the release of Version 2.0, at least a dozen vendors committed to the development of EDIF-based products, and another dozen vendors expressed interest pending customer demand. The first 2.0-based products will probably be EDIF netlist and schematic interfaces. These should appear within 6 months to 2 years.

Non-U.S. support for EDIF is growing rapidly. In 1985, the United Kingdom CAE Consortium "concluded that the EDIF format met its requirements and that it would therefore be better to work with the U.S. and the rest of Europe to support EDIF than to develop its own language." ("European IC Designers Vote for EDIF Standard") Britain's Alvey fifth-generation computer project has also demonstrated strong support and has made significant contributions to the development of the format by funding the development of information models, translators and other software utilities, and trial transfers. There are several European technical subcommittees which make recommendations to the U.S. organization. British, West German, and Japanese User Groups have also formed. Japan has recently formalized an interest in EDIF. "Fujitsu and Hitachi foundries are publishing requirements for future design information to be presented in EDIF formats." (Henry Alward, "Latest EDIF Version Marks a Milestone for CAE/CAD")
The support for **VHDL** has been driven by the development effort, the standardization process, and demonstration programs funded by the Air Force. According to John Hines (Appendix L),

CAE/CAD companies:

ENDOT, Daisy, Hewlett Packard, Mentor, Silvar-Lisco, CLSI, Intermetrics;

equipment and machine manufacturers:

General Dynamics, Boeing, Sperry, IBM, Honeywell, Gould, Unisys, TRW; and

universities and research organizations:

Stanford, Virginia Tech, Renssellaer Polytech, Dartmouth, JRS Research, Research Triangle Institute, and Arizona State University

participated in the development effort. The activities of the IEEE/Design Automation Standards Subcommittee have also generated strong interest within the design community. The VHDL mailing list contains about 200 names. An informal VHDL Users Group has been meeting at VPI. VHDL workshops and training classes are being offered on a regular basis to generate interest and expertise in VHDL.

Moe Shahdad in "An Overview of VHDL Language and Terminology" (July 1986) reports on the following activities which involve VHDL: the IBM/VHDL environment, Sperry Corporations' VHDL interface to the MIXSIM simulator, a bi-directional translator between VHDL and HHDL by Silvar-Lisco, design capture tools by Gould Research Center, a VHDL-ADAS interface by Research Triangle Institute (RTI), a silicon compiler by RTI, Silicon Compilers, and E-Systems, a microcode simulation system by JRS Research Laboratories, the MIMOLA Software System by Honeywell, and the Tester Independent Software Support System (TISSS) by Harris.

International Traffic in Arms Regulations (ITAR) which covered the VHSIC program prohibited non-U.S. participation in the initial design of VHDL. Documentation was not available outside the VHSIC community. Although ITAR restrictions were lifted two years ago, this will have a major impact on whether or not VHDL will be accepted as an International Standard. (Dr. T. L. Throp, in a letter to R. Waxman, March 1986) Some proponents of VHDL have reported that the European design automation community is expressing much interest in VHDL, especially in France. Specific international programs are occurring in Sweden (NMP-CAD adopted VHDL as a basis for design description),
Canada (BNR is retesting a VHDL interface on the IBM), and England (Plessey is creating a VHDL interface to their workstations).

The contributors to the PDES project are members of the IGES organization. The anticipated user community of PDES will be predominantly from the aerospace and defense industries. DoD (the CALS program and advanced weapon systems programs) and the International Standards Organization (ISO) Standard for the Exchange of Product Data (STEP) project are also promoting and contributing to PDES. Specific programs which are depending on PDES include: CALS, the AFLC CAD/CAM Integration PIM, the USAF ATF, and the Navy CAD II CAD/CAM procurement. PDES is not ready for implementation at this time. I do not know of any complete PDES proof-of-concept demonstrations with the exception of the Initiation Activities (see above).

H. FILE FORMAT

The IPC-D-35x formats are static data structures based on an 80-column card image ASCII format with specific field-oriented records. Reserved words, letters, and codes provide meaning.

Designs are organized in job sets. Within a job set, data is structured in data information modules. Types of data information modules include electrical description, artwork, boards, schematic, master drawing, assembly drawing, etc.

Discrete units of information are stored in individual files. For instance, there may be a file for plated-through holes, for lands, for conductor patterns, etc.

IGES is a static file structure based on an 80-column record format. The data is numerically coded in fixed and free format lines. The file can be formatted according to ASCII, compressed ASCII, or binary specifications.

IGES files contain basic information units called entities. Entities can be either geometric or non-geometric. Non-geometric entities provide annotation, dimensioning, attribute, and grouping capabilities. Entities are organized in five or six sections: Flag, Start, Global, Directory, Entry, Parameter Data, and Terminate. Relationships can be established among entities, meanings can be assigned to relationships, and specific characteristics can be assigned to entities.

Changes to IGES involve modifications of existing entity structures, the introduction of new entity structures, and/or the obsolescence of entities.
**EDIF** is a non-executable, ASCII data format patterned after LISP. Data in EDIF files are organized hierarchically in the form of EDIF statements. EDIF statements are parenthesized lists identified with a keyword. The semantics are based on keyword definitions. The keywords are defined in the EDIF specification.

The basic design unit in EDIF is called a cell. A cell can have one or more representations or views. Each view contains a particular perspective of the design. For instance, the electrical connectivity of a circuit is established in the Netlist view. Other views include Behavior, Document, Graphic, LogicModel, Masklayout, Netlist, PCBLayout, Schematic, Stranger, and Symbolic.

Extensions to EDIF are made by defining new keywords. The EDIF Technical Committee has established a set of general rules for extending EDIF in the future to ensure upward compatibility.

**VHDL** is a hierarchical design language patterned closely after Ada. It has a context-free syntax and uses a subset of the ASCII character set. Its semantics are keyword-driven. Both static and dynamic semantics are defined in the VHDL Language Reference Manual. The language provides procedural (sequential processing), concurrent, or a combination of the two (block-oriented) sequencing mechanisms.

Abstractions of real hardware are represented as design entities in VHDL. Design entities provide the means for modeling transforms (via input and output ports, signals, and functions). Each design entity has an interface description (input/output declarations and attribute definitions) and one or more body descriptions. "The body...describes the internal operation or organization of the component being described. The internal details of the component may be described using structural, data-flow, or procedural styles of expression." (M. Shahdad, "An Overview of the VHDL Language and Technology")

Design files may be complete or partial. To support partial design data, VHDL can read and write external files. (VHDL Language Requirements)

All of these formats provide provisions for handling data not defined by the format semantics. In EDIF, this is done with a userdata construct. In IGES, there is a copious data entity. Both IPC-D-35x series and VHDL handle comments. There are positive and negative aspects to the use of user-defined data extensions. These constructs serve as escape hatches, necessary when unanticipated data requirements become known. At the same time, however, their use requires coordination between the sender of the data and the
receiver of the data. This renders the data unacceptable for archival storage without the use of accompanying documentation.

I. FUTURE PROSPECTS

IPC is continuing to upgrade and standardize the IPC-D-35x specifications. Future activities will focus on meeting DoD objectives. If necessary, the language will be changed to meet users' needs. The users group is working on several guides to aid implementers of the specifications. These guides include a manual for Electronic Packaging Design and a "Plan to coordinate the automation efforts of IPC committees directed toward the development of a totally integrated facility." IPC leaders have identified six factors which have hindered the success of the specifications:

1. too much implementation inflexibility,
2. minimum support by CAD system vendors,
3. industry usage abuse,
4. inadequate training/promotion/visibility,
5. inexperience of tri-Service personnel, and
6. the lack of public domain tools (translators).

They are working on correcting these concerns. (See Appendix L.)

The IGES organization is continuing the refinement and enhancement of IGES. It will be distributing a draft of IGES Version 4.0 at its quarterly meeting in July 1987. Target publication date is in 3 to 6 months. Version 4.0 contains one form of solids model, constructive solids geometry (CSG). This is necessary for representing a complete 3-D assembly drawing, suitable for documentation. The entities for the CSG models were derived from SDRC's (a subsidiary of CALMA) CSG representations. The technical content of Version 5.0 will be closed at the end of the July 1987 meeting. Version 5.0 will contain the boundary-representation (b-rep) solids modeling and design rule representation capabilities. High priority is being placed on developing testing methodologies for the format. A SAE certification program to certify the compliance of commercial IGES translators with vendor claims is under formation. IGES 3.0 is in the final stages of approval as an ANSI standard by the ANSC Y14.26 Committee. At some point in the future, after the viability of PDES is certain, the refinement of IGES may discontinue. At this time, Version 5.0 is the last planned revision to IGES.
With the release of Version 2.0, the EDIF leadership will be concentrating on promoting EDIF. The first commercial EDIF training session will be held in August 1987. The technical subcommittees are preparing user guides. The guides will be released throughout 1987. By late 1987, an EDIF User's Guide will be published by the organization. Many people are still interested in extending the scope of EDIF. There is a movement underway to incorporate Computer-Aided Software Engineering (CASE) design descriptions into EDIF (Cadre Technologies, Inc.). Other appropriate applications include reliability, availability, and maintainability (RAMCAD) design data. There is also interest in developing a bridge between EDIF and VHDL.

Version 2.0 is an Electronics Industry Association (EIA) Interim Standard. This was published without "necessarily following the rigorous public review and resolution and comments which is a procedural part of the development of an EIA Recommended Standard" (EDIF Version 2.0). The EDIF organization will be pursuing standardization of the format through formal review and balloting procedures. The EIA has established a formal structure comprised of an EDIF Steering Committee and Technical Committee. Corporate members of EIA may join the EDIF Technical Committee under the EIA. According to the press, EDIF will be accepted.

Balloting for the IEEE version of VHDL closed July 1987. VHDL 1076/b was approved by the voting constituency by 88 percent. The VHDL Analysis and Standardization Group (VASG) plans to respond to all comments received during the balloting phase. IEEE approved VHDL in December 1987. Many believe that the vendor community will develop and release support tools (such as simulators and interpreters) and VHDL models within six months of IEEE approval. There are related projects underway. For instance, CLSI is creating a toolkit which includes VHDL and EDIF conceptual schemas (in the Interface Definition Language), data access tools, and tools which allow the importation of VHDL and EDIF into a central data repository. A new IEEE DASS Working Group has been formed to develop VHDL models of abstract behavior. These models will include commonly used functions in the design process.

DoD projects (such as the Engineering Information System and the Tester Independent Software Support System) are investigating the use of VHDL as an interface in an open system engineering environment. The Air Force is funding 10 demonstration projects and the development of an interface between EDIF and VHDL. There are tentative plans to issue a DoD directive which mandates the use of VHDL for all circuits delivered to
the government. More extensive experience with the applicability of VHDL in various environments is needed before a directive of this sort is accepted.

There is general agreement that, as a documentation language for the behavioral functions of hardware design, VHDL is powerful. The extent to which any programming-oriented hardware design language will be used for design entry, however, is in question. Designers are not necessarily programmers and may prefer a graphics-oriented interface. In "STDL: A Graphical Behavior Language," Hakan Soderstrom writes, "We believe that state diagrams are closer to the way a hardware designer thinks than a Pascal-like textual language."

CAE vendors are exploring the board and system-level design market. In the recent past, the CAE vendors' focus was on chip-level design tools. As vendors enter the system-level market, the applicability of VHDL in the commercial arena will be better understood.

The future of PDES depends on the organization of the PDES Cooperative and the volunteer effort. A proposed scenario for the redirection of PDES is illustrated in Figure II-2. The future plans of these organizations are summarized in Table II-5.

General comments:

(1) The IGES organization has made tentative plans to eventually replace IGES with PDES. None of the other organizations have made official statements regarding when or at what point the standards will be complete or replaced.

(2) All of the standards are affiliated with an ANSI-approved standardization organization, and are in the process of being approved or have been approved as an ANSI standard.

(3) The ongoing success of the standards is dependent on CAE/CAD vendor support.

(4) Testing is perhaps the most critical element of the acceptance of these formats. The testing plans for each of the formats, as reported in the NBS Plan for Validation (Conformance Testing) of Computer Products in Support of the CALS Program, is summarized in Table II-6. The charts in this table highlight the fact that IGES has the most complete plans for testing. The other organizations are depending on informal trial transfers and/or pilot programs such as EIS to demonstrate the capability for transfer.
Figure II-2. Development Strategy for the Product Data Exchange Specification
Table II-5. Plans of Standards Development Organizations

<table>
<thead>
<tr>
<th>PLANS</th>
<th>ICP-D-35X</th>
<th>IGES</th>
<th>EDIF</th>
<th>VHDL</th>
</tr>
</thead>
<tbody>
<tr>
<td>Near Term</td>
<td>Establish a user group. Release user guidelines.</td>
<td>Enhancements driven by aerospace and manufacturing industry. Technical content freeze at Version 5.0. Primary emphasis on testing program (SAE).</td>
<td>Enhancements driven by IC and systems designs and manufacturing industries. Seek endorsement by EIA.</td>
<td>Tool development underway.</td>
</tr>
<tr>
<td>Long Term</td>
<td>Mappings from IGES to PDES (co-existence strategies?).</td>
<td>Interfaces to VHDL (co-existence strategies?).</td>
<td>Interfaces to EDIF (co-existence strategies?).</td>
<td></td>
</tr>
</tbody>
</table>

J. CONCLUSIONS

Sections A through I provide evidence that all of these formats/languages are viable representations for specific application information. They are useful subsets of product data and meet the needs of the target user community. Many organizations have invested a substantial amount of manpower and other resources to advance the development and use of the formats. None of these formats will be or should be discarded or dismissed prematurely. Much can be gained from an in-depth understanding of the concepts introduced in this section. There are two areas in particular which need further investigation:

1. the strengths and weaknesses of the formats, and
2. the applicability of data modeling techniques to the analysis of the semantic content of the formats.

Item (2) is discussed in Chapters II and III of this report.

Appendices B and G and Supporting Materials 5, 6, 7, 10, 11, 12, 14, 15, 16, 19, 20, 21, 25, and 26 provide additional background material for the information discussed in this chapter.
<table>
<thead>
<tr>
<th>STANDARD</th>
<th>CURRENT STATUS OF TESTING</th>
<th>WHO'S DEVELOPING THE TESTS?</th>
<th>NEED FOR SUPPLEMENTAL TESTS FOR CALS</th>
<th>REQUIREMENTS FOR A TESTING PROGRAM</th>
<th>PROCESS FOR ADMINISTERING TESTING</th>
<th>TIMEFRAMES TO ESTABLISH/IMPLEMENT</th>
<th>INTERIM SOLUTIONS</th>
</tr>
</thead>
<tbody>
<tr>
<td>IGES</td>
<td>Users performing test program on translators to and from IGES format. Test cases are available from NBS. File analyzer available from commercial sources: one domestic/one foreign.</td>
<td>Test cases are developed by NBS, edited by IGES organizations, CAD system vendors, and user companies.</td>
<td>Yes. CALS has defined three (3) application subsets of IGES that will require validation and acceptance testing.</td>
<td>Involves a rigorous methodology, a comprehensive suite of test cases, documented criteria for measuring the degree of success, and various software tools to assist in the process. This program is being created in 1987.</td>
<td>NBS is committed to providing a neutral digital format for product data exchange. Through IGES committees, a testing program will be initiated by third party organizations with oversight by NBS and its IGES organization.</td>
<td>Initial operation by September 1987.</td>
<td>Develop guidelines for users to validate their own IGES translators. Publicize the experiences of sophisticated users. Make available good quality test cases.</td>
</tr>
<tr>
<td>VHDL</td>
<td>Possible validation and verification developers, test suites, and administration of conformance testing is being considered.</td>
<td>United Technologies Microelectronics Center is currently performing verification/validation of the VHDL and support environment. This organization as well as Intermetrics and CAD Language Systems are possible candidates.</td>
<td>Possibly. TBD after IEEE standardization of VHDL and refinement of the CALS electronics standards information model.</td>
<td>TBD</td>
<td>TBD. However, any organization is a possibility as long as it is accredited by NBS or other recognized accrediting program.</td>
<td>After forthcoming IEEE standardization of VHDL this fall.</td>
<td>TBD</td>
</tr>
<tr>
<td>EDIF</td>
<td>Nothing at this time. Second version just recently became available.</td>
<td>TBD</td>
<td>Possibly. Needs to be integrated with VHDL, which needs interfacing with CALS.</td>
<td>TBD</td>
<td>TBD</td>
<td>TBD</td>
<td>TBD</td>
</tr>
</tbody>
</table>
III. COORDINATION ACTIVITIES

This section describes three independent efforts to investigate the interoperability of the exchange formats described in this report. Issues addressed include:

1. What format or formats should be used to integrate CAE/CAD/CAM tools and databases?
2. Will one format ultimately take over the domain of the others, thereby rendering implementations useless?
3. What formats will the government require to deliver product data? and
4. What interfaces among the formats are needed?

The efforts described in this section, the December 17, 1986 Electronics Standards Coordination Meeting, the American National Standards Committee (ANSC) Y14.26 Electronic Product Working Group, and the IEEE Design Automation Standards Subcommittee (DASS), are three of many efforts concerned with this problem.

Informal industry collaborations are taking place to minimize the risks of supporting one or more of the formats. For instance, Hewlett-Packard and McDonnell Douglas Corporation co-authored a letter dated 20 March 1987 "to solicit some information regarding current and future standards work in the CAE/CAD/CAM community." (Supporting Material 10, Enclosure 8.3) The letter asked Mike Waters (EDIF Technical Committee Chairman), Brad Smith (IGES Program Manager), Larry O'Connell (IGES Electrical Applications Subcommittee Chairman), Dieter Bergman (IPC Technical Director), and Larry Saunders (IEEE/DASS VHDL Analysis and Standardization Working Group Chairman) questions regarding the objectives, users, and positioning within the standards community. This information will be used to guide Hewlett-Packard's and McDonnell Douglas' long-range strategic plans in this area.
A. THE DECEMBER 17, 1986, ELECTRONICS STANDARDS COORDINATION MEETING

The Electronics Standards Coordination Meeting was a joint effort of the OSD CALS Policy Office and IDA. (See Supporting Materials 9, 13, and 14 and Appendix L.) The objectives of this meeting were to:

(1) understand the interaction of the leading CAE standards with respect to DoD's requirements, and

(2) reach an agreement on the appropriate approach to resolve the overlap issue.

The leaders of the standards development efforts, the Chairman of the IEEE Design Automation Standards Subcommittee, OSD representatives, and IDA representatives participated in this meeting. A draft "Logistics Information Model for Electronic Equipment (the Matrix)" was presented by the OSD representatives as a structure for understanding the applicability of the standards in terms of DoD information needs. After much discussion regarding the information and application categories defined by the matrix, two recommendations and several follow-up actions were agreed on. The recommendations were:

(1) "A case study describing the acquisition process of an electronic product model from the CALS perspective should be developed."

(2) "DoD should leverage the work that is underway by the various standards organizations (i.e., the CAL POLY data modeling project)."

In response to these recommendations, John Hines of the VHDL Program Office agreed to support the development of the Electronic Product Case History. OSD tasked the National Bureau of Standards to coordinate the development of the matrix with the various standards and industry organizations working on the same problem.

Specific follow-up actions were established to secure the ongoing participation of the standards groups in the refinement of the information categories and completion of the matrix. The standards leaders agreed to review, revise, comment on, and distribute the matrix to members of the standards organizations. The group agreed on an ambitious draft schedule, which included applications and standards committee workshops.

This meeting was successful in bringing together the leaders of the standards groups to discuss each others' goals and plans in terms of DoD's needs. The meeting did not, however, provide a forum for defining specific domains for the standards as some of
the participants expected. These participants felt such an agreement would be necessary to ensure the future existence and interoperability of each format.

The follow-up actions did not take place as planned. Due to unforeseen complications, the development of the matrix structure was tasked to the CALS NSIA Committee. The results of that effort will be released by the OSD CALS Office in the fall 1987. This version of the matrix should describe information categories needed for particular logistics applications, as identified by NSIA subgroups.

B. THE ANSC Y14.26 ELECTRONIC PRODUCT WORKING GROUP

The ANSC Y14.26 Committee, titled "Computer Aided Preparation of Product Definition Data," is responsible for approving standards for product data exchange (i.e., IGES 3.0, IPC-D-35x, and EDIF). Additionally, this group is concerned with the overlap between product data exchange standards: namely, the overlaps which exist between IGES and EDIF; and peripherally among IGES, EDIF, VHDL, and IPC-D-35x. The Electrical Liaison Subgroup, under Y14.26, is investigating overlap issues raised by the Y14.26 Committee. These issues include:

1. the current proliferation of overlapping standards,
2. divergent technical approaches /philosophies, and
3. DoD policy.

In September, the Electrical Liaison Group invited members of EDIF (Dick Smith, Mike Waters, and Jeff LaVell) and IGES (Larry O'Connell and Brad Smith [member of Y14.26]) to a meeting to discuss the EDIF/IGES overlap. The EDIF position, expressed at this meeting, is as follows:

1. The EDIF Steering Committee could not identify a standard functionally equivalent to EDIF.
2. A variety of standards are needed to describe a product.
3. EDIF is best suited for electrical applications, IGES for mechanical, and VHDL for system-level applications.
4. It is up to industry to determine how the standards will be used.
5. EDIF people will not participate in a coordination activity until the release of EDIF version 2.00.

The IGES position, according to Larry O'Connell, the IGES Electrical Applications Chairman, and Brad Smith, the IGES Program Manager, is as follows:
(1) IGES can be used for IC design data.
(2) A conceptual data model is required to understand the overlaps among the formats.
(3) An industry team, the CAL POLY Task Team, will be attempting to create a conceptual data model for electronic product data.
(4) EDIF, VHDL, and IGES people should be involved in this effort.
(5) A bridge is necessary among the standards. For example, EDIF be used for component descriptions and IGES be used to build the circuit and archive the final product.

As a result of the EDIF and IGES presentations, the Y14.26 Electrical Liaison Group recommended the following actions:

1. "Focus on the content of the formats to bring convergence,"
2. "Pursue the joint modeling project,"
3. "Encourage a continuous dialogue between the Smith brothers,"
4. "Encourage DoD to formulate a consistent and coordinated policy with respect to product definition data standards,"
5. "Pursue the formulation and promulgation of a formal memo of understanding and agreement for a long range plan for interoperability of recognized electrical product definition data specifications and standards," and
6. "Recruit EDIF and VHDL experts to work with Y14.26."

A draft memo, suggesting the preparation of a long-range plan for the interoperability of Electrical Product Specifications, has been prepared. This memo, if signed by the leaders of the standards projects and the chairmen of interested ANSI, IEEE, and EIA committees, will be the first formal agreement by all of the standards development and endorsement groups.

The group is tracking the development of the standards efforts and the information modeling projects.

C. THE IEEE DESIGN AUTOMATION STANDARDS SUBCOMMITTEE

The Design Automation Standards Subcommittee (DASS), under the IEEE Computer Society Design Automation Technical Committee (IEEE/CS/DATC), provides "standard description languages for the capture, utilization, and communication of
Throughout 1986 and 1987 the DASS has been focusing on the standardization of VHDL and the preparation of supporting technical material.

With respect to standards for the electronics design industry, the DASS is coordinating efforts to define interfaces among overlapping standards. For the last two years, Ron Waxman, DASS Chairman, has run a panel presentation at the Design Automation Conference to discuss issues relating to the interoperability of the standards. The healthy attendance at these public forums suggests growing concern regarding the overlap issue within the design automation community. The DASS has made many attempts to address and resolve the interoperability issue. During the period, fall 1986 to spring 1987, it lent support to the development of a conceptual information model for electronics engineering data, under development by an ad hoc group called the CAL Poly Task Team. At the conclusion of the CAL Poly effort, it became apparent that the resulting model, although academically interesting, was not sufficient for solving the interoperability issues. The model was not universally understandable and agreed upon. Furthermore, procedures for mapping the model to the various formats were not defined.

At the July 1987 DASS meeting, priorities concerning the interoperability issue were established. The immediate priority became delivery of an interface between EDIF and VHDL. The use of information models was deferred.

D. ANALYSIS

From the experiences of these coordination efforts we have learned a great deal about the applicability of the four solutions to the interoperability issue listed in the Introduction (Chapter I, Section D). The following is a summary of what was learned:

**Solution 1**: Secure an agreement among the standards leaders to limit the scopes of the standards.
- **Implementation time table**: immediate
- **Probability of success**: low
- **Critical success factors**:
  1. Identification of appropriate scope boundaries that meet all long-range expectations
  2. Adherence to the scope boundaries by EVERYONE involved in the development and implementation activities.
Solution 2: Define interfaces among the formats without a rigorous specification of the content overlaps.

Implementation time table : 1-2 years
Probability of success : good
Critical success factors :
(a) the successful interaction of format experts
(b) the identification of workable subsets of the formats
(c) well organized trial transfers and demonstrations.

Solution 3: Develop one standard which will handle all product data for all applications.

Implementation time table : 5+ years
Probability of success : extremely low
Critical success factors :
(a) a rigorous understanding of what product data is by all participants
(b) full-time basic research on information modeling for engineering data
(c) the successful interaction of a large number of specialists from a wide spectrum of engineering disciplines.
(d) a demonstration of the full development methodology for workable subset of product data
(e) the availability of automated tools to support the development methodology (emphasis on the information modeling process)
(f) the successful reorganization and redirection of a PDES-like effort; well defined objectives for the project

Solution 4: Use well-defined areas of overlap as bridges among the standards.

Implementation time table : 2-3 years
Probability of success : good
Critical success factors :
(a) the availability of an understandable and validated conceptual information model and modeling methodology for electronic product data
(b) a systematic methodology for defining mappings between the conceptual data model and the formats
(c) the cooperation of specialists from the electronics community
(d) the availability of automated tools which support the systematic methodology.

E. CONCLUSION

Many programs depend on the successful interoperability of existing standards to achieve open system environments. Private industry, the defense industry, and non-profit organizations are involved in these programs and need to find solutions. The coordination efforts described above and others have made much progress toward understanding what can be done to define interfaces among the standards and toward communicating their concerns and needs to the appropriate organizations. Interoperability, however, is only one facet of the total solution to open architectures. A more fundamental aspect of the problem (which begins to meet the requirements for solution 4, above) is discussed in Chapter IV.

Both IEEE and EIA are the appropriate organizations for coordinating the development of interfaces among the standards. Methodologies need to be developed and neutral positions established, however, before this can be achieved. Theoretically, a conceptual information model for electronic product data is one potential approach to solve the overlap issue.
IV. DATA MODELING ACTIVITIES

Chapter I introduced the notion of a conceptual model of product data requirements (also referred to as a "conceptual information model," "conceptual data model," "conceptual schema for electronic product data," and other combinations). As explained in the introductory chapter concerning open architectures, a conceptual data model serves as a foundation for an integration architecture. Theoretically, by using a conceptual data model, it is possible to define interfaces among disparate databases, design files, and exchange formats.

The Cal Poly Task Team, a proof-of-concept project, was tasked to develop an industry-wide conceptual information model for electronic product data. The activity, described in Section IV.A, was a good test of whether or not existing modeling methodologies are sufficient to build conceptual schemas for engineering data. Prior to describing the Cal Poly experiment, this section describes what a conceptual data model is and why it is important.

A conceptual information model is an abstract representation of data requirements for a wide variety of applications. These requirements are expressed in terms of fundamental data elements and relationships among those elements. Traditionally, conceptual data models are used to design an "enterprise" database that will be accessed for a wide variety of applications. A conceptual data model also serves as a "meta-language" (a language to talk about other languages) for discussing, comparing, and contrasting the content of databases, design files, and CAE exchange standards. This communication is achieved by defining mappings between a conceptual data model and each of the exchange standards. This results in consistent interfaces among the standards. (See Figures IV-1 and IV-2.)

A conceptual data model is one that is independent of all databases, application tools, applications, formats, or output reports. Independence is achieved when the meanings contained in the model do not rely on the meanings assumed by a particular
application, database, etc. A conceptual model depicts the concepts necessary to generate information for a wide variety of applications, reports, and storage formats.

Application data models, on the other hand, represent the data elements and relationships used for a particular application. Many people confuse these two types of data models. Creating a conceptual data model is very, very difficult. Creating an application data model is not as difficult, although it does require the successful interaction
of a group of subject experts and experienced data modelers. To create an application data model, the application is used to set the context for the following steps:

1. identify input, output, and processing-specific data requirements,
2. define the relationships among the data elements (as dictated by the application), and
3. identify the properties (attributes) associated with each data element (also as dictated by the application).

Creating a conceptual data model requires the same basic steps outlined for the application data model. The significant difference is that instead of identifying application-specific data requirements, the data modeling team must identify abstract data requirements, relationships, and attributes which transcend applications.

One approach to developing conceptual models is to develop a set of application data models prior to creating the conceptual data model. After a set of application data models are considered stable and complete, they should be integrated to form a conceptual data model. The integration process consists of identifying common and inconsistent elements among the models, resolving differences, merging commonalities, and generalizing (or removing) application-specific elements.

The integration process, however, may be as difficult as the process of creating a conceptual data model without the use of application data models. It is difficult, because at any time during the process it is very easy to lose perspective regarding what is "conceptual" and what is "application-specific."

The original approach of the PDES project was to create application models prior to the conceptual model (the "logical layer"). As the application models became reasonably stable, they would be integrated. The integration of the PDES application models has not been proceeding as smoothly as expected. The integration of the models was one of the least-defined aspects of the process. It is not clear whether the difficulties that the PDES groups are facing are due to the fact that the process is not well understood, or whether the process is inherently difficult. Many lessons can be learned from this effort.

Data modeling techniques are traditionally associated with the design and development of databases. Neutral exchange formats, although not databases, are similar to databases in that they are mechanisms for the storage and transfer of data. Data models provide definitions of data structures. Theoretically, they can be used to describe either database schemas or exchange format structures.
A significant industry investment is required to develop an industry-wide conceptual data model. It is not only a long-term project (and never truly finished), but also it must be accepted by a wide range of industry representatives (both users and, most importantly, vendors). Although it serves as a foundation for open system architectures, it also presents a risk of data exploitation for both CAE vendors and product designers. Many believe that component models and design data must be kept proprietary to maintain a competitive edge.

A. THE CAL POLY TASK TEAM EXPERIMENT

The Cal Poly Task Team was a group of representatives from the electronics industry who assembled to develop a public domain conceptual schema for electronic product data. (See Appendices D, E, H, I, J, and K.) The Cal Poly Task Team, an outgrowth of the PDES modeling activities, was organized by Curtis Parks (General Dynamics) and Roger Gale (D. Appleton Co.), both heavily involved in PDES. The organizers felt that to develop a model of electronic product data, representatives of the electronics industry had to be involved. The IEEE DASS was identified as the appropriate organization to serve as the focal point for the model development activities. The IEEE DASS agreed to sponsor the activity and formed a Working Group in response.

The Cal Poly Task Team project was a six-week full-time modeling activity that took place during January and February 1987. The team met at the Kellogg West facilities of the California State Polytechnic University. There were 13 on-site participants (2 for the entire session), 3 telephone contributors, and 9 who provided assistance. The participants were from General Dynamics, D. Appleton Co., McDonnell Douglas, Westinghouse, Hughes, IDA (BITE), Digital Equipment Corporation, Viewlogic Systems, and STC Ltd (UK).

Members of the Cal Poly Task Team were provided a week of training in the IDEF1-x modeling language and methodology by employees of the D. Appleton Co. After this training, two 3-week modeling sessions were held. The organizers of the project participated throughout both sessions. All other participants attended either one of the 3-week sessions or shorter periods of time.

The result of this effort is an IDEF1-x data model of electronic product data "which is believed to establish a basic structure of data within which the functional description can be developed." (Cal Poly Task Team Final Report) This model contains 17 entities which describe functional hierarchy and logical connectivity. The team tried to incorporate a third
aspect of electronic product data behavior, but had much difficulty and decided to defer the development of this part of the model until later.

The model was presented to the public by the team organizers at three locations: East Coast (Bedford, Massachusetts); West Coast (Pomona, California); and the Middle Atlantic region (Dayton, Ohio). An average of 20 people attended each of the reviews. The following projects sent representatives to at least one of the reviews:

- Engineering Information System (EIS)
- Tester Independent Software Support System (TISSS)
- Product Data Definition Interface Extension (PDDIx)
- Product Data Exchange Specification (PDES)
- Computer-Aided Acquisition Logistics Support (CALS).

Many comments were received, and the model was modified as the result of each review. At the conclusion of the Cal Poly Task Team activities, the model and the Cal Poly Task Team Final Report were delivered to the IEEE DASS and the PDES Electrical Applications Chairmen.

Theoretically, the resultant model is elegant. Practically, however, the model is not suitable for implementation. The modeling methodology, IDEFIX, is not appropriate for all aspects of engineering design data.

An analysis of the CAL Poly Task Team results and lessons learned reveals the need for extensive basic research into modeling methodologies for engineering design data. There are many fundamental issues yet to be resolved concerning the modeling methodology (both the language and the process) used to develop a conceptual model. The critical issue (raised by participants at the reviews of the model) is that the the IDEF1-x language does not have the expressive capabilities required for modeling complex design data. Another very practical concern is the availability of automated tools to support the modeling process.

A demonstration of how the model can be used to define interfaces among exchange formats was never achieved. (See Appendix I.) Until such a demonstration is performed, industry will continue to vacillate over the necessity of a conceptual data model.

Another fundamental issue which is inhibiting the development of industry-wide conceptual data models is the lack of knowledge regarding how to test and validate such models.
B. THE CAL POLY TASK TEAM EXTENSION

The Cal Poly Task Team officially disbanded after delivery of the final report. As a result of recommendations made at the final review in Dayton, Ohio, another ad hoc team, the Cal Poly Task Team Extension, was formed. The focus of this effort is the development of a model for printed wiring board data.

C. CONCLUSIONS

Although the Cal Poly Task Team did not produce a usable model for electronic product data as intended, the team did succeed in testing the use of IDEFIX for complex design data. This effort highlights the need for comprehensive research into data modeling methodologies.

The most significant results of this effort are the questions which remain to be answered before modeling can take place on a wide-scale basis. It is imperative that these questions be addressed before another ambitious modeling project for CAE data is undertaken. These questions are included in Chapter V, Conclusion.
V. CONCLUSIONS AND RECOMMENDATIONS

1. *Do the data exchange formats provide what is needed to implement open system architecture?*

   Not completely. There are missing elements:

   (1) specifications which describe how to use the formats to represent classes of information for various applications,

   (2) interfaces among the formats, and most importantly

   (3) a conceptual model of electronic product data.

   Although the formats described throughout this paper are at various stages of development, none have reached the stage of specification (as defined in Terminology, Chapter II, Section B). In other words, none of these formats provide detailed instructions describing how to create descriptions which will be compatible with all other descriptions of that genre. Currently, to ensure data compatibility (one system can understand the data generated by another system), pre-arranged conventions must be established between the sender and receiver of the data.

   The standards groups are responding to this need by preparing "user guides." User guides establish conventions for using the formats in a variety of applications. The preparation of user guides will follow actual implementations and trial transfers. The development of specifications which describe how to use the various formats can be greatly accelerated if the government provides a structure and direction for the preparation of the specifications. Programs such as ULCE, RAMCAD, CALS, and EIS are the appropriate vehicles for providing this direction.

   The development of these standards will proceed at a pace required by users and as the electronics design community makes use of the formats. If the vendors do not implement the formats, then there is little chance that the formats will receive widespread acceptance. The IPC-D-35x series may be in this situation. With the current set of exchange formats, a great deal of vital electronic product design data can be exchanged. As technology advances, data requirements will change. It is anticipated that the capabilities of
the exchange formats will increase with the advance of technology. It is unlikely, however, that it will be possible in the foreseeable future to create one standard that does everything for everybody. The PDES project is currently misdirected. A more realistic goal is to create a method for the interoperability of formats.

2. How should interfaces among the formats be built?

A reasonable approach is to use rigorously defined overlaps as bridges to transfer data among the formats. This is the preferred solution, because it is technically viable (given the development of information modeling techniques and models for electronic product data), and is open to future requirements. It is applicable to any electronics product data exchange format. Finally, the implementation of this solution is not too far off into the future.

*These missing elements (specifications for the use of established formats and interfaces among the formats) are symptoms of the lack of a conceptual information model for electronic product data.* A conceptual model cannot be built, however, until advanced modeling methodologies are developed.

**RECOMMENDATIONS:**

**Concerning Information Modeling:**

(1) Fund a basic research project to answer the following questions:

   (a) What is a conceptual model for engineering product data?

   (b) What are the requirements for a modeling methodology and language to support a conceptual model for engineering product data?

   (c) Are there any existing data modeling methodologies which meet those requirements?

   (d) What automated tools are necessary to support the modeling methodology and the use of the conceptual model?

   (e) How are conceptual data models tested and validated?

**Concerning the Existing Data Exchange Formats for Electronic Product Data:**

(2) Staff a full-time team within DoD to serve as a focal point and central source of expertise on the activities of the CAE standards organizations, the standards coordination projects, related information modeling projects, and government projects involving open-system architectures for CAE/CAD/CAM environments.
Tasks for the team include:

(1) closely monitor the progress of each CAE exchange format,
(2) provide a consistent presence within those communities, and
(3) drive the development of the formats to meet DoD requirements.

(3) Support the development of specifications which describe how to use the CAE exchange standards for particular applications.

(4) Support the development of interfaces among the established CAE exchange formats.
SUPPORTING MATERIALS

13. CAE Standards Coordination Meeting Planning Notes, December 1986.
15. EDIF Joint Technical Committee/Subcommittee Trip Report, 3 November 1986.


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Appendix A

DESIGN AUTOMATED CONFERENCE POSITION PAPER
Needed: A Meta-language for Evaluating the Expressiveness of EDIF, IGES, VHDL and other Representation Mechanisms

ML BREI
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ABSTRACT

The IEEE/CS/DASS Electronic Model Working Group (EMG) is using data modeling methodologies to analyze the interoperability of existing exchange formats for electronic product data. The operational philosophy of the EMG is that a conceptual schema for shared product data can serve as a meta-language and foundation for CAE/CAD/CIM data integration.

DISCUSSION

To properly assess the uses of and relationships among VHDL, EDIF, and IGES/PDES, we must adopt a new perspective. Much time has been spent addressing the question, "Are these formats competing or complementary?" The consensus is that these formats 1) exist, 2) have solid support from specific sectors of the industry, 3) have a reasonable life-span, and 4) will become standards for a specific set of applications. Given these premises and the notion that there is wide-spread concern regarding their inter-operability, it is time to shift our focus to a more basic issue: How can we talk about the expressive capabilities of EDIF, IGES/PDES, and VHDL? In other words, what conventions, languages, and mechanisms are required to understand that which we are going to analyze (what is the common meta-language for communicating about data transfer formats and design languages).

The history of the development of EDIF, IGES, and VHDL explains the latent need for a meta-language. Each was developed by a core team of experts for a specific application. The language of the application served as the meta-language for the information content. Each format grew independently and established its own verbiage for expressing the information pertinent to its application. Unfortunately, osmosis has yet to occur. It is a challenge to discuss engineering product data with EDIF, IGES, and VHDL experts in one room. Invariably, this type of meeting becomes a terminology clarification session to establish a neutral ground for the terms "everybody understands."

This semantic gap exists because we, as an industry, have yet to define the conceptual foundation of CAE/CAD/CIM product data. A conceptual foundation is a formal specification of application-independent data and their meanings, attributes, and relationships. The transformation and use of conceptual data for an application results in the information embodied in a format. The conceptual foundation is realized by a conceptual schema (or model) for shared product data.

To bridge the semantic gap, the IEEE/DASS has formed the Electronic Modeling Working Group. After determining the technical feasibility of using data modeling technologies to analyze the expressiveness of EDIF, IGES, and VHDL, the group will define a standard set of meanings for the conceptual data of electronic products. The "Conceptual Schema for Shared Product Data" developed by the Cal Poly Task Team is the catalyst for this effort. The success of this work hinges on the cooperation of representatives from all aspects of the electronics industry. All who are truly concerned with establishing a viable solution for CAD/CAE/CIM data exchange should be involved in the definition of the neutral, conceptual model of the data of our enterprise.
Appendix B

PDES UPDATE, 18 MARCH 1987
**PDES UPDATE**

A. The PDES project is approaching a critical decision point. The issue in question is whether PDES should remain a totally voluntary activity under NBS, or whether it should become a fully funded project under an organization such as the DoD.

Advocates for the fully-funded option include T. Moffet, the ATF and the CALS people. These groups need PDES sooner than current development is proceeding.

There are advantages to keeping PDES under NBS. NBS provides a neutral focal point for the coordination of the development effort. Under NBS, PDES is strictly in the public domain. If PDES becomes a funded project, questions of ownership arise.

B. This critical decision point is the result of attempts to re-organize and re-direct the PDES efforts. For several months, T. Moffet has been actively seeking funding sources for the project. The OSD Cals Policy Office has responded by providing funds for the following tasks:

- Develop a short-range plan for PDES
- Perform a comparative analysis between CALS and PDES
- Develop a long-range plan for PDES
- Write a paper on the technical environment

These tasks are being performed by DACOM and Battelle. Battelle is providing the logistics expertise (poc: Carolyn Davis 202-785-8400).
C. A decision may be reached within the next month. A preliminary plan for PDES will be sent to key people (Edit Committee, DoD, GMAP, IDS, AMRF, PDDI, IPAD, AAAP, and NSIA representatives) within a week for review. A formal review meeting will be held in South Carolina on June 11, 1987. At this meeting, the PDES plan will be presented and feedback will be requested.

On June 17, 1987, Russ Shorey is holding a meeting to determine the future of PDES from the CALS perspective.

D. Controversy within the PDES working groups concerning the purpose of PDES continues. There are at least three prevailing perspectives:

1. PDES is an exchange format
2. PDES is a data structure
3. PDES is an integrated data model

If PDES is viewed as an integrated data model, then it can have many uses including 1 & 2 above. As an integrated data model, translators can be developed by provide mappings into IGES, EDIF, STEP, or any other relevant physical format.
Appendix C

ELECTRONICS MODEL GROUP STRATEGIC PLANNING
MEETING REPORT, 8 MAY 1987
EMG STRATEGIC PLANNING MEETING
May 1, 1987

- REPORT -

A meeting to discuss the goals and objectives of the Electronic Model Working Group (EMG) was held on May 1, 1987 at BITE Inc. The attendee list is enclosed (1).

Enclosure (2) is a list of issues discussed during the meeting. The following is a summary of the key points raised in response to the discussion items.

1. The Cal Poly Conceptual Schema for Electronic Product Data

The Cal Poly Conceptual schema is a neutral representation of the data primitives required for electronic product descriptions. The schema provides:

- semantics for the domain of discourse (for instance, what is meant by the word "signal") and

- a definition of existence dependencies (a type of data constraint) among data primitives.

The conceptual schema is independent of physical formats (such as VHDL, EDIF, and IGES). It is a high level abstraction of the data encapsulated by such formats.
The conceptual schema has many uses. First and foremost, it identifies the atomic data elements of electronic product descriptions. Secondly, it defines existence relationships among those elements. By describing primitive data elements, it may serve as a meta-model to analyze a specific subset of the overlaps between physical formats.

2. The DASS EMG

The EMG will provide recommendations for specific uses of the Cal Poly Conceptual schema. The first application which will be dealt with is the use of the conceptual schema to understand the overlap between VHDL and EDIF. The scope of the overlap which will be analyzed via the Cal Poly model is believed to be a small subset of the entire overlap between VHDL and EDIF. The aspects of the overlap which will be considered initially involve functional connectivity and structure.

The EMG will prepare a Recommended Practices Document to address this application. This document will provide:

- a list of terms and associated meanings
- a definition of the common atomic data elements within the domain of discourse
- mapping specifications between the Cal Poly model and EDIF, the Cal Poly model and VHDL, and the Cal Poly model and IGES
- a definition of the areas where dynamic data may exist

The Recommended Practices Document will help electrical engineers and other concerned parties understand how to make use of EDIF in a VHDL environment and vice-versa. It will be a pilot demonstration of formalizing the use of the Cal Poly Conceptual Schema to analyze the semantics of independent physical formats for electronic design data.

3. The Cal Poly Task Team

The Cal Poly Task Team provided the groundwork for the EMG. The Cal Poly Task Team Final Report, April 30, 1987, contains a comprehensive description of the conceptual schema, a list of unresolved issues, conclusions, recommendations, and sample applications of the model. The EMG will use this document as a starting point for the preparation of the Recommended Practices Document.

Although the Cal Poly Task Team formally dissolved as of May 1, 1987, ad hoc modeling groups have formed to develop models for
various aspects of electronic product data. The first such ad hoc group is concerned with the "actual" aspects of printed wiring boards. Members of this group are from various companies which have identified a need for a printed wiring board conceptual data model. The first modeling session of this group met during the week of May 4, 1987. Contact George Goldsmith (714-896-1712) or John Zimmerman (816-997-2932) for more information.

The models produced by these ad hoc modeling projects will most likely have a direct bearing on the Cal Poly Conceptual Schema. For this reason, the EMG will serve as a sounding board and focal point for these groups if desired.
Electronic Model Working Group  
Strategic Planning Meeting  
May 1, 1987

**ATTENDEE LIST**

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DISCUSSION ITEMS

1. What is the DASS perspective on the purpose of the EMG?

2. What is the IGES/PDES Cal Poly perspective on the purpose of the EMG?

3. Data transfer in the chip design process scenario:
   EDIF --> VHDL --> EDIF

4. What type of mapping should be defined between EDIF and VHDL?

5. What is the relationship between VHDL and the Cal Poly Conceptual schema?

6. Where does IGES fit in the scenario?

7. The EMG demonstration project
Appendix D

CAL POLY TASK TEAM FINAL REPORT, 30 APRIL 1987
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1. INTRODUCTION

1.1 THE TEAM HISTORY

The Cal Poly Task Team was an outgrowth of the activities of the Product Data Exchange Specification (PDES) project of the Initial Graphics Exchange Specification (IGES) program under the auspices of the National Bureau of Standards. One of the Technical Committees of that program is the Electrical Applications Subcommittee (EAC).

As a part of the PDES project, the EAC had a requirement to develop a model of the data involved in the design and manufacture of electrical and electronic products. This data model would be integrated with models developed by other committees to form what was called the Logical Layer of the PDES. The Logical Layer is based on the Conceptual Schema of the three schema idea developed by ANSI/X3/SPARC in the 1970's.

The EAC found that it was unlikely to meet its scheduled objectives for the initial publication of the PDES within its normal operating mode. There were two key factors involved. The first was that the normal pattern of meetings was that the group met periodically for a few days; usually as part of an IGES quarterly meeting. The second factor was that within the IGES/PDES community it seemed difficult to reach a sufficient number of people in the field of design and manufacture of electrical and electronic products.

There was a conclusion that the solution to the first factor was to pursue the data model development through a series of intensive modeling activities by small task groups. It was thought that organizations with an interest in the result would commit people for specific, short, scheduled periods. The Cal Poly Task Team was the first of such efforts to be scheduled. It was planned as a six-week intensive modeling activity. The six weeks were to be preceded by a week of training in the modeling method and followed by a series of three reviews of the model at different sites.

The solution to the second factor was to find a way to reach more directly into the electrical and electronic product community. To this end, there were discussions with the IEEE leading to sponsorship of the Cal Poly Task Team as a group performing within the Design Automation Standards Subcommittee (DASS).

The Task Team began its activities the second week of January 1987 and completes its formal activity with the delivery of this final report.

1.2 ORGANIZATION OF THIS REPORT

The body of this report contains this introduction, a summary, the conceptual data model developed by the task team and conclusions and recommendations. The bulk of the report body is the conceptual data model developed by the team. The model documentation includes a narrative explanation. The narrative is essentially the description presented orally during the reviews. Other documentation of the model consists of the diagrams, the glossary and the business rules.

Following the body of the report are 7 appendices. Appendices A1 and A2 are provided to expand upon the understanding of the model and its uses. Appendices A3 and A4 provide records of the issues and discussions of the participants in reaching the present state of the model. Also recorded in the issues are issues raised during the reviews of the model. Appendix A5 is the activity model used as a scoping aid. Appendices A6 and A7 identify persons involved with the team and reviews of the model.
2. SUMMARY

2.1 MEMBERSHIP AND TRAINING

The Task Team had an administrator, Curt Parks, who was a full-time participant throughout the term of its activities. Another member, Roger Gale, participated at least three days each week and served as expert modeler. Jerry Kane spent the first three weeks of the modeling period with the team and M. L. Brei spent the second three weeks. Others (see Appendix A6) participated for varying, shorter periods.

Training in the IDEF1X modeling language and methodology was conducted in the second week of January by Roger Gale and Jim Savage from the D. Appleton Co. Inc. IDEF1X was adopted for this activity because it is the language of choice for the integrated model of PDES.

IDEF1X was developed by the U.S. Air Force ICAM project. A manual describing the modeling language and methodology is available from:

ICAM - CIM Library
Air Force Wright Aeronautical Labs
AFWAL/MLTC
Wright Patterson AFB, OH 45433-6533
United States of America

2.2 CAL POLY TASK TEAM SCOPE

The team adopted an idea from the PDES Data Planning Model that, from the sense of a data model, there is a logical separation of the functional description of products from the physical description, and elements in the data model which establish the mapping of functions into physical parts. The team further decided to address the functional description first because there was more work to date in PDES on the model of the physical data.

The Task Team started with an initial scope that limited its efforts to the data which represents the data defining the design of electrical and electronic products at the point of handoff for fabrication and assembly. In many enterprises this is the Engineering Release. The team frequently found itself reexamining issues of Task Team scope. It found itself tangled in the definition of the term "Requirements." After considerable discussion, it established a concept that discriminated between data which represents requirements which have more than one possible technological solution and data which is the description of a design solution within a specific, chosen technology.

2.3 RESULTS

The team has produced a data model which is believed to establish a basic structure of data within which the functional description can be developed. There are three fundamental parts of this model. The first part is the data which represents the "bill of material" (the "functional hierarchy" to electrical engineers) relationships among units of function. This is the core structure (Defined Functional Unit and Defined Functional Sub Unit Occurrence). The second is the entities and relationships within which the data describing characteristics and behavior can be identified (Port, Electrical Property and Signal relationships). The third is the data which describes the way functional units are connected in the logical sense (Link, Port and Electrical Node relationships). Of the two parts, the connectivity is the part which seems most complete and stable. There is general agreement that the behavior part is where there is a large amount of work yet to be accomplished.
The model has been presented four times to different groups of interested persons for understanding and comment. These presentations were at Bedford, Mass., hosted by Computervision; at Pomona, Calif., hosted by Cal Poly University; at the joint meeting of ISO TC184/SC4/WG1 and PDES/IGES in West Palm Beach Florida; and in Dayton, Ohio hosted by the CIM branch of the Air Force.

The model has been modified as a result of comments at those reviews.

At the review in Dayton, John Zimmerman presented the results of his comparison of the Cal Poly model connectivity data to the IGES version 3.0 capability. This is discussed in more detail in Appendix A2.

2.4 WHERE NOW?

The Task Team result is only a beginning. There is considerable work yet to be done before there is a data model with enough entities and attributes to represent a useful subset of all of the possible data for electrical and electronic products. Additional teams need to be scheduled and formed. The List of Issues in Appendix A3 could serve to set the scope of specific task teams.

As part of the development and integration of PDES, the model should be further tested. There are two installations of a software tool called JANUS available to the PDES efforts. JANUS is a tool for managing, testing and integrating data models in the IDEF1X language. One of the installations is at Arizona State University at Tempe with the U.S. Air Force, Integrated InformationSupportSystem (IISS) project test bed. The other is with the National Bureau of Standards, Advanced Manufacturing Research Facility (AMRF) in Gaithersburg, Maryland. The model should be put into one, or both, of these test facilities and further validation performed.
3. THE DATA MODEL

3.1 NARRATIVE EXPLANATION OF THE MODEL

This section of the report provides a narrative explanation to the data model similar to the narrative of the presentations at the various reviews and workshops. The reader is referred to section 3.2 for the diagrams, section 3.3 for the definitions of the entities and attributes, and to section 3.4 for the business rules of the model. The reader is also invited to use the test circuit and data instance tables in appendix A1 as an aid to understanding the connectivity relationships of the model.

The diagrams of the model are presented as a series of IDEF FEO's. This narrative will refer to the FEO's by their identification which is found in the lower left corner of the form.

The reader is cautioned that this model has not yet become concerned with the data which tracks changes in design. When the concepts of "versions" of designs are considered, the model is expected to undergo some change which will add to the complexity of the keys of the entities.

3.1.1 CONNECTIVITY

FEO's 1 through 4 develop the data required to establish connectivity within a functional buildup through levels of assembly.

3.1.1.1 FEO-1

This is the core structure of the functional model. It represents the idea that a functional description of a product can be, and generally is, composed of large units of function which divide into smaller units of function until the designer arrives at his most discrete units. The design process probably is an iterative one of dividing large units into smaller and combining small units into a desired larger function.

Every identifiable unit of function appears as an instance of a Defined Functional Unit. A Defined Functional Unit may be a component of a higher functional assembly and it may have components of its own.

The key of the Defined Functional Unit is a Functional Unit ID. The developers of the model believe that this is not a "part number". It is a descriptive name which implies the function. [When this model becomes a part of the larger product model, it is anticipated that there will be some higher level context entities whose keys will migrate to become part of the identification (key) of the Defined Functional Unit]

Each instance of a Defined Functional Sub Unit Occurrence represents the data that a Defined Functional Unit is used as a component of another. The key of the Defined Functional Sub Unit Occurrence consists of the concatenation of the identification of the higher assembly (Higher Unit ID.Func Unit ID(FK)) and a unique identifier assigned to each component within the higher assembly. The most familiar form of such an occurrence identifier is a reference designator (this is what is used in the appendix A1 examples).

The non-key attribute of the Defined Functional Sub Unit Occurrence is the migrated key (Sub Unit ID.Func Unit ID(FK)) of the Defined Functional Unit which is the specific component in this occurrence.
These two entities with their two relationships provide the model for the data which describes all of the levels of assembly. The key of the Defined Functional Unit at the highest level of assembly will never appear in the Sub Unit ID role and the keys of Defined Functional Units at the lowest level of assembly will never appear in the Higher Unit ID role.

3.1.1.2 FEO-2

A Defined Functional Unit contains one or more Defined Functional Ports. A Defined Functional Port is a logical place of access to the function of the Defined Functional Unit. This is consistent with the definition in IEEE Standard 100. Whenever a logical point of access is defined by the designer as a place of functional connection, or by a test engineer as a point for functional test, that act creates a Defined Functional Port.

The identification (key) of a Defined Functional Port is the migrated key of its owning Defined Functional Unit plus a unique ID (The examples in appendix A1 use a number).

3.1.1.3 FEO-3

When a Defined Functional Unit is used more than once in the same higher assembly, there is a need for a unique identification for each occurrence of its ports so that one can be distinguished from another. This is the purpose for the Electrical Node entity.

An Electrical Node is a specific instance of a Defined Functional Port within a next higher functional assembly. Concatenating the complete migrated key from the Defined Functional Sub Unit Occurrence with the Port ID from the migrated key of the Defined Functional Port provides the unique identification of each Electrical Node.

The Functional Unit ID(FK) of the Defined Functional Port is not required for identification of the Electrical Node, so it migrates to a non-key position.

3.1.1.4 FEO-4

Readers having difficulty with this portion of the model are invited to examine the test circuit and instance table in appendix A1 as an aid.

Now that the identifications of Defined Functional Ports and Electrical Nodes have been established, it is possible to define logical connectivity among the functional units. It is important to keep in mind that no physical design data is present. Logical connectivity is data that functional units are tied together in specific ways.

A Defined Functional Unit which to the definer is a "black box" with no knowledge of its details has no known connectivity and therefore contains no Defined Electrical Logical Links.

A Defined Functional Unit which has known details and connectivity will contain one or more Defined Electrical Logical Links.

A Defined Electrical Logical Link must contain at least one Electrical Node and may contain more. This is established by one or more related instances of Electrical Logical Link Nodes.
A Defined Electrical Logical Link may include not more than one Defined Functional Port and may include none. This is established by zero or one related instance of Electrical Logical Link Port.

Therefore, the smallest possible Defined Electrical Logical Links are composed of either, two instances of Electrical Logical Nodes or one instance of Electrical Logical Link Port and one instance of Electrical Logical Link Node.

Defined Functional Ports and Electrical Nodes cannot be members of more than one Defined Electrical Logical Link. This is simply a matter of logic. Since the Defined Electrical Logical Link represents logical points that are electrically in common, joining two links through a common node would have the effect of joining two links into a single logical link. The same logic applies to ports.

Ports of Defined Functional Units which have not been used in higher functional assemblies are not members of links. Electrical Nodes which are unused in the next assembly are also not members of links.

At this point, the model provides for the fundamental data of logical connectivity. When the physical solution data model has been developed, there will be some mapping from the Defined Electrical Logical Link to the entities which establish the physical description where that logical connectivity is implemented.

3.1.2 BEHAVIOR

The next portions of the model are a limited set of entities and relationships indicating the manner in which the data of behavior may be modeled. There seem to be two kinds of behavior or characteristics. One is a dynamic sort of behavior which is described as output variations due to input variations. The other seems to be a thought of as static characteristics such as the those of a fixed resistor. FEO's 5, 6 and 7 are about the dynamic characteristics and FEO 8 about static characteristics.

3.1.2.1 FEO-5

Within the limited time available, the team set a narrow definition of "signal". It is defined for this model as a difference in electrical potential. That difference must appear between two Defined Functional Ports. This is the Defined Electrical Signal.

The identification (key) of a signal is a concatenation of the identification of the two ports between which it is defined and a signal ID which is unique within the Defined Functional Unit to which the ports belong.

3.1.2.2 FEO-6

Because it is sometimes necessary to establish that an output signal is dependent on more than one input signal, the model provides for collecting one or more signals into a Defined Functional Unit Input State. This is accomplished by the Defined Input State Signal entity. A Defined Electrical Signal may not be part of any input state or it may be part of one or more. Every Defined Functional Unit Input State must have at least one related instance of Defined Input State Signal.

3.1.2.3 FEO-7

In this diagram, we see some signals identified as Defined Functional Unit Output Signals. The fact that an output is dependent upon one or more input states of the same functional unit is established through the Defined Functional Unit Output Signal Related Input State entity.
The entity, Defined Functional Unit Output Signal Propagation Delay Definition, is modeled to show how to provide for data that an output signal is only required to be present within a specified time after an input state has been established.

3.1.2.4  FEO-8

The entity, Defined Electrical Property, is modeled to show how the static characteristics of behavior or function may be introduced into the data model. These are characteristics such as resistance and inductance. The model is merely a first guess. There is considerable work yet to be accomplished. It is anticipated that a more complicated data model will result with many entities and relationships. However, it is expected that they will still be related to ports of functional units.

3.1.2.5  FEO-9.2

The functional designer may find it necessary to collect Defined Electrical Logical Links into groups in order to express a requirement applying to the group. The Defined Electrical Logical Link Group provides this capability. A Defined Electrical Logical Link Group has one or more Defined Electrical Logical Group Members.

Two kinds of constraints may be specified with regard to electrical logical links. A constraint which applies only to a single link is provided by the Defined Electrical Logical Intralink Constraint. The idea here is that the functional designer can specify some limitation which must be met in the physical design which implements the function. An example might be that the link is specified to be a certain fraction of a wavelength at an operating frequency.

The other kind of constraint is a requirement that the physical solution must meet some specified functional condition between groups of links. This is provided for by the Defined Electrical Logical Interlink Constraint. Here is where the physical design might be constrained to some maximum capacitance between link groups.

The task team did not have time to explore these constraint ideas in any detail. This is an area of the model which could be expanded by another modeling team.

3.1.2.6  FEO-10

This is the complete model developed by the task team. FEO's 1 through 9.2 have provided the explanation of the model treating each major concept separately.

3.2  MODEL DIAGRAMS

The pages which follow contain the FEO's which are the diagrams of the model.
3.3 MODEL GLOSSARY

3.3.1 ENTITY DEFINITIONS

Defined Electrical Logical Intralink Constraint

Data which sets limiting values for a functional characteristic, contained within a single network, which must be satisfied by the physical design in which the corresponding physical connections are implemented. An example might be a length constraint in terms of wavelengths at a specified operating frequency.

Defined Electrical Logical Link

Data about the logical electrical connectivity within a Functional Unit. It establishes a set of two or more Electrical Nodes or one Defined Functional Port and one or more Electrical Nodes as being electrically in common.

Defined Electrical Logical Link Group

Data that establishes that one or more Defined Electrical Logical Links are combined into a group for some purpose.

Defined Electrical Logical Link Group Member

Data that a Defined Electrical Logical Link is a member of a Defined Electrical Logical Link Group.

Defined Electrical Logical Link Intergroup Constraint

Data which sets limiting values for a functional characteristic among Defined Electrical Logical Link Groups which must be satisfied by the physical design in which the corresponding physical connections are implemented. Examples would be capacitance limits or an insulation resistance requirement.

Defined Electrical Property

Data about electrical characteristics of a Defined Functional Unit existing between two Defined Functional Ports. For example, resistance, capacitance or inductance which are usually thought of as "static" rather than "dynamic". (These properties do have some variation such as the temperature coefficient of resistance for a resistor).

[Entities and attributes to capture the data of these variations have not yet been modeled.]
Defined Electrical Signal

Data used to define the behavior of a Defined Functional Unit, expressed in terms of electrical potential difference between two Defined Functional Ports. It is through the data which defines the relationships of output signals to input signal states that dynamic behavior of "active" Defined Functional Units is captured. The characteristic curves of a transistor can be derived by common, curve fitting algorithms from sets of these data.

Defined Functional Port

Data describing the logical accessibility to one of the functions of a Defined Functional Unit. (These ports are what is represented by lines or other graphic symbols identifying inputs and outputs for electrical devices. The port is a characteristic of a Functional Unit definition without its having a usage. The port can be thought of as a window through which the boundary networks of the functional unit are seen. When a Defined Functional Unit is given an instance of use (Defined Functional Sub Unit Occurrence), then the port becomes an Electrical Node of its higher assembly.)

Defined Functional Sub Unit Occurrence

Data that a particular Defined Functional Unit occurs as a component of another Defined Functional Unit. There is an instance of this entity for each occurrence of a Defined Functional Unit within the same higher level Defined Functional Unit. This provides a functional view of the various levels of component/assembly product relationship.

Defined Functional Unit

Data about the functional, or performance, aspects of a portion of a system. A Defined Functional Unit may be a sub unit of another Defined Functional Unit and it may have sub units of its own.

Defined Functional Unit Input State (a set of stimuli)

Data about conditions for a specific Functional Unit. (Through the Defined Input State Signal associative entity, a particular input state is defined as consisting of one or more Defined Electrical Signals, in the electrical application.)

Defined Functional Unit Output Signal Related Input State

Data that establishes that a Defined Functional Unit Output Signal results from a Defined Functional Unit Input State.

Defined Functional Unit Output Signal

An output signal of a particular Defined Functional Unit.
Defined Functional Unit Output Signal Propagation Delay Specification (response time)

Data that a Functional Unit Output Signal is required to be present within a specified time after the related Specified Functional Unit Input State has been established.

Defined Input State Signal

Data that establishes a particular Defined Electrical Signal as being a part of a Defined Functional Unit Input State.

Electrical Logical Link Node

Data that an Electrical Node is part of a Defined Electrical Logical Link.

Electrical Logical Link Port

Data that a Defined Functional Port is part of a Defined Electrical Logical Link. Each Defined Functional Port can be a member of only one Defined Electrical Logical Link.

Electrical Node

Data about a logical (functional) accessibility to the functionality of a specific occurrence of a Functional Unit. This entity serves to collect the Defined Functional Port ID (e.g., Pin Number) together with the reference label of the occurrence of the Defined Functional Sub Unit Occurrence (e.g., U2-Pin 1).

3.3.2 ATTRIBUTE DEFINITIONS

Defined Electrical Property Name

The name of a specific Electrical Property existing between two Ports of a Defined Functional Unit. These are such names as Resistance, Capacitance, Inductance, etc..

Defined Electrical Property Units

Identification of the kind of units in which an Electrical Property Value is expressed. Examples are Ohms, Farads, etc...

Defined Electrical Property Value

The value, or quantity, of an Electrical Property

Delay Specification

An expression of a constraint of the delay from the establishment of the related Defined Functional Unit Input State before the Defined Functional Unit Output Signal must be present. Most likely expressed in time units.

[Further examination of this attribute will probably result in additional attributes and, perhaps, entities.]
Electrical Logical Link ID

An identification of an Electrical Logical Link which is unique within a particular Defined Functional Unit. May be numeric or alphabetic.

Electrical Logical Link Group ID

An identification of an Electrical Logical Link Group which is unique within a particular Defined Functional Unit. May be numeric or alphabetic.

Functional Unit ID

A unique identifier assigned by the enterprise to each Defined Functional Unit. Most commonly this is a meaningful name. An example might be "multiplexer assembly".

[When the present model is integrated into a larger enterprise or PDES conceptual data model it is probable that a completely unique identification will require a concatenation of several attributes. These are likely to include the identification of the enterprise which establishes (or owns) this definition and a product or model identification as well as a functional unit name.]

Input State ID

An identifier assigned by the enterprise to each input signal state within the definition of a Defined Functional Unit. Thus, the identifier is unique only within the context of a specific Defined Functional Unit and the combination of Functional Unit ID and Input State ID is unique within the enterprise.

Port ID

An identifier assigned to each Defined Functional Port of a Defined Functional Unit.

Signal ID

An identifier assigned to uniquely distinguish a signal, which appears between the same pair of ports, from another.

(If the functional unit that is being defined is a digital unit, then typical signals are trains of digital pulses. These can be most simply defined as two signals, a high and a low. Where the functional unit is something such as a transistor, there could be many signals defined, each having a different voltage value.)

Signal Units

Identification of the kind of units in which the value of the signal is expressed.

Signal Value

A number indicating the quantity of the units of the particular signal.
Sub Unit Occurrence Identification

An identification assigned to a particular occurrence of a Defined Functional Unit within another Defined Functional Unit. (The most common form of this in electrical design is a reference designation. The same functional resistor used twice in a higher unit might be designated R1 in one occurrence and R2 in the other.)

3.4 BUSINESS RULES OF THE DATA MODEL

This section presents the business rules of the E/E conceptual model in English. The rules are grouped by entities. Entity names are distinguished by bold italics. The number scheme below does not correspond to number schemes used in other documentation.

1. A Defined Functional Unit has 0, 1, or many Defined Functional Unit Input States.
2. A Defined Functional Unit contains 1, or many Defined Functional Ports.
3. A Defined Functional Unit is 0, 1, or many Defined Functional Sub Unit Occurrences.
4. A Defined Functional Unit has 0, 1, or many Defined Functional Sub Unit Occurrences.
5. A Defined Functional Unit contains 0, 1, or many Defined Electrical Logical Links.
6. A Defined Functional Unit contains 0, 1, or many Defined Electrical Logical Link Groups.
7. A Defined Functional Unit Input State is 0, 1, or many Defined Functional Unit Output Signal Related Input States.
8. A Defined Functional Unit Input State is composed of 1 or many Defined Input State Signals.
9. A Defined Functional Port is a reference port for 0, 1, or many Defined Electrical Property(ies).
10. A Defined Functional Port is a measurement port for 0, 1, or many Defined Electrical Property(ies).
11. A Defined Functional Port is a reference port for 0, 1, or many Defined Electrical Signals.
12. A Defined Functional Port is a measurement port for 0, 1, or many Defined Electrical Signals.
13. A Defined Functional Port is 0 or 1 Electrical Logical Link Ports.
14. A Defined Functional Port becomes 0, 1, or many Electrical Nodes.
15. A Defined Functional Sub Unit Occurrence contains 1, or many Electrical Nodes.
16. A Defined Electrical Logical Link includes 0 or 1 Electrical Logical Link Ports.
17. A Defined Electrical Logical Link is composed of 1 or many Electrical Logical Link Nodes.
18. A Defined Electrical Logical Link has 0, 1, or many Defined Electrical Logical IntraLink Constraints.
19. A Defined Electrical Logical Link is 0, 1 or many Defined Electrical Logical Group Members.
20. A Defined Electrical Logical Link Group is the 1st logical link group of 0, 1, or many Electrical Logical Link Defined Constraints.
21. A Defined Electrical Logical Link Group is the 2nd logical link group of 0, 1, or many Electrical Logical Link Defined Constraints.
22. A Defined Electrical Signal is 0, 1, or many Defined Functional Unit Output Signals.
23. A Defined Electrical Signal is 0, 1, or many Defined Input State Signals.
24. A Defined Functional Unit Output Signal has 0 or 1 Defined Functional Unit Output Signal Propagation Delay Definitions.
25. A Defined Functional Unit Output Signal results from at least 1 Defined Functional Unit Output Signal Related Input State.
26. An Electrical Node is 0 or 1 Electrical Logical Link Nodes.

4. CONCLUSIONS AND RECOMMENDATIONS

As a result of the modeling efforts and the subsequent reviews, the core members of the team reached some conclusions and have some recommendations as follows:

4.1 CONCLUSION - THE PRESENT MODEL IS A START

The present model is seen by the team as a core structure. The connectivity data appears to be the most stable portion of the model.

The Defined Functional Unit and Defined Functional Sub Unit Occurrence relationships will alter when the effects of change are introduced into the model. There is a present concept in much of the manufacturing industry that some changes result in variations, or versions, of units while others result in new units. This concept is not covered in the present model.

The Defined Functional Port seems to be a strong idea. We believe that it is the key entity to which behavioral data relates. There is a great deal of work to do in the data of behavior and function.

There is a need for a data model for the physical part description of some electronic items. Then the mapping between the functional description and a physical description can be discovered.

4.2 RECOMMENDATIONS

4.2.1 MORE TESTING IS REQUIRED

The model should be subjected to additional testing and verification. This needs to be performed in a more formal process than the reviews conducted to date.

The model should be entered into JANUS at the IISS Test Bed at ASU or the AMRF or both. In JANUS, the normalization of the model should be checked.

After the JANUS verification, a database should be created and populated with data from test case parts. The database should then be tested to prove the data model by performing test queries.
4.2.2 ADDITIONAL MODELING IS REQUIRED

4.2.2.1 Data for a Physical Part

It is recommended that a sample printed circuit card assembly be adopted as a test case. A modeling team should work to develop a data model for the physical description of the printed circuit card and the components which mount on it. This team should attempt to make use of the mechanical products model and the work being performed on form features.

4.2.2.2 Change Data

The data representing change needs to be added to the models. It is recommended that this be deferred in hopes that a specific team will be formed to model the data for configuration management.

4.2.2.3 Function and Behavior Data

There is much work to be done for this type of data. A sequence by which this large scope might be attacked would be as follows:

a. Begin with the model of functional data for simple electronic parts such as resistors and capacitors. Model the characteristics of these one at a time by analyzing the data sheets for such devices and developing appropriate data model extensions.

b. Model "active" devices starting with simple devices such as individual diodes and transistors and then progressing to complex electronic devices such as integrated circuits. Here again, the approach should be to analyze data sheets and specifications to determine the data which describes function and behavior.

It is believed that the data resulting from these tasks is the essential performance data required for a components library. As such it should be of considerable interest to industry.
APPENDIX A1

DATA MODEL CONNECTIVITY TEST CASE
AND
INSTANCE TABLES

April 30, 1987
1. TEST CASE CIRCUIT AND DATA INSTANCE TABLE

1.1 THE TEST CIRCUIT

Figure A1-1 is a simple schematic type of diagram providing a test case with two levels of assembly. It also contains an example of a part with multiple uses, some in the same next assembly. It should be noted that there is no idea of physical characteristics intended here. The schematic indicates only function.

The tables on the following pages represent the data of functional component/assembly relationships and the connectivity of the test case. Each table represents one entity in the data model and is identified by the entity name. Each row of a table equates to one instance of the entity. The columns of the table are the attributes within the entity. The columns to the left of the heavy vertical line represent the key attributes of the entity.

![Figure A1-1](image-url)
### Defined Functional Unit

<table>
<thead>
<tr>
<th>Func Unit ID</th>
<th>&quot;&quot;</th>
</tr>
</thead>
<tbody>
<tr>
<td>IN NI Res</td>
<td>&quot;&quot;</td>
</tr>
<tr>
<td>1st Cap</td>
<td>&quot;&quot;</td>
</tr>
<tr>
<td>Voltage Div</td>
<td>&quot;&quot;</td>
</tr>
<tr>
<td>Le Pass FB</td>
<td>&quot;&quot;</td>
</tr>
<tr>
<td>Func Assy</td>
<td>&quot;&quot;</td>
</tr>
</tbody>
</table>

### Defined Functional Sub Unit Occurrence

<table>
<thead>
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<th>Higher Unit ID Func Unit ID</th>
<th>Sub Unit Doc ID</th>
<th>Sub Unit ID Func Unit ID</th>
</tr>
</thead>
<tbody>
<tr>
<td>Func Assy</td>
<td>A1</td>
<td>Voltage Div</td>
</tr>
<tr>
<td>Func Assy</td>
<td>A2</td>
<td>Le Pass FR</td>
</tr>
<tr>
<td>Voltage Div</td>
<td>R1</td>
<td>IK NI Res</td>
</tr>
<tr>
<td>Voltage Div</td>
<td>R2</td>
<td>IK NI Res</td>
</tr>
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<td>Le Pass FR</td>
<td>R1</td>
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### Defined Functional Port

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</table>
1.2 TEST QUERY

There is a symbol on the test circuit indicating that Port 4 of the Functional Assembly is connected to ground. The test query is to determine all of the Nodes/Ports which are logically connected to this ground.

On the page which follows, the navigation through the tables needed to answer the query is shown. In each row of the table the data needed to inquire is shown with a dotted fill and the data needed as the answer is shown with a heavy outline. The answer from one table provides the query data for the next table as well as being, in some cases, part of the answer to the general question.
APPENDIX A2

MAPPING THE MODEL TO IGES

April 30, 1987
1. MAPPING THE MODEL TO IGES

At the Dayton review, John Zimmerman presented a mapping he had developed between the Cal Poly model connectivity and the entities of IGES Version 3.0 provided for that purpose. This mapping was an example of the use of a conceptual schema model to examine an internal schema. IGES, as a transfer format specification is an example of an internal schema.

After the Dayton review, Curt Parks performed more analysis of the mapping to IGES. The results of the combination of John Zimmerman's and Curt Parks' work are discussed in this appendix.

IGES is based on the idea of providing a standard, neutral format for exchange of files among graphics systems. Such files represent "pictures" to be displayed on CRT's along with data which establishes some meanings for the elements seen in the pictures. IGES, therefore, includes entities which are "graphic" entities providing visual presentations of conceptual entities such as curves and surfaces.

IGES provides entities by which to transfer data present in sending systems. If an originating system does not contain certain kinds of data, it is not required to appear in the transfer file. A major difference of PDES is the use of a data model to establish requirements for data which must be present and meanings of the data for correct interpretation. A PDES transfer should be interpretable by a computer program. An IGES file may require human interpretation of its presentation on a graphics screen.

An IGES file may be a representation of an electrical schematic. An electrical schematic is, basically, a functional representation. The Cal Poly model is a functional model. Therefore, the applicable mapping is to the IGES schematic representation.

An aid to understanding how to use the IGES format for electrical data is the IGES Version 3.0 Electrical Applications Guide, EACP-1.4, dated 6/1/86 available through the IGES project at the National Bureau of Standards, Gaithersburg, MD.

It should be noted that the Cal Poly model is a relational model describing data integrity by relationships among entities. In the IGES file structure, relationships tend to be implemented as pointers.

In IGES electrical schematics, the component/assembly relationship is implemented by nesting instances of Network Subfigures (entity 420) which represent functional units within others. The indication that a Network Subfigure is a representation of a functional unit is the presence of a pointer to a Part Number Property (entity 406, form 9) in the Network Subfigure Definition (entity 320). IGES permits the identification of a collection of entities in a file which represent the "top assembly" as a Network Subfigure. However, this is a case where this is an IGES option. Thus, the mapping from the Cal Poly model of the hierarchy of functional units may be "bald headed" in an IGES file because the top assembly is not explicitly identified. (The identification of the file itself in the Global Section may be the identification of the top assembly).

Connectivity in an IGES file is established by Flow Associativities (entity 402 form 18). A Flow Associativity "links" Connect Points (entity 132) logically together by pointers from the Flow Associativity to the Connect Point. Flow Associativities may point to each other.

Both the Defined Functional Port and Electrical Node of the Cal Poly model map to Connect Points. IGES does not make the port and node distinctions made by the model. It is interesting that VHDL does have the same distinctions represented by Formal Port and Actual Port.
Figure A2-1 is the test case circuit from Appendix A1 modified to illustrate the way IGES implements connectivity. The filled squares are IGES Connect Points which represent Defined Functional Ports and Electrical Nodes required by the Cal Poly model. The open circles are Connect Points required by IGES in order to locate lines correctly on graphic schematic presentations.

There is a mapping from the Cal Poly model Defined Electrical Logical Link to the IGES Flow Associativity. However, there is a subtle difference. In an IGES file for Figure A2-1 where the component/assembly hierarchy is present, the connectivity in the Voltage Divider between port 1 of R1 and port 1 of the Voltage Divider would be a Flow Associativity. The connection in the Functional Assembly between port 1 of the Voltage Divider and port 1 of the Functional Assembly would be another Flow Associativity. Each of these Flow Associativities would include a pointer (CFPTR) to the other to establish the link providing the continuity between levels of the hierarchy from port 1 of the Functional Assembly to port 1 of R1.

The Cal Poly model establishes this linkage through the Electrical Logical Link Port entity and the relationship that identifies that same port as an Electrical Node of a higher functional assembly (see the examples in Appendix A1).

This mapping is an example of relating a conceptual schema model to one internal schema as represented by a file format. Other formats such as VHDL and EDIF may be related in a similar manner.

![Figure A2-1](image-url)
APPENDIX A3

LIST OF ISSUES

April 30, 1987
ISSUE #

1. 3/18/87

**ISSUE:** CONNECTIVITY

**DISCUSSION:**

Connectivity has been examined. It was determined that more than one entity would be needed to capture the functional interconnections in a PWB. Functionality must be separated from physical implementations and entity definitions should be explicit in this respect. There is a need to consider logical (functional) connectivity separately from physical connectivity.

**RESOLUTION:**

The issue is partially resolved as of 2/4/87.

We have separated functional (logical) connectivity from physical connectivity. An instance of functional connectivity is modeled as a Required Electrical Network (Renamed Defined Electrical Logical Link).

We have not yet established a particular model of the physical connectivity. We have tentatively adopted a concept of Path to represent a physical connectivity. We think that Paths may be composed of Sub Paths with Physical Interfaces. The model will map the functional connectivity onto the physical connectivity by associative entities relating Required Electrical Networks to Paths.

2. 1/20/87

**ISSUE:** ELECTRICAL AND ELECTRONIC REFERENCE DESIGNATORS

**DISCUSSION:**

There is a lot of discussion possible about these and how they are used.

3. 1/20/87

**ISSUE:** SUBSTITUTE AND ALTERNATE PARTS

**DISCUSSION:**

SUBSTITUTE_PART is found in Source Document #2 (Westinghouse PWA Study). The possibility exists of more than one substitute part for an item on a parts list. Substitute parts are also program dependent.

Substitute part and Alternate Part are similar ideas, but there appears to be some distinction between them. The Mechanical Products team in Peoria have some ideas on these.
Parts that are components on higher assemblies must often be submitted for approval from the customer. Alternate parts, superseded parts, and substitute parts must be submitted to various authorities for approval. It is not clear what the definitions of each of these terms should be.

4. (Combined with issue #3)

5. 1/21/87

**ISSUE:** FILL PATTERN

**DISCUSSION:**

Graphical Entities from the UK EDIF Support Document such as Fill Pattern need to be understood to see if they represent conceptual data required in our model. It was also suggested that graphical characteristics such as fill color were actually representations of other meanings which should be discovered.

6. 1/21/87

**ISSUE:** SIGNAL ARRAY

**DISCUSSION:**

Signal Array from the UK EDIF Support document needs clarification. Our interpretation is that it represents a set of "signals" that may be carried on an instance of ELECTRICALNETWORK. Other entities that may require clarification are those associated with INSTANCE and PATH.

**RESOLUTION:**

Signal Array has been deleted from EDIF 200. This issue is closed.

7. 1/21/87

**ISSUE:** PRODUCT DEFINITION DOCUMENT

**DISCUSSION:**

The definition for the conceptual entity Product_Definition_Document needs clarification. There are many source elements, some of which may be out of scope anyway, which may be mapped into this conceptual entity.
8. 1/25/87

**ISSUE:** GROUND

**DISCUSSION:**
From a functional standpoint, Ground seems to be a Node rather than an Electrical Network. Electrical designers frequently designate more than one Ground. (e.g. Signal Ground, Power Ground, etc.) These serve to identify requirements that these nodes are references for different collections of functions and that the physical designer is to keep these distinct and avoid "ground loops".

3/18/87

There is a developing belief that Ground is more likely to be a special kind of signal.

9. 1/25/87

**ISSUE:** POWER

**DISCUSSION:**
Power (B+) seems to be another Node idea like Ground.

3/18/87

Power seems also to be a kind of signal.

10. 2/4/87

**ISSUE:** OWNERSHIP OF SHAPE/SIZE

**DISCUSSION:**
The Shape/Size entity recognizes the existence of definitions of dimensions and tolerances for items which apply to more than one item. That is, there are many different part numbers with the same shape, size and tolerances. An example of this is resistors where there are over 30,000 different MIL Standard part numbers for just 1/4 Watt metal film resistors with the same shape, size and tolerances.

The existence of a multiple use Shape/Size brings up the need to identify whose Shape/Size it is. That is, there is an owner of the definition who must be associated with it. In the case of industry, National or International Standards, there is a custodian of the Standard who is the owner. In the case of sharing of data among different enterprises, a Shape/Size must be identified with the enterprise who owns it.
11. 2/6/87

**ISSUE:** HOW SHOULD ENVIRONMENTAL REQUIREMENTS BE MODELED?

**DISCUSSION:**

In VHDL, ambient temperature is introduced as a requirement through a "PORT". The VHDL solution may work well within their specific application but we need to consider a more general solution which accommodates all environmental constraints.

12. 2/10/87

**ISSUE:** UNIQUENESS OF PART NUMBERS. - COULD THERE BE DUPLICATE PART NUMBERS WITHIN AN ORGANIZATION?

**DISCUSSION:**

Some task team members believe that the answer is yes, depending on the level of design. This is something that needs to be tested. A variety of different enterprises should be asked. There has long been a belief in many places that the combination of the owning enterprise identification and its part number is unique.

13. 2/10/87

**ISSUE:** FUNCTIONAL UNITS VERSUS IMPLEMENTATIONS

**DISCUSSION:**

A functional unit may have 1 implementation (1 design) but 2 distinct functional interfaces. The behavior is the same in both cases, but the description of the behavior is different. An example of this is the part 74LS138 which may be used as a binary/decimal decoder or a demultiplexer. Are the binary/decimal decoder and demultiplexer different functional units which may be implemented by the same physical design?

**RESOLUTION:**

See issue 16 and Appendix A4 items 15, 16, and 17

14. 2/10/87

**ISSUE:** SIGNAL BUNDLES/BUSESSES

**DISCUSSION:**

A bundle of signals, a bus, is a notational and graphical convenience for schematics. The connectivity expressed via a bus construct can be expressed using the concepts of the electrical network (Renamed Defined Electrical Logical Link).

During high-level design, a bus may be defined without specifying its width. Can this be handled with the electrical network concept?
15. 2/10/87

**ISSUE:** CONSTANT FUNCTIONS

**DISCUSSION:**

A constant function is a functional unit whose output is always the same, regardless of the inputs. There are familiar examples such as voltage regulators whose purpose is to flatten out variations of input into unvarying output.

There are also some times when digital devices are involved when there seem to be needs for an idea of unchanged output. The examples of this seem to be issues involving simulation ideas and the description seems to be talking in "Green Stuff":

a) allowing 0 input states which results in 1 output (all inputs are "don't care" by default), or

b) introducing the notion of "don't care" signals.

16. 2/18/87

**ISSUE:** SEPARATION OF DEMAND REQUIREMENTS FROM DESIGN SOLUTIONS

**DISCUSSION:**

As a result of proposals in PDES, the PDES Product Data Planning Model has separated the ideas of functional characteristics data from physical characteristics data.

In the Cal Poly modeling, there were discussions and diagrams drawn which included such ideas as a "Logic Diagram" and truth tables (expressed in T's and F's or 0's and 1's) being part of the design of some systems. A question was raised about where data of this sort fits in the model.

There is a view that the "Logic Diagram" and the T-and-F or 0-and-1 Truth Tables are a form of demand requirements at a fairly detailed level. A Truth Table represents a requirement for logic which may be satisfied by more than one technological solution. For example, logic can be implemented by fluidics or electronics. In electronics we have various solutions to choose from such as ECL and TTL.

When a specific solution technology is chosen, then the characteristics of the design solution must be expressed in terms of the units of the chosen technology. For example, if the chosen solution is electronic, the characteristics become expressed in transistors, resistors, capacitors, etc. and their details in ohms, volts, amperes, etc.

**RESOLUTION:**

We have recognized three separate structures rather than two. The first structure is the breakdown of demand requirements. Then there is a structure of definition of functional characteristics. This second structure is defined in terms of a chosen technology. The third structure is the breakdown of the physical characteristics of the design solution to the requirements. Between any two of these structures, it is unlikely that there will be a one-to-one map between the units.
A FEO was developed at Cal Poly to illustrate the three structures. Because the structures were each drawn in a different color, they became referred to as "green stuff", "blue stuff" and "red stuff". The figure below is this FEO.
17. 3/12/87

ISSUE: FEEDBACK

DISCUSSION:

There are cases where an output signal depends not only on some present state, but on some prior state or condition as well. The model at this time will not satisfy this.

18. 3/12/87

ISSUE: DELAY/TIME BASED PHENOMENA

DISCUSSION:

The model needs to provide for signal relationships which vary by defined frequency, time, phase, etc.

19. 3/12/87

ISSUE: ORDERED SETS OF SIGNALS

DISCUSSION:

The model needs to provide for relationships of ordered sets of signals.

20. 3/12/87

ISSUE: NON-VOLTAGE SIGNALS

DISCUSSION:

Many electrical units have inputs and/or outputs which are not voltage. Some signals seem to be physical motion (e.g., the movement of the toggle on a switch, the rotation of a motor armature) or radiation (e.g., the light from a flashlight, infrared from an electric heater, etc.).

21. 3/12/87

ISSUE: ANALOG AND PERIODICALLY REPEATING SIGNALS

DISCUSSION:

The model should provide a means for expressing signals such as sine waves or repeating sawtooth voltages.
22. 3/25/87

ISSUE: SHOULD SIGNALS BE DEFINED ON BOTH PORTS AND NODES?

DISCUSSION:

There was considerable discussion on this. Ports are defined as the logical places where functions of a functional unit are accessed. The common view is that the original designer establishes the ports of the functional unit when he designs it. Normally these are the places which are involved with the functional connection of the functional unit to some other functional unit.

It is also not unusual for someone deciding how to test units in production, or in service, will decide that it will be necessary to define "signals" at places within the networks of the functional unit which were not defined as ports by the original designer. It is believed that persons doing this are also defining ports. These "test points" seem to satisfy the definition of "Port". Not all ports are defined at the time of first design.

23. 3/25/87

ISSUE: ARE THERE SIGNALS WHICH ARE "ONE PORT" SIGNALS?

DISCUSSION:

When discussing signals, we explored various different kinds of signals which might be involved in describing the behavior of functional units. Some things within the scope of electrical products are energy converters or electro-mechanical units. These give rise to "signals" which are in the form of radiation (e.g., the light from a flashlight, heat from an electric heater, the infra-red signal from the TV remote controller), physical force (e.g., the shaft torque of an electric motor), etc.

Are there two ports involved in the "light" signal from the flashlight, or only one?
APPENDIX A4

GENERAL RECORD OF DISCUSSIONS

April 30, 1987
GENERAL

This appendix is provided as documentation of the discussions during the development of the model. It is included so that readers may have some sense of the arguments and analyses which took place. Not all of the opinions captured were unanimous or even consensus views. Some still represent strong differences of opinion.

1. **PODES PLANNING MODEL.** The PODES planning model is a management tool. It defines the scope of product data, thereby describing the scope of PODES. It is used to establish the context for the detailed, refined conceptual models. With the PODES planning model it is possible to see aspects of conceptual product data which cross all disciplines such as the bill of materials.

2. **CONCEPTUAL DATA.** A conceptual data model talks about data; it contains the fundamental data elements of an enterprise. Fundamental data elements are combined to create compounds. These compounds constitute the external views. The procedures for creating the compounds are unique recipes or instructions for manipulating elementary data. These procedures are unique entities in their own right. Are these recipes part of the conceptual data model? No.

The conceptual data model captures the meaning and relational integrity rules for data of an enterprise. It does so in a way that makes it independent from the uses of the data for information and the manner of physical storage of the data. Much of the data we are accustomed to using as people is presented to us in a form of symbols to which we have attached meaning. An example of this is the familiar notation of music. The sheet music presents a complex set of symbols designed for human comprehension. The lines and spaces of the treble clef actually stand for a musical scale of predefined tones or audible frequencies. The open and filled ellipses of notes with their attached lines are symbols conveying tone and duration to humans. It is the meanings of the musical symbology which are the domain of conceptual data modeling.

The conceptual data model does not tell one how to arrive at the data. Rather it depicts the relationships among the fundamental data items of the enterprise. For instance, a conceptual model does not contain the rules/procedures necessary to create a schematic (an external view of the raw data) although it does contain all of the data elements (and their interrelationships) necessary to construct this external presentation view of the functionality of the circuit. The rules for deriving external views are user-specific. The proper place for these rules might be the external schema.

We tend to get into arguments over what is conceptual data. This is to some degree because there are a number of different concepts of our enterprises which various disciplines are trying to model. We need to separate those concepts which are different from each other and give them different names. The developing world of Artificial Intelligence (AI) is where some of these come to light. AI is concerned with the meanings and referential integrity rules which we are modeling in the conceptual data model. They are also concerned with other kinds of rules that the enterprise has established. Some of those rules are for manipulating the fundamental data to derive information for specific purposes. Some of those rules are the knowledge of how certain activities of the enterprise are performed which result in the creation of values of the conceptual data. We should not confuse the conceptual data with the rules for its use or creation.
3. **A CONCEPTUAL DATA MODEL FOR ELECTRICAL-ELECTRONIC DATA.** An electrical/electronic product (e/e) is a product which makes use of, transmits, or generates electricity. A product is a concept of goods, not services, sold. A conceptual data model for e/e products, using diagrams and text, depicts the entities, relationships, and attributes describing the fundamental data which defines the products over their life cycle. The present team scope is a limited subset of the total.

The current detailed conceptual model for e/e product data will contain the data that defines the functional characteristics and the physical realization of an e/e product based on a specified technology.

The data which will be captured by this model is expressed in the units of a particular technology and concerns the notions of connectivity, structure, behavior, electrical properties, and physical solutions.

a) **CONNECTIVITY:** An electrical circuit is composed of functional units connected together. Connectivity is expressed via logical or physical networks. A logical network is a collection of functional unit nodes (may include one port) which are declared to be electrically equivalent. Electrical connectivity can be expressed logically (i.e. the circuit design on a schematic), or physically, via the actual implementation of the logical idea (i.e., wire conductors, copper paths on a PWB, etc.).

b) **STRUCTURE:** Electrical products are assemblies of functional units from primitives up through appropriate levels of aggregates. This is parallel to physical assemblies. The mapping, however, is not one-to-one (4 functional gates may be in one physical package). With respect to the initial requirements which drive the functional realization, the notion of hierarchical structure pertains but is not yet fully understood. Once again, there is some kind of mapping between the initial requirements breakdown, and the functional definition breakdown.

c) **BEHAVIOR:** The behavior is the description of the functionality in the unit. There seem to be two kinds of functions. Some units, such as resistors and capacitors, usually are thought of as having “passive” characteristics even though those characteristics are subject to change from such stresses as applied voltage or temperature. Other units such as transistors are thought of as having “dynamic” characteristics. There is an additional complication in that some electrical units are “energy converters” so that their behavior involves other than purely electrical values. A flashlight, for example, has a physical force input to turn it on or off and an output of light and some heat.

i. **ELECTRICAL PROPERTIES:** These are the static, or passive, constraints on the behavior of a functional unit. These constraints cannot be derived. Examples include resistance, capacitance, and inductance.

ii. **DYNAMIC CHARACTERISTICS:** Some of these can be recognized as being described by relating signals applied as inputs to signals which appear as outputs. Some of these relationships become quite complex where an output depends not only on some present input state but on some prior condition as well.

iii. **NON-ELECTRICAL CHARACTERISTICS:** The team has made no attempt to model data for these kinds of characteristics. We can conjecture a little about the description of such simple units as a toggle switch where the electrical characteristic is dependent upon the position of some movable physical geometry.
4. **E/E CONCEPTUAL MODEL SCOPE.** There are four clusters of entities within the PDES PLANNING MODEL which have counterparts in the e/e conceptual data model.

   **FUNCTIONAL UNIT ENTITIES:** Functional Unit, Required Functional Subunit Occurrence, Functional Interface Requirement, Required Functional Characteristic.

   **SHAPE/SIZE ENTITIES:**
   Shape/Size Specification, Shape/Size element specification, Shape/Size Tolerance Requirement.

   **PHYSICAL DESIGN ENTITIES:**


   The boundary entities are those entities immediately outside the scope of the model. They include Technology-independent Specified Demand entities and Manufacturing Process entities (purchasing, quality assurance, etc.)

5. **FUNCTIONAL/PHYSICAL CHARACTERISTICS.** We have recognized at least two distinct aspects to the conceptual model of electrical/electronics data: FUNCTIONAL and PHYSICAL. The functionality of a circuit is represented by a top-level entity, functional unit. The physical realization of the circuit is represented by a top-level entity, product item. Both are hierarchical. The decompositional nature of both the functional unit and product item is depicted by the is-has dual relationship to some sub-unit occurrence entity.

   Intersection entities will be necessary to depict the correspondence between the functionality of the e/e product and the physical realization.

6. **CONTEXT ENTITY.** Functional units have unique identity within a particular business context. This suggests the need for entities which provide a global framework for uniquely identifying functional units. These entities will represent the data which describes the direction and boundary of the design effort.

   Sample definitions for these entities include:

   A. Information identifying a business concept which serves as a direction and boundary for design efforts. This is of a sufficiently abstract nature that it is not in itself a functional unit. Things such as “project”, “program” are examples. Such a “design context” distinguishes design efforts from each other.

   C. The owner of the name of the thing; the perpetrator of the thing. This seems to be the identification of the owning “enterprise”.

   The product item must fit in this new structure. It will tie either directly to the enterprise or the design context.
7. WHAT IS THE IDENTIFICATION (KEY) OF A FUNCTIONAL ITEM?

Functional Items first seem to appear in early design stages. System engineering starts to break a system down into functional block concepts. These concepts are given meaningful names. These names are the identification of the items. Examples are terms such as: Guidance Section, Signal Processor, Decoder, etc. This idea seems to continue to considerable detail where we have schematic symbols representing resistor, capacitor, transistor, NAND Gate, etc.

When we draw the block diagram or schematic, we create occurrences of the generic functional items. In order to distinguish one occurrence from another, we assign "reference designations" (i.e. R1, R2, U12).

The functional names alone do not seem to be enough. When we design similar products, we tend to use similar generic names. Therefore, we think that the identification of a Functional Unit is actually a concatenation of the generic name with a migrated key from an entity which represents the product being designed. This is probably Product Model. This is an indication that we probably need to do some modeling of the Product, Product Model, End Item and End Item Unit ideas.

8. WHERE ARE THE REQUIREMENTS?

[see also items 16 and 17]

In our data planning model, everything about the product is in fact a specification or requirement until an actual manufactured unit appears. What is released from design engineering to the manufacturing process is specifications and requirements. What is established by the manufacturing planning activity is requirements.

When a fabrication or assembly process produces hardware, if examinations or tests are performed on the hardware, for the first time actual, observed characteristics come into being.

9. LOGICAL vs. PHYSICAL NETWORKS.

More than one logical (or functional) network may exist on the same set of physical connections (Path). An example of this is in waveguide multiplexers where RT/TR functions separate transmitted signals from received signals although they share some of the same physical waveguide. Tri-State devices can be involved in this concept.

10. VHDL SIGNAL vs CAL POLY MODEL NETWORK AND SIGNAL

[The Network was renamed Defined Electrical Logical Link during later modeling activities]

We have modeled two separate ideas which we have named Network and Signal. The Network is a name for the idea of functional connections. Signal is a name for a difference in potential between two Networks (Revised to difference between ports). We have an idea named Node which represents a place where a function of a Functional Unit may be accessed. A Network is a connected set of Nodes.

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VHDL appears to use Signal to represent what we have called Network. For purposes of simulation, in VHDL values (i.e., voltages) can be assigned to Signals. Different values can be assigned to the same Signal name at different times. VHDL has a concept of Port. VHDL distinguishes between Formal Port and Actual Port. A Formal Port is an instance of a place of access to a Design Entity. When a Design Entity is "instantiated" (used in relation to some other Design Entity), a Formal Port becomes an Actual Port. The Actual Port must be assigned a name (which may be the same as its Formal Port name). The Formal Port seems to map to our Defined Functional Port and the Actual Port to our Electrical Node.

As of 6 February, we have a concept that a Node may be part of more than one Network. For example, when tri-state devices are involved, a device is sometimes functionally connected and sometimes not. This means that Networks are dynamically defined depending upon the state of the devices. [This idea of a node participating in more than one network has been rejected at all reviews of the model].

VHDL contains the idea of a Bus. It provides for a user-defined, bus arbitration rule which will define how to determine what is present on the Bus when driving devices are in different states.

11. LOGICAL NETWORK. [Note: Logical network was renamed Defined Electrical Logical Link] The e/e conceptual model contains the concept of electrical network. To have an electrical network, there must be at least one electrical network node which demands at least one electrical node which in turn demands exactly one functional subunit occurrence. An electrical network node is an instance of a port which is part of a network. Logically, one can access the network anywhere. Physically, one can access the network only at a node.

The logical network concept embodied by the model is distinct from the physical concept of connectivity. A logical network is a collection of instantiated nodes and at most one port which are electrically in common. A signal is the difference in potential between two ports. It must be defined with respect to at least two ports. A signal has a value (voltage), a measurement port and a reference port.

"Ground" is a signal of some kind.

A node or a port can belong to only one network. Sub-networks and dynamically re-configured assemblies do not fundamentally describe different networks. Different subsets do not signify unique nets in action.

A network may contain at most one port to convey the boundary conditions between levels. All ports connected to the same network are logically the same port. This allows the model to capture the logical connectivity correspondence between the internal design of functional unit A and the instantiation of functional unit A in a higher unit design.
12. NETWORK ANALOGIES.

<table>
<thead>
<tr>
<th>TOPOLOGICAL ANALOGY</th>
<th>INFORMATION TRANSFORMATION</th>
</tr>
</thead>
<tbody>
<tr>
<td>NET</td>
<td>out1</td>
</tr>
<tr>
<td>in2</td>
<td>T</td>
</tr>
<tr>
<td>FUNCTION</td>
<td>out1 = in1 &amp; in2</td>
</tr>
<tr>
<td>PORTS</td>
<td>in1, in2, out1</td>
</tr>
<tr>
<td></td>
<td>place-holders in the equation (variables)</td>
</tr>
</tbody>
</table>

13. FUNCTIONAL UNIT. A logical design of a circuit describes functions and interconnections. A function has an interface and a design. The function's design describes its subunits and the (internal) electrical interconnections among the subunits. The internal connectivity is expressed in terms of the nodes of the subunits which are electrically common. When the function is part of a larger design, the ports described by the function's interface constitute the external signal connections to the internal network.

A **nand gate** is an example of a functional unit. The functional design of the nand gate describes the subunits which compose the nand gate. The subunits include several instances of resistors, which at the next lower level are viewed as primitive functional units (a resistor cannot be further decomposed).

A primitive component may have a functional design entity. Although it has no sub-units, its behavior can be represented by signal relationships or electrical properties between ports.

The interface of the nand gate defines the external ports. The interface is the view which describes the functionality available at the ports. This may be regarded as a black-box description of the behavior of the functional unit. A black-box description is one in which the internal transformation is unknown; only the inputs and resultant outputs and the defined electrical properties are known.

Ports are windows into the functions of the functional unit. The ports are not separate entities, they are used to make associations with the internal functionality.

14. MULTIPLE VIEWS.

There is an opinion that the model must capture the the notion of functional units with distinct interfaces but identical designs. A functional unit may have one implementation (1 design) but two descriptions of what it does (2 interfaces or views). When this is the case, the behavior of the functional unit is the same, but is described in 2 distinct ways. An example of this is the 74LS138. This functional unit may be described as either a binary/decimal decoder or as a demultiplexer. The internal structure of the 74LS138 is identical whether it is used as a decoder or as a demultiplexer.
There is a differing opinion that the binary/decimal decoder and the demultiplexer are two different functional units which may be satisfied by the same physical design. This is a subtle but importantly different idea from that of multiple views.

15. **IEC CHARACTERIZATIONS.** The IEC has identified three distinct aspects of e/e data:

<table>
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<tr>
<th>Functional</th>
<th>NAND</th>
</tr>
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<tbody>
<tr>
<td>Mechanical</td>
<td>JEDEC PKG</td>
</tr>
<tr>
<td>Physical</td>
<td>TI SN74L300</td>
</tr>
</tbody>
</table>

There is not a consensus among the members of the task team that these three aspects are required. From the data model standpoint, two seem to be adequate to some members; these would be called functional and physical. The mapping between these two would appear as intersection entities in the model. There is an opinion that the IEC idea works backward from the existence of completed solutions in the form of parts. When the data model starts with the ideas of required functional solution and moves to designed physical solution, then it seems that the two aspect model appears and is a more correct model. The JEDEC Package specification seems to fit as a Shape/Size definition within the PDES planning model.

The logical characterization deals with non-electrical values (T, F, 1, 0). The mechanical characterization deals with company-specific manufactured parts. An intermediate view which expresses the abstract logical value in terms of electrical properties is needed.

<table>
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<tr>
<th>Abstract Logical</th>
<th>Electrical</th>
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<tr>
<td>T</td>
<td>+5v</td>
</tr>
<tr>
<td>F</td>
<td>0v</td>
</tr>
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</table>

This intermediate view must include electrical properties (delay, capacitance) but should not be tied to a specific manufactured part.

18 Mar 1987

Subsequent work concluded that the T (true) and F (false) descriptions are "green stuff" (see items 16 and 17). That is, they are requirements not expressed in a chosen design solution technology and are out of the present task team scope. The "blue stuff" of the present scope seems very like the "Intermediate view" expressed above. It is required to be expressed in units of the chosen solution technology. The T's and F's of "green stuff" become signals in volts in a "blue stuff" electrical solution technology.

16. **SOLUTIONS VS. REQUIREMENTS.** A solution at one level becomes a requirement at the next level in the design life cycle. The problem is that solutions must be distinguished from requirements, but at what level? The mappings probably occur at the lowest levels. The model must capture three fundamentally different concepts: requirements definition, physical definition, and functional definition.

A requirement is a statement of demand. Requirements can be decomposed. They are independent of technology.
A functional unit is a solution, or a statement of "what-is", it is an actuality. It is a characteristic definition. It is defined behavior. (Note: test vectors can be derived from defined behavior, the definition of test is out of the scope of the task team.)

A physical definition describes the materials, dimensions, tolerances, etc. of the physical product.

17. **DAISY CHAIN TRIADS.** The three distinct aspects which describe the design data of e/e products have been designated green stuff, blue stuff, and red stuff. Data may be part of the specified demand (green stuff), functional characteristic definition (blue stuff), or physical definition (red stuff). We have limited the scope of the initial model to blue and red stuff. This is consistent with the activity model (see appendix 5). In terms of the activity model, the information flows described as the inputs and outputs for the activities, Perform EE Functional Design, and Perform EE Physical Design, constitute the data of blue and red stuff. The green stuff data include all of the controls for the activity, Perform EE Functional Design.

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**Diagram: Daisy Chain Triads**

**GREEN STUFF**
- Requirements
- Structure

**BLUE STUFF**
- Functional Design
- Solution Structure
- Functional Connectivity (Net List)
- Functional Characteristics

**RED STUFF**
- Physical Design
- Solution Structure
- Physical Interfaces
- Dimensions and Tolerances
- Materials
- Physical Interfaces

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The most important distinction between the green and the blue worlds is that the green data talks about requirements independently of a particular technology. The blue data talks about functional solutions to the requirements in the units of a specific technology. For instance, a logic diagram which has not yet been expressed in terms of a particular technology (TTL, ECL, etc.) is green. The solution to the logic diagram which expresses the design using a particular technology (hydraulics, etc) is blue. A semiconductor solution would require the expression of the logical T's and F's or Zeros and Ones as electrical volts.

Each of these domains is represented by the conceptual model with a high-level entity. Each high-level entity has a corresponding is-has relationship with a sub-unit entity, and with some characteristics entity. These triads of entities will relate to each other through intersection entities: perhaps at both the high-level entities and the sub-unit entities.
APPENDIX A5

ACTIVITY MODEL FOR

DESIGN ELECTRONIC AND ELECTRICAL PRODUCTS

April 30, 1987
1. ACTIVITY MODEL - DESIGN ELECTRONIC AND ELECTRICAL PRODUCTS

This model was developed by the Cal Poly Task Team as an aid to understanding the scope and context of their modeling activity. The diagrams of the model to one level of decomposition appear on the pages which follow.

The model illustrates the concept that design tends to begin with functional design where the major functions are identified and then broken down into smaller elements of functionality until the basis for a physical design is reached. The feedback paths show that this is an iterative process. The model also shows that design analyses are performed at both the functional design level and after a physical solution is designed.

Electronic and electrical products have a wide range including transistor devices, printed wiring boards, wire harnesses, electrical relays and switches, electric motors and generators, etc. We believe that this general model applies to the design of all of those kinds of products.

In its early scoping decisions the team identified certain of the ICOM's of the model as containing data within the task team scope and others as out of scope as follows:

IN SCOPE

The input; "Knowledge of part characteristics" is in scope to the degree that it encompasses a library of characteristics of parts.

The outputs of A1 are within scope.

The outputs of A2 are within scope. [These were later determined to be beyond the six week schedule of the task team]

OUT OF SCOPE

All other ICOMs were determined to be out of present scope.

Particular note should be taken of the external controls, "Technology", "Design Requirements", "Approved Parts List" and "Design Rules" which are out of scope.

2. A-0 THE CONTEXT - DESIGN ELECTRONIC AND ELECTRICAL PRODUCTS

The purpose of this activity model is to portray the fundamental activities of the design process. The model is used as a scoping aid for data modeling.

The viewpoint of this model is that of engineers involved in the design of electronic and electrical products.
2.1 A0 - DECOMPOSITION OF DESIGN ELECTRONIC AND ELECTRICAL PRODUCTS

The design process is decomposed into activities of Perform Electronic and Electrical Functional Design, Perform Design Analyses and Perform Electronic and Electrical Physical Design. These are described in detail below.

2.1.1 A1 - PERFORM ELECTRONIC AND ELECTRICAL FUNCTIONAL DESIGN

This activity produces the functional design of the product. It usually precedes the physical design although this is not absolutely so. In any case, it is an iterative process. The functional design is a description of functional characteristics and connectivity without physical solution characteristics such as dimensions and tolerances and package characteristics.

This activity is constrained by the controls of available technology and design requirements. The functional design produced from this activity is expressed in the terms and units of a chosen solution technology.

Electrical schematics are a common presentation of functional design.

2.1.2 A2 - PERFORM DESIGN ANALYSES

This activity is where analysis of both functional and physical designs is performed. These are analyses executed on the characteristics specified by the design. These are not analyses performed from measurements of actual parts being compared to the specified design characteristics.

2.1.3 A3 - PERFORM ELECTRONIC AND ELECTRICAL PHYSICAL DESIGN

In this activity, the size, shape, physical layout and orientation of items are determined. Specification of materials and other physical characteristics is part of this process. Packaging decisions are made which frequently result in combining more than one functional unit into a single physical unit.

3. DEFINITIONS FOR THE ACTIVITY MODEL ICOMs

3.1 Approved Parts List - A list of parts with known characteristics for which the enterprise has established prior usage approvals and the intent that they be used repeatedly in multiple products. [Most such parts are purchased parts]

3.2 Available Technology - A set of materials, manufacturing methods and processes available within the enterprise, and its preferred sources, for production of its products.

3.3 Analyzed Physical Design - A physical design of a product, or portion of a product, which has been determined to satisfy the design requirements through design analysis.

3.4 Design Requirements - A collection of parameters which the product must satisfy. These requirements include the initial requirements and changes which occur over the product life.

3.5 Design Rules - Policies, procedures and specific practices within the enterprise which establish constraints on how designs are to be implemented and expressed.
3.6 Functional Connectivity - The data which specifies the manner in which the functional units are to be logically connected to form functional assemblies.

3.7 Functional Parts List and Characteristic Requirements - The data which identifies the functional units and their specified functional characteristics.

3.8 Knowledge of Part Characteristics - Any knowledge related to the functional and physical characteristics of pre-defined electronic and electrical parts. This is knowledge typically found in manufactureres data books and enterprise standard parts manuals. It is data about the parts independent of specific uses.

3.9 Knowledge of Product Design - This is knowledge which complements the knowledge of part characteristics. It is knowledge of ways of assembling parts into products which have proven successful. Unfortunately, other than the design rules, most of this is not documented.

3.10 Physical Design - The specification of the physical characteristics and constraints of a particular electronic or electrical product. Includes dimensions and tolerances, material specifications, manner of joining parts, etc.

3.11 Requirements for Functional Design Changes - These are requirements resulting from analyses of the functional or physical design which determine that the design will not satisfy all of the controlling requirements. Some of these requirements for change result from the physical design process which determines that the functional design cannot be implemented within the technology constraints or rules and practices of the enterprise.

3.12 Requirements for Physical Design - Results from design analyses which set specific constraints upon the initial physical design to assure the functional characteristics are met.

3.13 Requirements for Physical Design Changes - That part of the results of design analyses which identifies the needs for changes to an existing physical design.

3.14 Validated Functional Design - A functional design of a product whose performance has been determined by analyses to satisfy the design requirements.
Purpose: To portray the processes of Electronic and Electrical functional design, physical design and design analysis.

Viewpoint: Engineers involved in design of Electronic and Electrical products.

Available Technology
Design Requirements
Approved Parts List
Design Rules

Knowledge of Part Functional Characteristics

Validated Functional Design

Knowledge of Product Design

Analyzed Physical Design

DETAILED DESIGN ELECTRONIC AND ELECTRICAL PRODUCTS
Available Technology
Design Requirements
Approved Parts List
Design Rules

Knowledge of Part Functional Characteristics

Knowledge of Product Design

Functional Connectivity

PERFORM ELECTRONIC AND ELECTRICAL FUNCTIONAL DESIGN

PERFORM DESIGN ANALYSES

Functional Parts List and Characteristic Requirements
Requirements for Functional Design Changes
Requirements for Physical Design Changes

PERFORM ELECTRONIC AND ELECTRICAL PHYSICAL DESIGN

Analysis of Physical Design

Validated Functional Design

Physical Design

DEcomposition of Design Electronic and Electrical Products

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APPENDIX A6

LIST OF PARTICIPANTS

April 30, 1987
### THE CAL POLY TASK TEAM PARTICIPANTS

#### ON-SITE PARTICIPANTS

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</table>

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<tbody>
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</tbody>
</table>
APPENDIX A7

LIST OF MODEL REVIEW AND WORKSHOP ATTENDEES

April 27, 1987
LIST OF ATTENDEES AT MODEL REVIEWS

B = Boston Area  
P = Pomona, Cal Poly  
W = West Palm Beach (ISOfPDES/IGES Mtg)  
D = Dayton

<table>
<thead>
<tr>
<th>Name</th>
<th>Affiliation</th>
<th>Review</th>
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<tbody>
<tr>
<td>Ramon Alonso</td>
<td>Draper Labs</td>
<td>B</td>
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<tr>
<td>Derec Anderson</td>
<td>McDonnell Douglas Aircraft</td>
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<td>Lougie Anderson</td>
<td>Tektronix</td>
<td>D</td>
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<td>Mindy Baden</td>
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<td>Dennis Bak</td>
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<td>Goeff Blith</td>
<td>Marconi Instruments, UK</td>
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<td>Michael Boone</td>
<td>Naval Weapons Center, Corona</td>
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<tr>
<td>M. L. Brei</td>
<td>Bitt, Inc.</td>
<td>D</td>
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<tr>
<td>Don Buckley</td>
<td>Harris Govt Systems</td>
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<tr>
<td>Richard Butler</td>
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<td>Pete Campbell</td>
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<td>Richard Cockrum</td>
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<tr>
<td>Simon Corne</td>
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<td>W</td>
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<tr>
<td>Dorothy Cross</td>
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<td>B</td>
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<tr>
<td>Norm Dietrich</td>
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<tr>
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<tr>
<td>Mark Edwards</td>
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<td>Dave Evans</td>
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<td>Larry Ferguson</td>
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<tr>
<td>Marc Fleschmann</td>
<td>Sanders Assoc.</td>
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<td>Thomas Furtis</td>
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APPENDIX A8

LIST OF SOURCE REFERENCE MATERIAL

April 30, 1987
LIST OF DOCUMENTS AVAILABLE AS SOURCES TO THE TASK TEAM

Source #1:
From: MDAC-St. Louis
Subject: PDDB Project 12/86
Items Included:
1. PWB Data Model IDEF1X Diagram
2. PDDB - PWB Diagram
3. Entity Extended definitions
4. Attribute Extended Definitions
5. Entity Relationship Structure
6. PODB Attribute Structure

Source #2
From: Westinghouse Defense Center Baltimore
Subject: Printed Wire Assembly (PWA) Study
Items Included:
1. To-Be Data Model
2. To-Be Entity List
3. Supporting Appendices

Source #3
From: IGES
Subject: IGES Electrical Entities
Items Included:
1. Network Subfigure
2. Connect Point
3. Flow Associativity
Source #4
From: EDIF
Subject: The UK EDIF Support Project - Data Model of EDIF
  EDIF 1 0 0 Specification, 1985
  EDIF 2 0 0 Draft, 12/31/86
Items Included:
  1. EDIF 1 0 0 Glossary
  2. EDIF Level 0 Netlist and MaskLayout View Models

Source #5
From: VHDL 7.2 (five documents)
Subject: This is the VHSIC Hardware Description Language. This is a language which primarily captures requirements for integrated circuits. Its concept is that the requirements can be described in a standardized manner through this language which can then be interpreted by design programs such as Silicon Compilers.
APPENDIX A9

MODELING TEAMS
LESSONS LEARNED

April 30, 1987
1. GENERAL

The creation and operation of the Cal Poly Task Team provided some lessons for future teams of this type. These lessons are described below.

1.1 PERSONNEL COMMITMENTS

The schedule for the task team was set in anticipation of the commitment of resources necessary to execute the modeling task. The experience was that the team infrequently had the number of source experts and methodology experts present to reach the "critical mass" which is needed for maximum productivity of such a team. The model probably could have been extended further into the data of behavior had a more constant level of expertise been present.

In the future, it is suggested that plans for such activities should be developed with scopes and descriptions of resources required and schedules in terms of weeks of effort after start. Actual dates for execution should not be established unless the resource commitments are in hand. These commitments should be from supervisors or managers who have the authority to commit manhours, travel, and facilities.

1.2 FACILITIES

To be most effective, a modeling team needs certain kinds of facilities which are described below.

- Space in which to meet in group discussion.
- Spaces in which to divide into smaller groups for discussion.
- Large amounts of "blackboard" space.
- Easels and tear off "flip charts".
- Wall space on which to tape up flip chart pages.
- Ready access to computer graphics and word processing tools.

The Cal Poly Team had the personal Apple Macintosh Computer of one of the participants in the team room and access to the Apple Macintosh and Apple LaserWriter in the office of the Dean of Engineering. These proved to be invaluable when attempting to maintain the documentation of the project.

The Apple Macintosh seemed particularly useful because it was easy for team members to pick up applications on it. Its facilities for graphics and inserting graphics in word processing documents was very helpful since the products of a data modeling team are a mixture of graphics and text.

This report was prepared on the Apple Macintosh and the Apple LaserWriter.

The team did not have sufficient "blackboard" space to encourage the free flow of ideas when modeling.

There was a complete wall available to tape reference material on. This was particularly useful to develop the storyboard for the review presentations.
The Cal Poly Team had the personal Apple Macintosh Computer of one of the participants in the
team room and access to the Apple Macintosh and Apple LaserWriter in the office of the Dean of
Engineering. These proved to be invaluable when attempting to maintain the documentation of the
project.

The Apple Macintosh seemed particularly useful because it was easy for team members to pick up
applications on it. Its facilities for graphics and inserting graphics in word processing documents was
very helpful since the products of a data modeling team are a mixture of graphics and text.

This report was prepared on the Apple Macintosh and the Apple LaserWriter.

If the team could have had ready access to one of the JANUS installations being made available for
PDES, JANUS would have been used to assist with testing and documenting the model.

The source expert people that make this kind of team effective are the kind of people that "cannot be
spared". When on home ground, such people are frequently interrupted for "important matters". The
University setting provided a neutral ground where participants were spared from such interruptions.
Appendix E

ANNOTATED CAL POLY CONCEPTUAL SCHEMA,
30 APRIL 1987
PACKAGE CONTENTS

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INSTRUCTIONS

All readers: This Model Kit is offered for review and validation by any persons having an interest in a conceptual scheme for the data which defines electrical and electronic products. Comments and suggested changes should be marked on a copy in red ink and forwarded to:

Curt Parks
General Dynamics, Pomona Division
P.O. Box 2507, MZ 50 24
Pomona, CA 91769

STRATEGIC OBJECTIVES

SCOPE and CONTEXT:

This Kit is intended to provide a model of the basic structure of the data which defines the functional characteristics of an electrical or electronic product in the terms of a chosen technology for a design solution to product requirements.

PURPOSE:

This model is intended to be a portion of the total product data model needed to establish the understanding of data required to enable construction of Computer Integrated Manufacturing (CIM) environments.

VIEWPOINT:

The viewpoint is a synthesis of individual contributions to the understanding of the functional definition of electrical and electrical products. Contributing individuals were from a variety of design and computer implementation disciplines.

VERSION

This version is the Kit modified as the result of the review April 13-17 at Dayton, Ohio (USAF CIM).
CAL. POLY TASK TEAM
ELECTRONIC AND ELECTRICAL DATA MODEL

GLOSSARY

ENTITY DEFINITIONS

Defined Electrical Logical Intralink Constraint

Data which sets limiting values for a functional characteristic, contained within a single network, which must be satisfied by the physical design in which the corresponding physical connections are implemented. An example might be a length constraint in terms of wavelengths at a specified operating frequency.

Defined Electrical Logical Link

Data about the logical electrical connectivity within a Functional Unit. It establishes a set of two or more Electrical Nodes or one Defined Functional Port and one or more Electrical Nodes as being electrically in common.

Defined Electrical Logical Link Group

Data that establishes that one or more Defined Electrical Logical Links are combined into a group for some purpose.

Defined Electrical Logical Link Group Member

Data that a Defined Electrical Logical Link is a member of a Defined Electrical Logical Link Group.

Defined Electrical Logical Link Intergroup Constraint

Data which sets limiting values for a functional characteristic among Defined Electrical Logical Link Groups which must be satisfied by the physical design in which the corresponding physical connections are implemented. Examples would be capacitance limits or an insulation resistance requirement.

Defined Electrical Property

Data about electrical characteristics of a Defined Functional Unit existing between two Defined Functional Ports. For example, resistance, capacitance or inductance which are usually thought of as “static” rather than “dynamic”. (These properties do have some variation such as the temperature coefficient of resistance for a resistor).

[Entities and attributes to capture the data of these variations have not yet been modeled.]
ENTITY DEFINITIONS

Defined Electrical Signal

Data used to define the behavior of a Defined Functional Unit, expressed in terms of electrical potential difference between two Defined Functional Ports. (It is through the data which defines the relationships of output signals to input signal states that dynamic behavior of "active" Defined Functional Units is captured. The characteristic curves of a transistor can be derived by common, curve fitting algorithms from sets of these data.)

Defined Functional Port

Data describing the logical accessibility to one of the functions of a Defined Functional Unit. (These ports are what is represented by lines or other graphic symbols identifying inputs and outputs for electrical devices. The port is a characteristic of a Functional Unit definition without its having a usage. The port can be thought of as a window through which the boundary networks of the functional unit are seen. When a Defined Functional Unit is given an instance of use (Defined Functional Sub Unit Occurrence), then the port becomes an Electrical Node of its higher assembly.)

Defined Functional Sub Unit Occurrence

Data that a particular Defined Functional Unit occurs as a component of another Defined Functional Unit. There is an instance of this entity for each occurrence of a Defined Functional Unit within the same higher level Defined Functional Unit. This provides a functional view of the various levels of component/assembly product relationship.

Defined Functional Unit

Data about the functional, or performance, aspects of a portion of a system. A Defined Functional Unit may be a sub unit of another Defined Functional Unit and it may have sub units of its own.

Defined Functional Unit Input State (a set of stimuli)

Data about conditions for a specific Functional Unit. (Through the Defined Input State Signal associative entity, a particular input state is defined as consisting of one or more Defined Electrical Signals, in the electrical application.)

Defined Functional Unit Output Signal Related Input State

Data that establishes that a Defined Functional Unit Output Signal results from a Defined Functional Unit Input State.

Defined Functional Unit Output Signal

An output signal of a particular Defined Functional Unit.
ENTITY DEFINITIONS

Defined Functional Unit Output Signal Propagation Delay Specification (response time)

Data that a Functional Unit Output Signal is required to be present within a specified time after the related Specified Functional Unit Input State has been established.

Defined Input State Signal

Data that establishes a particular Defined Electrical Signal as being a part of a Defined Functional Unit Input State.

Electrical Logical Link Node

Data that an Electrical Node is part of a Defined Electrical Logical Link.

Electrical Logical Link Port

Data that a Defined Functional Port is part of a Defined Electrical Logical Link. Each Defined Functional Port can be a member of only one Defined Electrical Logical Link.

Electrical Node

Data about a logical (functional) accessibility to the functionality of a specific occurrence of a Functional Unit. This entity serves to collect the Defined Functional Port ID (e.g., Pin Number) together with the reference label of the occurrence of the Defined Functional Sub Unit Occurrence (e.g., U2-Pin 1).
GLOSSARY

ATTRIBUTE DEFINITIONS

Defined Electrical Property Name

The name of a specific Electrical Property existing between two Ports of a Defined Functional Unit. These are such names as Resistance, Capacitance, Inductance, etc.

Defined Electrical Property Units

Identification of the kind of units in which an Electrical Property Value is expressed. Examples are Ohms, Farads, etc.

Defined Electrical Property Value

The value, or quantity, of an Electrical Property

Delay Specification

An expression of a constraint of the delay from the establishment of the related Defined Functional Unit Input State before the Defined Functional Unit Output Signal must be present. Most likely expressed in time units.

[Further examination of this attribute will probably result in additional attributes and, perhaps, entities.]

Electrical Logical Link ID

An identification of an Electrical Logical Link which is unique within a particular Defined Functional Unit. May be numeric or alphabetic.

Electrical Logical Link Group ID

An identification of an Electrical Logical Link Group which is unique within a particular Defined Functional Unit. May be numeric or alphabetic.

Functional Unit ID

A unique identifier assigned by the enterprise to each Defined Functional Unit. Most commonly this is a meaningful name. An example might be "multiplexer assembly".

[When the present model is integrated into a larger enterprise or PDES conceptual data model it is probable that a completely unique identification will require a concatenation of several attributes. These are likely to include the identification of the enterprise which establishes (or owns) this definition and a product or model identification as well as a functional unit name.]
ATTRIBUTE DEFINITIONS

Input State ID

An identifier assigned by the enterprise to each input signal state within the definition of a Defined Functional Unit. Thus, the identifier is unique only within the context of a specific Defined Functional Unit and the combination of Functional Unit ID and Input State ID is unique within the enterprise.

Port ID

An identifier assigned to each Defined Functional Port of a Defined Functional Unit.

Signal ID

An identifier assigned to uniquely distinguish a signal, which appears between the same pair of ports, from another.

(If the functional unit that is being defined is a digital unit, then typical signals are trains of digital pulses. These can be most simply defined as two signals, a high and a low. Where the functional unit is something such as a transistor, there could be many signals defined, each having a different voltage value.)

Signal Units

Identification of the kind of units in which the value of the signal is expressed.

Signal Value

A number indicating the quantity of the units of the particular signal.

Sub Unit Occurrence Identification

An identification assigned to a particular occurrence of a Defined Functional Unit within another Defined Functional Unit. (The most common form of this in electrical design is a reference designation. The same functional resistor used twice in a higher unit might be designated R1 in one occurrence and R2 in the other.)
This is the core structure of the functional model. It represents the idea that a functional description of a product can be, and generally is, composed of large units of function which divide into smaller units of function until the designer arrives at his most discrete units. The design process probably is an iterative one of dividing large units into smaller and combining small units into a desired larger function.

Every identifiable unit of function appears as an instance of a Defined Functional Unit. A Defined Functional Unit may be a component of a higher functional assembly and may have components of its own.

The key of the Defined Functional Unit is a Functional Unit ID. The developers of the model believe that this is not a "part number". It is a descriptive name which implies the function. When this model becomes a part of the larger product model, it is anticipated that there will be some higher level context entities whose keys will migrate to become part of the identification (key) of the Defined Functional Unit.

Each instance of a Defined Functional Sub Unit Occurrence represents the data that a Defined Functional Unit is used as a component of another. The key of the Defined Functional Sub Unit Occurrence consists of the concatenation of the identification of the higher assembly (Higher Unit ID.Func Unit ID(FK)) and a unique identifier assigned to each component within the higher assembly. The most familiar form of such an occurrence identifier is a reference designator.

The non-key attribute of the Defined Functional Sub Unit Occurrence is the migrated key (Sub Unit ID.Func Unit ID(FK)) of the Defined Functional Unit which is the specific component in this occurrence.

These two entities with their two relationships provide the model for the data which describes all of the levels of assembly. The key of the Defined Functional Unit at the highest level of assembly will never appear in the Sub Unit ID role and the keys of Defined Functional Units at the lowest level of assembly will never appear in the Higher Unit ID role.

FEO's 1 through 4 develop the data required to establish connectivity within a functional buildup through levels of assembly. The reader is cautioned that this model has not yet become concerned with the data which tracks changes in design. When the concepts of "versions" of designs are considered, the model is expected to undergo some change which will add to the complexity of the keys of the entities.
A Defined Functional Unit contains one or more Defined Functional Ports. A Defined Functional Port is a logical place of access to the function of the Defined Functional Unit. This is consistent with the definition in IEEE Standard 100. Whenever a logical point of access is defined by the designer as a place of functional connection, or by a test engineer as a point for functional test, that act creates a Defined Functional Port.

The identification (key) of a Defined Functional Port is the migrated key of its owning Defined Functional Unit plus a unique ID.
When a Defined Functional Unit is used more than once in the same higher assembly, there is a need for a unique identification for each occurrence of its ports so that one can be distinguished from another. This is the purpose for the Electrical Node entity.

An Electrical Node is a specific instance of a Defined Functional Port within a next higher functional assembly. Concatenating the complete migrated key from the Defined Functional Sub Unit Occurrence with the Port ID from the migrated key of the Defined Functional Port provides the unique identification of each Electrical Node.

The Functional Unit ID(FK) of the Defined Functional Port is not required for identification of the Electrical Node, so it migrates to a non-key position.
DEFINING FUNCTIONING UNIT

DEFINED FUNCTIONAL BASE LINE OCCURRENCE

DEFINED ELECTRICAL LOGICAL LINE

ELECTRICAL NODE

ELECTRICAL LOGICAL LINE PORT

ELECTRICAL NODE

ELECTRICAL LOGICAL LINE PORT

NODE: FEO-4

TITLE: DEFINED ELECTRICAL LOGICAL LINK - THE LOGICAL CONNECTIVITY

NUMBER: A/EPHY/CP1
Now that the identifications of Defined Functional Ports and Electrical Nodes have been established, it is possible to define logical connectivity among the functional units. It is important to keep in mind that no physical design data is present. Logical connectivity is data that functional units are tied together in specific ways.

A Defined Functional Unit which to the designer is a "black box" with no knowledge of its details has no known connectivity and therefore contains no Defined Electrical Logical Links.

A Defined Functional Unit which has known details and connectivity will contain one or more Defined Electrical Logical Links.

A Defined Electrical Logical Link must contain at least one Electrical Node and may contain more. This is established by one or more related instances of Electrical Logical Link Nodes.

A Defined Electrical Logical Link may include not more than one Defined Functional Port and may include none. This is established by zero or one related instance of Electrical Logical Link Port.

Therefore, the smallest possible Defined Electrical Logical Links are composed of either, two instances of Electrical Logical Nodes, or one instance of Electrical Logical Link Port and one instance of Electrical Logical Link Node.

Defined Functional Ports and Electrical Nodes cannot be members of more than one Defined Electrical Logical Link. This is simply a matter of logic. Since the Defined Electrical Logical Link represents logical points that are electrically in common, joining two links through a common node would have the effect of joining two links into a single logical link. The same logic applies to ports.

Ports of Defined Functional Units which have not been used in higher functional assemblies are not members of links. Electrical Nodes which are unused in the next assembly are also not members of links.

At this point, the model provides for the fundamental data of logical connectivity. When the physical solution data model has been developed, there will be some mapping from the Defined Electrical Logical Link to the entities which establish the physical description where that logical connectivity is implemented.
BEHAVIOR

The next portions of the model are a limited set of entities and relationships indicating the manner in which the data of behavior may be modeled. There seems to be two kinds of behavior or characteristics. One is a dynamic sort of behavior which is described as output variations due to input variations. The other seems to be a thought of as static characteristics such as the those of a fixed resistor. FEO's 5, 6 and 7 are about the dynamic characteristics and FEO 8 about static characteristics.

**FEO-5**

Within the limited time available, the team set a narrow definition of "signal". It is defined for this model as a difference in electrical potential. That difference must appear between two Defined Functional Ports. This is the Defined Electrical Signal.

The Identification (key) of a signal is a concatenation of the Identification of the two ports between which it is defined and a signal ID which is unique within the Defined Functional Unit to which the ports belong.
Because it is sometimes necessary to establish that an output signal is dependent on more than one input signal, the model provides for collecting one or more signals into a Defined Functional Unit Input State. This is accomplished by the Defined Input State Signal entity. A Defined Electrical Signal may not be part of any input state or it may be part of one or more. Every Defined Functional Unit Input State must have at least one related instance of Defined Input State Signal.
In this diagram, we see some signals identified as Defined Functional Unit Output Signals. The fact that an output is dependent upon one or more input states of the same functional unit is established through the Defined Functional Unit Output Signal Related Input State entity.

The entity, Defined Functional Unit Output Signal Propagation Delay Definition, is modeled to show how to provide for data that an output signal is only required to be present within a specified time after an input state has been established.
The entity, Defined Electrical Property, is modeled to show how the static characteristics of behavior or function may be introduced into the data model. These are characteristics such as resistance and inductance. The model is merely a first guess. There is considerable work yet to be accomplished. It is anticipated that a more complicated data model will result with many entities and relationships. However, it is expected that they will still be related to ports of functional units.
DEFINED FUNCTIONAL LINE

DEFINED ELECTRICAL LOGICAL LINE
From the ID
To Logical Link ID

DEFINED ELECTRICAL LOGICAL LINK GROUP
From the ID
To Logical Link Group ID

DEFINED ELECTRICAL LOGICAL INTERFACE CONSTRAINT
From the ID
To Logical Link

Note: There is a whole

DEFINING INTRALINK AND INERALNK ELECTRICAL CONSTRAINTS

NODE: FEO 92
TITLE: LOGICAL INTERLINK AND INTRALINK ELECTRICAL CONSTRAINTS
NUMBER: AI/EPI/ICP1
The functional designer may find it necessary to collect Defined Electrical Logical Links into groups in order to express a requirement applying to the group. The Defined Electrical Logical Link Group provides this capability. A Defined Electrical Logical Link Group has one or more Defined Electrical Logical Group Members.

Two kinds of constraints may be specified with regard to electrical logical links. A constraint which applies only to a single link is provided by the Defined Electrical Logical Intralink Constraint. The idea here is that the functional designer can specify some limitation which must be met in the physical design which implements the function. An example might be that the link is specified to be a certain fraction of a wavelength at an operating frequency.

The other kind of constraint is a requirement that the physical solution must meet some specified functional condition between groups of links. This is provided for by the Defined Electrical Logical Interlink Constraint. Here is where the physical design might be constrained to some maximum capacitance between link groups.

The task team did not have time to explore these constraint ideas in any detail. This is an area of the model which could be expanded by another modeling team.
This is the complete model developed by the task team.

FEO's 1 through 9.2 have provided the explanation of the model treating each major concept separately.
This section presents the business rules of the E/E conceptual model in English. The rules are grouped by entities. Entity names are distinguished by bold italics. The number scheme below does not correspond to number schemes used in other documentation.

1. A Defined Functional Unit has 0, 1, or many Defined Functional Unit Input States.
2. A Defined Functional Unit contains 1, or many Defined Functional Ports.
3. A Defined Functional Unit is 0, 1, or many Defined Functional Sub Unit Occurrences.
4. A Defined Functional Unit has 0, 1, or many Defined Functional Sub Unit Occurrences.
5. A Defined Functional Unit contains 0, 1, or many Defined Electrical Logical Links.
6. A Defined Functional Unit contains 0, 1, or many Defined Electrical Logical Link Groups.
7. A Defined Functional Unit Input State is 0, 1, or many Defined Functional Unit Output Signal Related Input States.
8. A Defined Functional Unit Input State is composed of 1 or many Defined Input State Signals.
9. A Defined Functional Port is a reference port for 0, 1, or many Defined Electrical Properties.
10. A Defined Functional Port is a measurement port for 0, 1, or many Defined Electrical Properties.
11. A Defined Functional Port is a reference port for 0, 1, or many Defined Electrical Signals.
12. A Defined Functional Port is a measurement port for 0, 1, or many Defined Electrical Signals.
13. A Defined Functional Port is 0 or 1 Electrical Logical Link Ports.
14. A Defined Functional Port becomes 0, 1, or many Electrical Nodes.
15. A Defined Functional Sub Unit Occurrence contains 1, or many Electrical Nodes.
16. A Defined Electrical Logical Link includes 0 or 1 Electrical Logical Link Ports.
17. A Defined Electrical Logical Link is composed of 1 or many Electrical Logical Link Nodes.
18. A Defined Electrical Logical Link has 0, 1, or many Defined Electrical Logical IntraLink Constraints.
19. A Defined Electrical Logical Link is 0, 1 or many Defined Electrical Logical Group Members.
20. A Defined Electrical Logical Link Group is the 1st logical link group of 0, 1, or many Electrical Logical Link Defined Constraints.
21. A Defined Electrical Logical Link Group is the 2nd logical link group of 0, 1, or many Electrical Logical Link Defined Constraints.
22. A Defined Electrical Signal is 0, 1, or many Defined Functional Unit Output Signals.
23. A Defined Electrical Signal is 0, 1, or many Defined Input State Signals.
24. A Defined Functional Unit Output Signal has 0 or 1 Defined Functional Unit Output Signal Propagation Delay Definitions.
25. A Defined Functional Unit Output Signal results from at least 1 Defined Functional Unit Output Signal Related Input State.
26. An Electrical Node is 0 or 1 Electrical Logical Link Nodes.
Appendix F

PLANS FOR THE AD HOC CAL POLY EXTENSION TEAM,
28 APRIL 1987
Plans for the Ad Hoc Cal Poly Extension Team

A. An ad hoc Cal Poly Extension Team has been formed under the IEEE/DASS Electronic Model Group (EMG). This is an intensive, concentrated activity to produce a usable conceptual data model for the "actual" aspects of printed wiring boards. This is a results-oriented group. The model should be complete by early fall 1987.

B. The team will consist of experienced data modelers who are working on similar projects in their respective organizations. Each member of the team will bring copies of the model he/she is working on to the modeling sessions.

The following people have been contacted to participate:

<table>
<thead>
<tr>
<th>NAME</th>
<th>STATUS</th>
</tr>
</thead>
<tbody>
<tr>
<td>George Goldsmith</td>
<td>Host for first session;</td>
</tr>
<tr>
<td>McDonnell Douglas</td>
<td>Is organizing the team;</td>
</tr>
<tr>
<td>Astronautics</td>
<td>Session Administrator</td>
</tr>
<tr>
<td>5301 Bolsa Avenue</td>
<td></td>
</tr>
<tr>
<td>Huntington Beach, CA 92647</td>
<td></td>
</tr>
<tr>
<td>714-896-1712</td>
<td></td>
</tr>
<tr>
<td>(FAX 896-1315; verify 896-2323)</td>
<td></td>
</tr>
<tr>
<td>John Zimmerman</td>
<td>Session Facilitator</td>
</tr>
<tr>
<td>Bendix Corporation</td>
<td></td>
</tr>
<tr>
<td>P.O. Box 419159</td>
<td></td>
</tr>
<tr>
<td>Dept. 883-1</td>
<td></td>
</tr>
<tr>
<td>MS FB 22</td>
<td></td>
</tr>
<tr>
<td>Kansas City, MO 64141-6159</td>
<td></td>
</tr>
<tr>
<td>816-997-2932</td>
<td></td>
</tr>
<tr>
<td>James Nell</td>
<td>PDDI people very interested,</td>
</tr>
<tr>
<td>Westinghouse</td>
<td>but schedule conflicts for</td>
</tr>
<tr>
<td>3200 Berger Road</td>
<td>May 4th session.</td>
</tr>
<tr>
<td>Columbia, MD 21046</td>
<td></td>
</tr>
</tbody>
</table>

F-1
301-993-5856

Curtis Parks  Will attend.
General Dynamics
P.O. Box 2507, MS 5024
Pomono, CA 91769
714-868-4923

Kevin Blackwell  Contacted by J. Zimmerman
Lawrence Livermore Laboratory
415-422-8087
Is interested, but might not be able to attend.

Leo Kellett  Contacted by J. Zimmerman
Kodak
716-477-1027
Needs more information.

Paul Nelson  Needs to be contacted.
Hughes Aircraft Company
Product Operations Division
Bldg. 607, MS N323
PO Box 3310
Fullerton, CA 9634
714-732-5008

Susan Johnston  Needs to be contacted.
Boeing Aerospace Company
P.O. Box 3999, MS 9Y-19
Seattle, Washington 98124-2499
206-657-6658

Bill Lowe (?)  Needs to be contacted
(C. Parks?)

Eric Gunther  Has information; Needs to be contacted
U.S. Airforce
AFWAL/MLTC
WPAFG, OH 45433
513-255-8976

Joan Tyler  Has information; needs to secure funding source.
National Bureau o Standards
Bldg 220 MS A127
Geithersburg MD 20899
301-975-6545
FAX: 975-2128 (verify: 975-3327)

F-2
C. DISCUSSION TOPICS

1. Modeling Sessions
   Bring models and other supporting material to the sessions
   Meet once every two months
   Rotate meeting sites
   Exchange information via the IGES BBS: 301-963-6234: Cal Poly

2. Domain of model
   Printed wiring boards (not printed circuit boards)
   printed wiring assemblies?
   Perspective of the model. OPTIONS:
   1) Graphics: physical layout
   2) Graphics: logic schematic
   3) abstract functionality
   4) actual printed wiring board
   Who else is modeling the "actual" aspects of PWB's?

3. Tools
   What tools are available for IDEFix?
   - IDEF graphics editor for the IBM PC -
     (Tom Voegali: 309-578-3244)

4. Assignments
   Need a list of assignments to be completed prior to follow-on modeling sessions.
Appendix G

EXCHANGE STANDARDS AND DATA MODELING PROJECT
PROGRESS REPORT, 24 APRIL 1987
EXCHANGE STANDARDS AND DATA MODELING PROJECT
PROGRESS REPORT

The goals of this project are to analyze and influence the development of emerging CAE data exchange standards in support of DoD's integration requirements for electronic product design automation. To solve today's integration problems, existing and emerging exchange standards must be used. The effective use of these standards requires a precise understanding of the interrelationships among the standards. This understanding will help us determine the extent to which the standards overlap, and the areas where the standards do not provide the representation required.

Much progress has been made toward the achievement of these goals. First, we identified four leading CAE data exchange formats with ambiguous overlapping areas: EDIF, IGES, IPC-D-35x, and VHDL. By establishing contacts with the principle figures involved in the development of these formats, we have been able to track the progress of each development effort. These contacts have also provided us with current assessments of industry's views regarding 1) the current and future viability of these standards, and 2) the technical capabilities of the standards.

We began the investigation of the overlap issue with the cooperation of the CALS OSD Policy office. This office is working on a structure to identify both information requirements and standards for the exchange of electronic product data. We have been participating in that effort to the extent that it applies to the goals of this project. To this end, we helped organize a landmark meeting with the leaders of EDIF, IGES, VHDL, and IPC. At this meeting, DoD's need for cooperation among the efforts to minimize redundancy was communicated to the standards people. The standards people, in turn, explained the philosophies driving the respective development efforts and provided a historical perpective explaining why the current situation exists.
Further investigation led to the discovery of an IEEE effort (the Cal Poly Task Team) and the establishment of an IEEE DASS working group, the Electronic Model Group (EMG). Both are applying data modeling technologies to the analysis of these standards. We are active participants on the Cal Poly Task Team, and are leading the Electronic Model Working Group. The Cal Poly Task Team has developed a conceptual model of the structural information required for electronic product design. The purpose of this model is to identify and define the primitive data involved in electronic product design. This conceptual data representation may provide a foundation for creating interfaces among disparate formats and databases. The IEEE/DASS EMG will demonstrate the technical feasibility of this approach.

We are in the process of organizing the IEEE/DASS EMG and will be coordinating with users of CAE information to test the Cal Poly model, evaluate data modeling methodologies, and refine the model if appropriate. The first action of the EMG is the formation of an ad hoc modeling group, the Cal Poly Extension Team, to produce a model for the physical aspects of printed wiring boards.

The results of the work of the EMG will be useful to all users of electronic product data. This includes CAD/CAE vendors, CAD/CAE users, DoD projects (such as CALS, TISSS, and EIS), and the standards development groups.
TO: F. Riddell  
FROM: ML Brei  
SUBJ: FY87 Deliverables  
DATE: April 21, 1987

CAE EXCHANGE STANDARDS PROJECT FY87 DELIVERABLES

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<td>10/08/86</td>
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<td>10/21/86</td>
<td>RAMCAD TIM Exchange Standards Presentation</td>
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<td>10/16/86</td>
<td>EDIF Printed Circuit Board Technical Subcommittee Trip Report</td>
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<td>CALS Information Requirements Matrix</td>
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<td>03/01/87</td>
<td>Design Automation Standards Position Paper</td>
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<td>02/13/87</td>
<td>Electronic Product Case History (M. Melkanoff) Meeting Report</td>
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<td>IDEF0 Modeling Guidelines (in progress)</td>
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G-3
TO: F. Riddell  
FROM: ML Brei  
SUBJ: FY87 Meetings Attended

DATE: April 21, 1987

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<tr>
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<td>7-10 October 86</td>
<td>San Francisco</td>
<td>Ansi Y14.26 Meeting</td>
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<tr>
<td>15-17 October 86</td>
<td>Dallas</td>
<td>EDIF PCB Technical Subcommittee Meeting</td>
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<td>21-22 October 86</td>
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<tr>
<td>27-28 October 86</td>
<td>San Francisco</td>
<td>EDIF Joint Technical Committee/Subcomm.</td>
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<tr>
<td>10-11 November 86</td>
<td>Santa Clara</td>
<td>EDIF User's Group Meeting</td>
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<td>17 December 86</td>
<td>IDA</td>
<td>EDIF/IGES/IPC/VHDL Joint Meeting</td>
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<td>05-09 January 87</td>
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<td>IDEF1x modeling training</td>
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<tr>
<td>12-15 January 87</td>
<td>San Diego, CA</td>
<td>IGES/PDES quarterly meeting</td>
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<tr>
<td>01-04 February 87</td>
<td>New Orleans</td>
<td>Ans1 Y14.26 Meeting</td>
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<td>08-27 February 87</td>
<td>Pomona, CA</td>
<td>Cal Poly Modeling Assignment</td>
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<td>12 March 87</td>
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<td>IEEE/DASS Steering Committee Meeting</td>
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<td>19-20 March 87</td>
<td>Cupertino, CA</td>
<td>EDIF PCB Technical Committee Meeting</td>
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<td>13-15 March 87</td>
<td>Dayton, Ohio</td>
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<td>14 March 87</td>
<td>Wright Patterson</td>
<td>EIS meeting (J. Ebel)</td>
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<td>ULCE Architecture Planning Meeting</td>
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<tr>
<td>21 April 87</td>
<td>Harris Corp.</td>
<td>TISSS Informational Meeting</td>
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<td>22-23 April 87</td>
<td>IDA</td>
<td>RAMCAD TIM</td>
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Appendix H

DAYTON REVIEW OF THE CONCEPTUAL SCHEMA,
13 APRIL 1987
THE DAYTON REVIEW
OF THE
IEEE/PDES CONCEPTUAL SCHEMA FOR ELECTRONIC PRODUCT DATA

April 13-16, 1987
Dayton, Ohio

- REPORT -

Prepared by: ML Brei, BITE Inc.
Prepared for: The Institute for Defense Analyses

Attachments:
(1) Attendance List
(2) Presentation Material Outline
(3) Model Kit 4/11/87
(4) Test Circuit 1a
(5) Electrical Functional FEO 2.1.4
(6) IGES Electrical Functional Conceptual Schema

The final review of the IEEE/PDES conceptual schema for electronic product data (created by the Cal Poly Task Team) was held on April 13-17, 1987 in Dayton, Ohio under the auspices of the Air Force. Meeting arrangements were handled by Universal technology Corporation.

A diverse group of industry, government, and defense representatives attended the review. The broad knowledge base of the participants contributed to lively sessions during which many creative and controversial ideas were explored. As a result, a greater understanding of the strengths, weaknesses, and potential applications of the model has been achieved.

The issues raised by the participants and other highlights of the review during the first three days are summarized below. (See attachment 2 for the presentation material.)
A. CAL POLY TASK TEAM INTRODUCTION

Roger Gale, D. Appleton Co., and Curt Parks, General Dynamics, discussed the background of the Cal Poly Task Team and the motivation driving the modeling effort. A tutorial of the IDEFlx language and modeling methodology was given by Roger Gale. The TISS Information Modeling Manual for IDEFlx was distributed.

B. DETAILED WALKTHROUGH

A detailed examination of the latest version of the Cal Poly model was led by Roger Gale. The examination consisted of an entity-by-entity discussion of the meaning conveyed by the model. The model kit (attachment 4) presents the model incrementally. Several of the entities reflected new ideas from the PDES review held in Florida.

The walkthrough revealed both strong and weak aspects of the model. The entities which describe connectivity and structure are technically sound. The entities which describe behavior at the interface of a device, however, are not quite right. We still do not know how to clearly define the level of detail the model should represent. To model the behavioral aspects of electronic design data, we must understand how to describe behavior as data. The general consensus of the audience was that the input/output and signal entities should be re-worked completely.

C. TEST CIRCUIT

At the Cal Poly (March 23-26) Review, a test circuit (attachment 4) was devised to illustrate how to build instance tables for the model. Roger Gale presented the instance tables for the test circuit and explained how the data elements in the tables were derived. Each table corresponds to an entity in the model. The columns represent attributes. The rows represent specific occurrences of each entity.

D. THE RELATIONSHIP OF THE CAL POLY MODEL TO IGES

John Zimmerman, Bendix Corporation, presented an excellent analysis of the Cal Poly model with respect to an IGES electrical subset schema (attachment 6). The analysis consisted of the creation of an IGES electrical schema, comparing the IGES schema to the Cal Poly schema, and comparing the IGES schema with the IGES physical pointer structure.

The IGES schema was created after examining the IGES Specification (Version 3.0) Appendix B, "Electrical Electronic Product
Representation”. This appendix contains descriptions of IGES concepts, entities, and pointer structures.

The connectivity and structure entities of the Cal Poly schema have direct counterparts in the IGES schema. Thus, the mapping from the IGES schema to the Cal Poly schema can be considered one-to-one. This discovery has very important implications regarding the use of the Cal Poly model to analyze the semantic content of various exchange formats. The one-to-one mapping suggests that the conceptual definition of connectivity is the same in both the IGES and the Cal Poly schema.

The difference between the two schemas is their respective domains of discourse. The IGES schema represents graphics. The Cal Poly schema intends to represent abstract functionality. The difference may be a question of interpretation or perspective.

The critical question becomes, "what interpretation will stand the test of time?". One interpretation should be designated the anchor model with which all other interpretations are associated. Until we can determine which interpretation persists over time (independent of technology), mappings among diverse interpretations may be ambiguous.

E. OUTSTANDING ISSUES

Many issues were raised throughout the model review. Unresolved questions and discussion items are listed here for future reference.

1. What type of standard intermediate format/data dictionary is needed?

   We need a good mapping language which is both machine understandable and human-digestable.

   Does anyone really know what a good data dictionary is?

2. What organization will assume responsibility for the configuration control of the Cal Poly model?

   The Cal Poly model is only a small part of a much larger model under development by the PDES project of the IGES organization. The IEEE Design Automation Standards Subcommittee (DASS) has agreed to support the model. The DASS Electronic Model Working Group (EMG) will contribute to the on-going development of the model and promote the use of the model to understand overlaps among different physical formats. The configuration control of the model will remain in the context of the PDES effort.

3. Does the IDEF1x language and methodology have the expressive capability required for modeling complex design data?
- Cardinality is limited to discrete values and a pre-defined set of ranges, user-defined ranges cannot be expressed.

- Relationship labels are non-unique. This contradicts standard data modeling practices which enforce unique relationship labeling schemes.

- Conditional relationships can be expressed via the generalization construct. The IDEF1x generalization, however, requires exclusive categorization. The IDEF1x methodology does not encourage generalization to the same extent as other data modeling practices.

- How is partial and potentially inconsistent design data modeled in IDEF1x?

- Can changes and/or alternates be modeled?

4. What does the current version of the model represent?

The ultimate purpose of the model is to represent abstract functionality. A description of abstract functionality includes static and dynamic behavior, connectivity, and the parts which are interconnected. Currently, the model is a good description of connectivity and interconnected parts. The behavioral description, however, requires considerably more work.

We need to determine:

- What is meant by connectivity?
- What is meant by structure?
- What is meant by behavior?

5. How are we going to get the vendors involved?

6. What should be done next with the Cal Poly model?

The Cal Poly Task Team will disband after preparing a final report within the next month.

The plans of the IEEE/DASS EMG will be announced at the culmination of the Cal Poly Task Team effort.

A brain-storming session on Wednesday afternoon yielded the following ideas as follow-on activities:

- Pursue full attribution of the model (non-key)
- Build mappings to the Cal Poly model (the model will serve as a unification point) from IGES/EDIF/VHDL
- Build and populate a simple database
- Create sample outputs (netlists, parts list...)
- Create EDIF/IGES/VHDL post-processors
- Develop a shareable test suite/benchmark product to test versions of the model, the database, the post-processors, etc.
- Pursue the establishment of a mapping from the logical solution data (blue stuff) to the physical solution data (red stuff). Form an ad hoc group to create a physical model by Oct. 1987.
- Consider how spice, hilo, and other simulation model data should be incorporated into the model.
- Do some additional work with the signal concept.
ATTENDANCE LIST
FOR
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13-17 April 1987
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Manassas, VA  22110  
(703) 367-5511
A CONCEPTUAL SCHEMA FOR SHARED PRODUCT DATA

PRESENTATION MATERIAL

cpl-01 WORKSHOP AGENDA

Day 1: Introduction: Purpose, Players, Plans, and Goals
Tutorial: Reading IDEF1-X
Model Walk-through: Part 1
Day 2: Model Walk-through: Part 2
Day 3+: Workshops

cpl-02 SCHEDULED REVIEWS AND WORKSHOPS

10-13 March 87 EAST COAST
Computervision: Bedford, MA
Mr. Alex Rawling 617-275-1800
Dr. Charles Savage 617-431-7207

23-27 March 87 WEST COAST
California Polytechnic Univ.: Pomona
Prof. Richard Cockrum 714-869-2511
Curtis H. Parks 713-868-4923

13-17 April 87 DELIVERABLES Review
Stouffer's Inn; Dayton, Ohio
PDES Registration Desk 513-426-8530


cpl-03 WORKSHOP TEAM LEADERS

* ROGER GALE: D. Appleton Company, Inc.
* CURTIS PARKS: General Dynamics/Pomona

cpl-04 INTRODUCTIONS

* Name and Organization
* General Background, Experience
* Purpose for attending and Expectations

cpl-05 THE CAL POLY TASK TEAM

* Hosted by the ECE Department: Prof. R. Cockrum.
* Full-time, 6-week effort to develop an initial public domain Electronic Product Data Model (January 12 to February 28).

cpl-06 CAL POLY TASK TEAM CONTRIBUTORS

M. L. Breif - Bite Inc.
Richard Brooks - McDonnell Douglas Astronautics
Dr. David Chalmers - STC
Roger Gale - D. Appleton Co.
George Goldsmith - McDonnell Douglas Astronautics
CAL POLY TASK TEAM CONTRIBUTORS - cont'd.

Kaz Hori - McDonnell Douglas Astronautics
Jerry Kane - Westinghouse
Andrew Moulton - Viewlogic Systems
Paul Nelson - Hughes Aircraft Co. Ground Support Group
Curtis Parks - General Dynamics Pomona Division
Tom Smith - Digital Equipment Corp.

Via Telephone:

Bert Gibbons - Westinghouse
Erich Marschner - CAD Language Systems
John Zimmerman - Bendix Kansas City Division

**BACKGROUND**

- Product Data Exchange Specification (PDES) effort
- IEEE Design Automation Standards Subcommittee (DASS)
- Cal Poly Task Team full-time working sessions

**CAL POLY TASK TEAM GOAL**

Create an electronic product data model depicting fundamental data elements, attributes, and relationships. The model will be:

- CONCEPTUAL,
- neutral,
- in the public domain, and
- the result of a cooperative effort among diverse players of the electronics industry.

This data model will be the initial IEEE Conceptual Schema for Shared Product Data.

**CAL POLY TASK TEAM OBJECTIVES**

- Use the IDEFI-X language and methodology to create the model.
- Establish an expert participant base from diverse segments of the electronics industry and academia.
- Prepare supporting material to be submitted to the appropriate publications for widespread dissemination to the public.

**CAL POLY TASK TEAM ACCOMPLISHMENTS**

- A Proposed Conceptual Data Model.
- Participation from a diverse segment of the Industry.
- Supporting documentation and source material to be used by future modeling efforts.
- A realistic understanding of the magnitude of the modeling task.
WHAT'S NEXT?

* Continue to validate the Conceptual schema by testing it in real-world situations.
* Continue to refine and enhance the schema through participation in the cognizant IEEE DASS working groups.
* Integrate the schema with related efforts currently underway in projects such as PDES, EIS, CALS, etc.

Continue to refine and enhance the schema through participation in the cognizant IEEE DASS working groups.

- The model needs to be populated with non-key attributes.
  - Defined Electrical Properties
  - Network Constraints
- The Physical Definition data of electrical and electronic parts needs to be modeled.
- The Intersection, or mapping, between the functional model and the physical definition needs to be modeled.
- "Change" data needs to be modeled.

CAL POLY TASK TEAM MOTIVATION

- THE DATA PROBLEM: a monster
  - INTERORGANIZATION SHARING
  - INTRAORGANIZATION SHARING
- CONCERNED GROUPS: seeking solutions
  (i.e. the IEEE, PDES, CALS, etc.)
- THE 3-SCHEMA CONCEPT: a viable approach

THE DATA PROBLEM

- Islands of Automation
- The Need to Share
- Interfacing is an expensive solution
- Running a phone wire does not ensure communication

A SOLUTION STRATEGY FOR THE PROBLEM

- MANAGE DATA FROM A DATA PERSPECTIVE
- STANDARDIZE THE MEANINGS OF DATA
  - INDEPENDENT FROM ITS USES (APPLICATIONS)
  - INDEPENDENT FROM ITS STORAGE TECHNOLOGY
    (DATABASES, FILES, TRANSFER FORMATS)
IEEE
A CONCEPTUAL SCHEMA FOR SHARED PRODUCT DATA

THE FOUNDATIONS OF KNOWLEDGE

KNOWLEDGE IS INFORMATION WITH AN UNDERSTANDING OF HOW IT MAY BE APPLIED

INFORMATION IS DATA PLACED IN A CONTEXT SATISFYING A USER'S NEED

A DATUM IS A FACT WITH A KNOWN MEANING

DATA

USER NEED

FACT

MEANING

THE DOMAIN OF THE CONCEPTUAL SCHEMA

CAL POLY TASK TEAM
28 MAR 87
A CONCEPTUAL SCHEMA FOR SHARED PRODUCT DATA

THE 3-SCHEMA CONCEPT

INTERNAL SCHEMAS

CONCEPTUAL SCHEMA

EXTERNAL SCHEMAS

USER VIEWS OF DATA

MANY

ONE

MANY

null
IEEE
A CONCEPTUAL SCHEMA FOR SHARED PRODUCT DATA

WHAT IS CONCEPTUAL DATA?

A USER VIEW

CONCEPTUAL DATA

MUSICAL SCALE
TONE

MUSICAL NOTE
TONE
DURATION
**PURPOSE**

- To specify INFORMATION REQUIREMENTS from an enterprise view
- To provide a control point for integration architectures
- To build shareable databases
- To analyze the expressiveness of transfer formats and design languages.

**THE LANGUAGE OF THE MODEL**

- Developed as part of the USAFICAM Project
- Named IDEFI-X

**CAL POLY TASK TEAM SCOPE PRIORITIES**

- Cannot capture the conceptual data of the entire electronic product data universe in 6 weeks.
- Narrowed the scope to the data of the design solution ready for manufacturing.
- Initial focus on FUNCTIONAL DESIGN.
- Wait to see if the PDES Mechanical Products model will satisfy our needs.

**TASK TEAM SCOPE ISSUES**

- DIFFERENTIATION OF KINDS OF DATA
  - REQUIREMENTS
  - DESIGN SOLUTIONS
- STARTED WITH TWO KINDS
  - FUNCTIONAL
  - PHYSICAL
- A "DESIGN VIEW" MODEL WAS THE TRIGGER TO A NEW UNDERSTANDING

**TASK TEAM SCOPE ISSUES**

- USE THE "DESIGN ELECTRICAL AND ELECTRONIC PRODUCTS ACTIVITY MODEL"
- THE "GREEN STUFF" IS IN THE CONTROL OF ACTIVITY A1

**THE MODEL WALKTHROUGH**

*Rules Of Procedure:*

1. Team leaders will present the model during the review.
2. Questions are encouraged during the review.
3. Issues should be identified throughout the review.
4. Issues will not be resolved during the review.
5. The workshops will be problem-solving sessions.
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CAL POLY TASK TEAM
MODEL SCOPE

THE PRODUCT LIFECYCLE
IEEE
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TASK TEAM SCOPE ISSUES

74LS138

SAME PART USED DIFFERENTLY

IEEE
A CONCEPTUAL SCHEMA FOR SHARED PRODUCT DATA

TASK TEAM SCOPE ISSUES

74LS138

SAME PART USED DIFFERENTLY
# A Conceptual Schema for Shared Product Data

## The Technology Independent Truth Table

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IEEE
A CONCEPTUAL SCHEMA FOR SHARED PRODUCT DATA

TASK TEAM ISSUES

GREEN STUFF
REQUIREMENTS
STRUCTURE

BLUE STUFF
FUNCTIONAL
DESIGN SOLUTION
STRUCTURE

RED STUFF
PHYSICAL
DESIGN SOLUTION
STRUCTURE

SUB FRONT

SUB FUNC

SUB ITEM

MAPPING

MAPPING

MAPPING

CAL. POLY TASK TEAM
28 FEB 87
THE FUNCTIONAL MODEL

- Diagrams
- Glossary of Terms
  - Entity Definitions
  - Attribute Definitions
- Business Rules

(.all) Refer to Model KIT

THE PHYSICAL DATA MODEL

- The PDES Mechanical Products Model will be examined to see that it satisfies the needs for electronic and electrical products.
- FEO 3.1.1 illustrates the mapping between the functional and physical data via the ELECTRICAL TERMINAL construct.

(Note: FEO 3.1.1 is FEO-11 in Model KIT)

PROBLEMS, problems!

OPEN ISSUES FROM BOSTON WALKTHROUGH

- Feedback - Cases where the output depends not only on present states, but some prior state, condition, signal or time.

- Delay/Time Based Phenomena - Relationships among signals or signal states which vary by defined frequency, time, phase, etc.

- Relationships among ordered sets of signals or states.

- Non-voltage signals (many electrical functional units have outputs which are radiation or mechanical motion).

- Data representation of analog etc. signals.
PACKAGE CONTENTS

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<th>Description</th>
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<td>G-D</td>
<td>Glossary for Data Model</td>
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<td>FEO: 1,10</td>
<td>Data Model FEO's</td>
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<tr>
<td>B</td>
<td>Data Model Business Rules</td>
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INSTRUCTIONS

All readers: This Model Kit is offered for review and validation by any persons having an interest in a conceptual schema for the data which defines electrical and electronic products. Comments and suggested changes should be marked on a copy in red ink in accordance with IDEF review methodology and forwarded to:

Curt Parks  
General Dynamics, Pomona Division  
P.O. Box 2507  
MZ 50-24  
Pomona, CA 91769

STRATEGIC OBJECTIVES

SCOPE and CONTEXT:
This Kit is intended to provide a model of the basic structure of the data which defines the functional characteristics of an electrical or electronic product in the terms of a chosen technology for a design solution to product requirements.

PURPOSE:
This model is intended to be a portion of the total product data model needed to establish the understanding of data required to enable construction of Computer Integrated Manufacturing (CIM) environments.

VIEWPOINT:
The viewpoint is a synthesis of individual contributions to the understanding of the functional definition of electrical and electronic products. Contributing individuals were from a variety of design and computer implementation disciplines.

VERSION
This version is the Kit prepared for review April 13-17 at Dayton, Ohio (USAF CIM).
ENTITY DEFINITIONS

Constituent Physically Defined Product Item

Data that establishes that one Physically Defined Product Item is a necessary constituent of another.

Defined Electrical Logical Intranlink Constraint

Data which sets limiting values for a functional characteristic, contained within a single network, which must be satisfied by the physical design in which the corresponding physical connections are implemented. An example might be a length constraint in terms of wavelengths at a specified operating frequency.

Defined Electrical Logical Link

Data about the logical electrical connectivity within a Functional Unit. It establishes a set of two or more Electrical Nodes or one Defined Functional Port and one or more Electrical Nodes as being electrically in common.

Defined Electrical Logical Link Group

Data that establishes that one or more Defined Electrical Logical Links are combined into a group for some purpose.

Defined Electrical Logical Link Group Member

Data that a Defined Electrical Logical Link is a member of a Defined Electrical Logical Link Group.

Defined Electrical Logical Link Intergroup Constraint

Data which sets limiting values for a functional characteristic among Defined Electrical Logical Link Groups which must be satisfied by the physical design in which the corresponding physical connections are implemented. Examples would be capacitance limits or an insulation resistance requirement.

Defined Electrical Property

Data about electrical characteristics of a Defined Functional Unit existing between two Defined Functional Ports. For example, resistance, capacitance or inductance which are usually thought of as "static" rather than "dynamic". (These properties do have some variation such as the temperature coefficient of resistance for a resistor).

[Entities and attributes to capture the data of these variations have not yet been modeled.]
ENTIT Y DEFINITIONS

Defined Electrical Signal

Data used to define the behavior of a Defined Functional Unit, expressed in terms of electrical potential difference between two Defined Functional Ports. (It is through the data which defines the relationships of output signals to input signal states that dynamic behavior of "active" Defined Functional Units is captured. The characteristic curves of a transistor can be derived by common, curve fitting algorithms from sets of these data.)

Defined Functional Port

Data describing the logical accessibility to one of the functions of a Defined Functional Unit. (These ports are what is represented by lines or other graphic symbols identifying inputs and outputs for electrical devices. The Port is a characteristic of a Functional Unit definition without its having a usage. The port can be thought of as a window through which the boundary networks of the functional unit are seen. When a Defined Functional Unit is given an instance of use (Defined Functional Sub Unit Occurrence), then the port becomes an Electrical Node of its higher assembly.)

Defined Functional Sub Unit Occurrence

Data that a particular Defined Functional Unit occurs as a component of another Defined Functional Unit. There is an instance of this entity for each occurrence of a Defined Functional Unit within the same higher level Defined Functional Unit. This provides a functional view of the various levels of component/assembly product relationship.

Defined Functional Unit

Data about the functional, or performance, aspects of a portion of a system. A Defined Functional Unit may be a sub unit of another Defined Functional Unit and it may have sub units of its own.

Defined Functional Unit Input State (a set of stimuli)

Data about conditions for a specific Functional Unit. (Through the Defined Input State Signal associative entity, a particular input state is defined as consisting of one or more Defined Electrical Signals, in the electrical application.)

Defined Functional Unit Output Signal Related Input State

Data that establishes that a Defined Functional Unit Output Signal results from a Defined Functional Unit Input State.

Defined Functional Unit Output Signal

An output signal of a particular Defined Functional Unit.
Glossary

Entity Definitions

Defined Functional Unit Output Signal Propagation Delay Specification (response time)

Data that a Functional Unit Output Signal is required to be present within a specified time after the related Specified Functional Unit Input State has been established.

Defined Input State Signal

Data that establishes a particular Defined Electrical Signal as being a part of a Defined Functional Unit Input State.

Electrical Logical Link Node

Data that an Electrical Node is part of a Defined Electrical Logical Link.

Electrical Logical Link Port

Data that a Defined Functional Port is part of a Defined Electrical Logical Link. Each Defined Functional Port can be a member of only one Defined Electrical Logical Link.

Electrical Node

Data about a logical (functional) accessibility to the functionality of a specific occurrence of a Functional Unit. This entity serves to collect the Defined Functional Port ID (e.g., Pin Number) together with the reference label of the occurrence of the Defined Functional Sub Unit Occurrence (e.g., U2-Pin 1).

Electrical Terminal

The three-dimensional object at a physical place for connection to the functionality of a Product Item. Examples are the leads on an axial lead resistor, the leads on a TO-18 transistor and the pins of an electrical connector.

Electrical Terminal Electrical Logical Link Node Site

Data that a particular occurrence of an Electrical Terminal is a physical instance of a particular Electrical Logical Link Node. (This is the mapping between a specific physical terminal definition and the functional node.)

Electrical Terminal Occurrence Location

Data that establishes a defined location for an instance of an Electrical Terminal within a higher assembly.
ENTITY DEFINITIONS

Physically Defined Product Item

An aggregation all of the defined characteristics of a Product Item. The physical shape and size are collected here and the mappings of functional characteristics from the functional definition are also collected by this entity. This is the entity which has a "part number" as its key.

Physically Defined Product Item Occurrence

For each occurrence of the Constituent Physically Defined Product Item there is an instance of this entity. Each instance within the same higher item acquires a unique identity and location within the attributes of this entity.

Physical Port

Data that collects shape and size elements (geometry, topology and tolerances) and permits mapping them as an Electrical Terminal. It may be noted that this model allows one shape and size definition to be used to define more than one Electrical Terminal. (This seems to be an example of the PDES mechanical products model idea of Shape/Size Element Group.)
ATTRIBUTE DEFINITIONS

Defined Electrical Property Name

The name of a specific Electrical Property existing between two Ports of a Defined Functional Unit. These are such names as Resistance, Capacitance, Inductance, etc.

Defined Electrical Property Units

Identification of the kind of units in which an Electrical Property Value is expressed. Examples are Ohms, Farads, etc.

Defined Electrical Property Value

The value, or quantity, of an Electrical Property

Delay Specification

An expression of a constraint of the delay from the establishment of the related Defined Functional Unit Input State before the Defined Functional Unit Output Signal must be present. Most likely expressed in time units.

[Further examination of this attribute will probably result in additional attributes and, perhaps, entities.]

Electrical Logical Link ID

An identification of an Electrical Logical Link which is unique within a particular Defined Functional Unit. May be numeric or alphabetic.

Electrical Logical Link Group ID

An identification of an Electrical Logical Link Group which is unique within a particular Defined Functional Unit. May be numeric or alphabetic.

Functional Unit ID

A unique identifier assigned by the enterprise to each Defined Functional Unit. Most commonly this is a meaningful name. An example might be “multiplexer assembly”.

[When the present model is integrated into a larger enterprise or PDES conceptual data model it is probable that a completely unique identification will require a concatenation of several attributes. These are likely to include the identification of the enterprise which establishes (or owns) this definition and a product or model identification as well as a functional unit name.]
ATTRIBUTES DEFINITIONS

Input State ID

An identifier assigned by the enterprise to each input signal state within the definition of a Defined Functional Unit. Thus, the identifier is unique only within the context of a specific Defined Functional Unit and the combination of Functional Unit ID and Input State ID is unique within the enterprise.

Port ID

An identifier assigned to each Defined Functional Port of a Defined Functional Unit.

Signal ID

An identifier assigned to uniquely distinguish a signal, which appears between the same pair of ports, from another.

(If the functional unit that is being defined is a digital unit, then typical signals are trains of digital pulses. These can be most simply defined as two signals, a high and a low. Where the functional unit is something such as a transistor, there could be many signals defined, each having a different voltage value.)

Signal Units

Identification of the kind of units in which the value of the signal is expressed.

Signal Value

A number indicating the quantity of the units of the particular signal.

Sub Unit Occurrence Identification

An identification assigned to a particular occurrence of a Defined Functional Unit within another Defined Functional Unit. (The most common form of this in electrical design is a reference designation. The same functional resistor used twice in a higher unit might be designated R1 in one occurrence and R2 in the other.)
DEFINING ELECTRICAL LOGICAL LINK - THE LOGICAL CONNECTIVITY
DEFINITE BLOCK UNIT

[Diagram showing relationships between defined electrical logical units and link groups]

DEFINITE ELECTRICAL LOGICAL LINK
Port Line ID

DEFINITE ELECTRICAL LOGICAL LINK GROUP
Port Line ID

DEFINITE ELECTRICAL LOGICAL LINK
Port Line ID

DEFINITE ELECTRICAL LOGICAL LINK GROUP
Port Line ID

TITLE:
DEFINED ELECTRICAL LOGICAL LINKS CAN BE GROUPED

NODE:
FEO 9.1

NUMBER:
AIE/PHY/CP1
BUSINESS RULES OF THE E/E CONCEPTUAL MODEL

This section presents the business rules of the E/E conceptual model in English. The rules are grouped by entities. Entity names are distinguished by bold italics. The number scheme below does not correspond to number schemes used in other documentation.

1. A Defined Functional Unit has 0, 1, or many Defined Functional Unit Input States.
2. A Defined Functional Unit contains 0, 1, or many Defined Functional Ports.
3. A Defined Functional Unit is 0, 1, or many Defined Functional Sub Unit Occurrences.
4. A Defined Functional Unit has 0, 1, or many Defined Functional Sub Unit Occurrences.
5. A Defined Functional Unit contains 0, 1, or many Defined Electrical Logical Links.
6. A Defined Functional Unit contains 0, 1, or many Defined Electrical Logical Link Groups.
7. A Defined Functional Unit Input State is 0, 1, or many Defined Functional Unit Output Signal Related Input States.
8. A Defined Functional Unit Input State is composed of 1 or many Defined Input State Signals.
9. A Defined Functional Port is a reference port for 0, 1, or many Defined Electrical Property(ies).
10. A Defined Functional Port is a measurement port for 0, 1, or many Defined Electrical Property(ies).
11. A Defined Functional Port is a reference port for 0, 1, or many Defined Electrical Signals.
12. A Defined Functional Port is a measurement port for 0, 1, or many Defined Electrical Signals.
13. A Defined Functional Port is 0 or 1 Electrical Logical Link Ports.
14. A Defined Functional Port becomes 0, 1, or many Electrical Nodes.
15. A Defined Functional Sub Unit Occurrence contains 0, 1, or many Electrical Nodes.
16. A Defined Electrical Logical Link includes 0 or 1 Electrical Logical Link Ports.
17. A Defined Electrical Logical Link is composed of 1 or many Electrical Logical Link Nodes.
18. A Defined Electrical Logical Link has 0, 1, or many Defined Electrical Logical IntraLink Constraints.
19. A Defined Electrical Logical Link is 0, 1 or many Defined Electrical Logical Group Members.
20. A Defined Electrical Logical Link Group is the 1st logical link group of 0, 1, or many Electrical Logical Link Defined Constraints.
21. A Defined Electrical Logical Link Group is the 2nd logical link group of 0, 1, or many Electrical Logical Link Defined Constraints.

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BUSINESS RULES OF THE E/E CONCEPTUAL MODEL

22. A Defined Electrical Signal is 0, 1, or many Defined Functional Unit Output Signals.
23. A Defined Electrical Signal is 0, 1, or many Defined Input State Signals.

24. A Defined Functional Unit Output Signal has 0 or 1 Defined Functional Unit Output Signal Propagation Delay Definitions.
25. A Defined Functional Unit Output Signal results from at least 1 Defined Functional Unit Output Signal Related Input State.

26. An Electrical Node is 0, 1, or many Electrical Logical Link Nodes.
### DEFINED FUNCTIONAL UNIT
**SUB UNIT OCCURRENCE**

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<th>Sub Unit Occ ID</th>
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### ELECTRICAL NODE

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</tr>
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</tr>
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</tr>
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<td>2</td>
</tr>
<tr>
<td>Lo Pass Fil</td>
<td>3</td>
</tr>
<tr>
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</tr>
<tr>
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<tr>
<td>1μf Cap</td>
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<tr>
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<td>Lo Pass Filt</td>
<td>2</td>
</tr>
<tr>
<td>Lo Pass Filt</td>
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### ELECTRICAL LOGICAL LINK PORT

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<tr>
<td>Voltage Div</td>
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<tr>
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</table>
IGES Electrical
Conceptual Schema
IGES "SWITCH" SUPPORTS DIFFERENT INTERPRETATIONS

IEEE/PDES
4-15-87

H-59
This can be considered a model for an electrical signal or a fluid flow.
APPENDIX B - ELECTRICAL ELECTRONIC
PRODUCT REPRESENTATION

APPENDIX B
ELECTRICAL/ELECTRONIC PRODUCT REPRESENTATION

INTRODUCTION

Purpose

The purpose of this appendix is to provide IGES implementors and users with a roadmap of the IGES representation of electrical/electronic product designs. The topics of discussion will include (but are not limited to) design, engineering, manufacturing, testing, and inspection.

Assumptions

The reader should have a basic understanding of electrical/electronic product design using CAD/CAM/CAE tools, including (but not limited to) connectivity, component descriptions, placement and routing, and the manufacturing interface. Each topic will be discussed in general, but these discussions are not intended to provide a tutorial in the subject.

CONNECTIVITY

In General

Forming a connection between two or more items requires the ability to represent the following:

1. the exact location of each connection point
2. the signal formed and its identification (if any)
3. the physical connection between the items (if any)

The term "connect node" will refer to a database entity which represents the exact location of connection. The term "link" will refer to the representation of the signal formed, and "signal name" will refer to the signal identifier. The
term "join" will refer to the database entity or entities which represent the physical connection between the items.

Each item to be connected requires a connect node to represent each possible connection point of the item. A signal may be formed between any such items by a link which references the connect nodes to be connected. This creates an associativity between the connect nodes, and thus the connected items. The signal name may be used to uniquely identify the particular signal formed. The join may be used to provide a graphical representation of the signal. In electrical applications the join will most often be represented by a line (schematic) or a widened line (printed wiring board).

In electrical applications, the items to be connected are typically electrical components (i.e., resistor, 16-pin DIP, etc.). Most often, these components are represented by subfigures which are defined once, then referenced (instanced) in the database for each occurrence of the component. Each pin of the component is a potential connection point in a signal; thus each subfigure has a connect node defined for each pin. When such a subfigure is instanced, its connect nodes must also be instanced. This allows each connect node to participate in the unique signal to which it belongs. An instanced connect node, when added to a signal, is different from its definition which is not a member of any signal.

These subfigures, representing electrical components, often contain text describing the component and its pins. In some cases (e.g., part number), this text is fixed and unchanging. In other cases (e.g., reference designator), the text may be variable, and thus may not be filled in until the subfigure is instanced. This text (sometimes called a "text node"); like the connect node, is instanced along with its parent subfigure. In some cases, a connect node and a text node are related (e.g., the connect node represents a component pin and the text node represents the pin number).
In ICES, the connect node is represented by the Connect Point entity. The text node is represented by the Text Display Template entity. The Flow Associativity entity represents a signal and contains the link, signal name, and pointers to the join entities. The Network Subfigure entities (definition and instance) represent electrical components which participate in signals. A number of property entities will also be used, as mentioned below.

Network Subfigure Construction

A component is constructed using the Network Subfigure Definition entity. The graphics representing the component geometry are referenced as for the Subfigure Definition entity. In addition, a separate set of pointers to defining Connect Point entities is provided. These Connect Point entities define the locations and characteristics of the component's pins. Properties, for example the Part Name property, may be attached to the Network Subfigure Definition entity.

Connect Points

A component pin (or surface mounted device pad, IC I/O port, lead frame, schematic symbol lead, etc.) is represented by the Connect Point entity. The Connect Point entity is used in both logical and physical product designs. The exact location in model space is specified, along with several characteristic flags (connection type, function type, I/O direction). There is a pointer to the parent Network Subfigure entity (definition or instance), which provides a much-needed association for signal processing. An additional Subfigure Instance pointer is provided for Connect Point display. This allows a graphical symbol to be displayed, representing the Connect Point. The pin number is provided in the Function Connect Point Identifier field, along with a pointer to a Text Display Template for pin number display. A pin function name is provided in the Connect Point Function Name field, along with a pointer to a Text Display Template for its display.
Signal Construction

A signal, representing one set of electrically common Connect Points, is constructed using the Flow Associativity entity. It contains pointers to other associated Flow Associativity entities, the Connect Point entities participating in the signal (this is the Link), and the Join entities representing the geometry of the signal (either logical or physical). Also contained is a list of signal names which may be used to identify the signal, along with a set of pointers to Text Display Template entities which may be used to display the first signal name in a number of locations. Two characteristic flags determine the signal type (logical or physical), and the function type (fluid flow or electrical signal).

A signal, then, is represented by one Flow Associativity entity pointing to a set of electrically common Connect Points. This is the Link. The Join entities represent the physical display geometry of the signal. For a schematic (logical), a line without width is typically used. For a printed board (physical), a line with the Line Widening property is typically used. A number of signal names may be associated with the signal. Multiple displays of the first, or primary, name are possible.

The components participating in a signal are represented by the Network Subfigure Instance entity. Note that the Connect Point entities "belonging" to a component are instanced along with the subfigure. This is necessary to allow a subfigure to participate in a number of different signals, while retaining unique component/pin identification. Each component is usually identified by a reference designator. This is supplied by the Primary Reference Designator field of the Network Subfigure. Any alternate reference designators may be designated with the Reference Designator property, attached through the normal property pointer mechanism.

Information Display

Throughout the above discussion, references to the Text Display Template entity have been made. This entity allows text, embedded in an entity, to be displayed without the redundant specification of the text string. There are
two reasons for this feature. First, it eliminates a possible source of error by allowing the information to be specified in only one place. Second, it reduces the file size overhead. This entity exists in two forms, absolute and incremental. The absolute form provides an exact location for display of the information, as in the display of a reference designator. The incremental form provides an offset to be applied to the parent entity's location to provide the exact location for display of information like pin numbers. When a direct pointer for information display is provided, the base location is readily determined from the parent entity's location such as when displaying a pin number. In the case of property value display, the base location must be determined by "remembering" the location of the property entity's parent entity. This would occur when displaying the Part Name. Also in this case, the pointer to the Text Display Template entity is located in the additional pointers section of the property entity parameters.

Additional Considerations

The situation is exactly the same for both logical and physical representations. The only differences arise in the subfigure and Join entities used. In fact, a file may contain representations for both the schematic and the board. The Flow Associativity entity contains a type flag to indicate the connection type (logical or physical). In this case, one Flow Associativity would represent the logical connection and a second the physical connection. The two associativities would be related by the pointers provided in the Flow Associativity.

Figures

The following figures illustrate certain aspects of the above discussions. Figure B-1 illustrates the basic entity relationships. Figure B-2 and Table B-1 illustrate the usage of the Text Display Template. Figure B-3 illustrates an actual implementation. Figure B-4 shows an example of logical and physical signals and their relationships in the same file.
IGES ELECTRICAL ENTITY DESCRIPTIONS

The following entities (in entity number order) are the subset of IGES entities which have particular meanings when used for electrical product data.

100 Circular Arc Entity

The electrical use of this entity is in the geometric representation of component parts and their symbolic representations. In such usage, it is generally part of a subfigure. It may be used as a join entity. Its use may be defined by a Level Function property or DE Level field.

102 Composite Curve Entity

The electrical use of this entity is in the geometric representation of component parts and their symbolic representations. In such usage, it is generally part of a subfigure. It may be used as a join entity. Its use may be defined by a Level Function property or DE Level field.

106 Copious Data Entity

Forms 11, 12, and 13 of this entity may be used to implement the electrical join (i.e., schematic or wiring diagram circuit connection lines). Any of these forms may point to a Line Widening property. Examples of this entity-property combination are circuit paths on a PC board or IC metalization, or as a bus in a schematic. Form 63, Simple Closed Area, may be used to define an auto-router restriction area or a PC (or IC) defined area having special attributes.

108 Plane Entity

Certain layers of PC design are designated as "ground", "power", or "heat sink", and as such are large conductive areas. These layers, as well as larger curved or rounded conductive areas on other layers, are best defined by the Plane entity. Note that the form number indicates whether the bounded region is positive or void (i.e., copper clad area or cutout).
Line Entity

The Line entity has several important uses in the electrical application. It may be used to construct component outlines, and to represent both logical and physical connections (as a join entity). As a physical join entity, the Line Widening property will most often be attached, giving the width of metatization to be etched on the board. As a logical join entity, the line will most typically be used without the Line Widening property.

Point Entity

The point entity is used to locate features that do not participate in electrical connectivity, for example, a mounting hole.

Transformation Matrix Entity

A Transformation Matrix may be used to rotate subfigures to other than normal (top up) positions. Generally, rotations are about the Z axis for PC and IC constructs, but may be about any axis for 3D cabling files.

Flash Entity

The Flash entity may be used to represent a repetitive artwork feature which is usually produced by photo-optical means. Examples include PC pads, targets, clearances, and IC features.

Connect Point Entity

The Connect Point entity is used to represent a point of connection. A subfigure defining an electrical component typically uses the Connect Point entity to represent a pin of the logical or physical component or symbol. A Connect Point may also be used in a "stand-alone" mode, representing a via hole, for example.
212 General Note Entity

A General Note is used to display constant text. Design notes would require a General Note, for example.

302 Associativity Definition Entity

When the originating system provides for a relationship not included among the IGES predefined associativities, this entity is required. Possible uses are to relate subfigures to entities in other databases (e.g., circuit analysis or text requirements) or for back-annotation purposes.

312 Text Display Template Entity

Form 0: absolute, Form 1: incremental

The Text Display Template may be used to display text which may be unique in each instance of the defined entity (a pin number, for example).

320 Network Subfigure Definition Entity

For PC and Cable usage, a subfigure usually represents a component and its required PC constructs. This entity is normally a library physical or logical figure in the originating system.

402 Associativity Instance Entity

This entity relates other entities within a file to provide a "set" with a common meaning. Those associativities which are predefined by IGES are identified by IGES form numbers (e.g., form 18: Flow). The user defined associativities are defined by an entity 302 and its form number.

406 Property Entity

The use of a property to indicate the meaning or purpose of a geometric entity applies to electrical constructs as well as general graphics. A Connect Point
entity may point to the Drilled Hole property. A Plane entity or Simple Closed Area entity may point to the Region Restriction property. Any property, however, may point to the Text Display Template, with the text string specified in the property. In this case, the Text Display Template locates the text display. This entity is an open-ended list allowing for expansion to address future needs such as simulation, testing, inspection applications, and extensions into electrical/electronic systems hierarchical design.

412 Rectangular array Subfigure Instance Entity
414 Circular Array Subfigure Instance Entity

These entities may be used to instance multiple Network Subfigure Instances, but must not be used for instancing Connect Points.

420 Network Subfigure Instance Entity

This entity allows an electrical component to be instanced in a number of unique locations. Note that "owned" Connect Point entities must be instanced with this entity.
Figure B-1 General Pointer and Entity Model

APPENDIX B - ELECTRICAL ELECTRONIC
PRODUCT REPRESENTATION

--- 1 PER UNIQUE SUBFIGURE ---

- GEOMETRY

- NETWORK SUBFIG. DEF

- CONNECT POINTS

--- 1 PER UNIQUE SUBFIGURE ---

- GEOMETRY

- NETWORK SUBFIG. DEF

- CONNECT POINTS

DEFINITION [TO OTHER SIMILAR FLOW ASSOCIATIVITIES OF DIFFERENT TYPES, THEREBY ASSOCIATING LOGICAL WITH PHYSICAL DATA]

MANY INSTANCES

- NETWORK SUBFIG. INST

- CONNECT POINTS

TEXT TEMPLATE

- OTHER CONNECT POINTS USING THIS TEMPLATE

PROPERTY

- APPROACH ANGLE RESTRICTION

- DRILL HOLE

TEXT TEMPLATE

H-70
### TABLE 1. TEXT TEMPLATE VALUES FOR SAMPLE SCHEMATIC

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**PINS USING THE TEXT TEMPLATES**

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**Figure B-2 Sample Schematic**

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H-71
Figure B-3 Entity Relations Chart for Sample Schematic
Figure B-4  Schematic/Physical Diagram for Sample Schematic
Appendix I

RESEARCH TO TEST AND DEMONSTRATE THE CONCEPTUAL INFORMATION MODEL, 2 APRIL 1987
A. INTRODUCTION

Much research in the area of computer-aided engineering/design/manufacturing (CAE/CAD/CAM) software integration techniques has occurred over the last several years. This research has produced many discrete theories concerning information modeling and the development and implementation of neutral data exchange formats. There have been very few, if any, demonstrations of how these theories can be tied together for practical application in the CAD/CAM domain. With respect to the CAE domain, however, the practical application of these theories in a global context is non-existent. It is time to test the concepts developed and put the theory to use in a global context for CAE. This paper proposes a project to prove or disprove the viability of these theories for solving CAE/CAD software integration problems.

B. BACKGROUND

The proliferation of special-purpose software design tools has led to the need to transfer design data between disparate engineering databases. Users and developers of design systems seek exchange mechanisms which minimize the cost of creating interfaces between the design tools and maximize the integrity of the data exchange. When more than two dissimilar databases share data, the most sensible transfer mechanism is via a neutral interchange format. Users and developers of design automation tools have committed substantial resources toward the development of neutral interchange formats.

This effort has resulted in many formats either under development or currently in use for the exchange of design data between CAE/CAD/CAM tools. One segment of the CAE/CAD/CAM industry, the electronics industry, is focusing particular attention on four formats: the Initial Graphics Exchange Specification/Product Description Exchange Specification (IGES/PDES), the Electronic Design Interchange Format (EDIF), the VHSIC Hardware Description Language (VHDL), and the Institute for Printed Circuits (IPC) D-350 series. These standards are capable of representing some
particular aspect of design data for electronic equipment. They are neutral and non-proprietary.

These standards were developed to serve the needs of applications specific to the members of the respective development efforts. For instance, IGES was originally developed to interchange geometric information. This has been extended to include many other types of information such as electronic design data. EDIF was intended for the exchange of gate array and semi-custom design data between IC design organizations and IC foundaries. It has been subsequently enhanced to include additional data such as printed circuit board design data. VHDL is a hardware description language (not a format) for system design and can be used to transfer design data from designers to manufacturers to other designers. The IPC-D-35x formats describe printed wiring board (PWB) data for exchange between PWB design facilities and manufacturing groups. The series has been extended to include schematic and other electrical descriptions.

There has been minimal contact, however, between the IGES, EDIF, VHDL, and IPC organizations during development activities. This has resulted in semantic overlaps between the formats. The extent of overlap between the standards is ambiguous, and has not been fully analyzed. This ambiguity makes it difficult to develop sound and extensible exchange mechanisms for global integration projects. The problem is made more complex when the integration task requires the use of more than one standard. Thus, the interrelationships between the standards must be well-defined and understood. The standards should be viewed as complementary rather than competing. This perspective necessitates a formal definition of the interoperability of the standards.

To unambiguously define the information content (semantics) of each standard with respect to one another and to identify the areas of overlap, a common means of communication is necessary. Conceptual information models which depict fundamental data elements and relationships between those elements are capable of representing "the consensus view of the business rules of an enterprise." This is the genre of meta-language needed to talk about exchange formats.

Many people believe that a conceptual information model for electronic equipment can be used as a basis for the analysis of the areas of overlap between standard exchange formats. The IEEE Design Automation Standards Subcommittee has initiated an effort to create a conceptual information model for electronic equipment and to use that model to analyze the exchange capabilities and interrelationships between EDIF, VHDL and IGES/PDES. Ultimately, the analysis
will support a formal definition of the interfaces between the standards. This is a very ambitious project.

The information model for electronic equipment will be incorporated in a large-scale conceptual information model for product data under development by the PDES organization. This global conceptual model will be used as the foundation of the PDES format.

The development of the PDES conceptual data model is proceeding slowly. This is due to the highly theoretical and abstract nature of the concept and the methodology. Information modeling for engineering product data is still in the research stage. Issues yet to be resolved include:

1. What is a conceptual model for engineering product data?
2. What is the most appropriate modeling language and methodology?
3. What computerized tools are necessary to support the modeling methodology and the use of the conceptual model?

The process of creating a conceptual data model for engineering applications requires many expert participants (such as electrical and mechanical engineers) committed to the effort and committed to providing rigorous attention to minute details. This commitment will not occur until the CAE industry clearly understands the utility of the conceptual information model and the neutral exchange formats as a foundation for CAE integration.

This gap could be bridged by testing and demonstrating the use of conceptual information models and neutral data exchange formats to solve CAE software integration problems. This demonstration will serve as a communication device between a vast array of players (engineers, modelers, standards developers, CAE/CAD/CAM vendors, government representatives, politicians, budgeteers, etc.)

The objectives of the test/demonstration system are to:

1) show how one can take advantage of conceptual models and neutral exchange formats to integrate heterogeneous CAE design tools,

2) exercise a selected subset of the capabilities of the neutral exchange formats for electronics design data, and

3) identify critical issues for selecting information modeling languages and methodologies.
Appendix J

CAL POLY TASK TEAM STATUS REPORTS,
9 JANUARY-27 FEBRUARY 1987
STATUS REPORT  
9 January, 1987

A nucleus of the team met during this week to receive training on the Air Force "IDEF" modeling methodology and purpose. Excellent instruction was provided by Roger Gale and Jim Savage of D. Appleton Company.

We also looked at the computer resources to help us in the data administration and model normalization tasks. Here, we are fortunate to have a good DBMS to store and manage data of the model, the software tool JANUS installed at Arizona State University for model verification, and MACdraw for on-the-spot model views capture. We feel we have gained an understanding of a methodology for constructing a conceptual data model, and that model's solution to the problem of our CAE environment.

The intensive full-time modeling period which begins January 19th will be in Room 129 of the Electrical Engineering Building. Our expert team will include people from Westinghouse, McDonnell Douglas, General Dynamics, BITE, and View Logic Systems. We deeply appreciate the generous contribution to this effort from these companies. Any additional firms which can also contribute team membership are encouraged to do it, particularly the February 9-27 session. Call the ECE Department for details or attendance information.

Some of the issues relating to publishing our model were discussed. Hopefully, one of the IEEE Proceedings will be targeted. There are also at least two industry "testbed" database systems in which the model will be converted into an operational environment and tested. The latter activity will follow our team's effort and may not be includable in our findings.

Don't forget our major review dates:

March 10-13  Boston Area Review and Workshop
March 23-27  Bay Area (Livermore) Review and Workshop
April 13-17  Wright-Patterson AFB Presentation and Mappings Workshop

Check issues of the applicable area IEEE "Bulletin" for announcements. We will have telephone numbers to call in the next Task Team letter.

Richard Cockrum  
ECE Department Chairman
STATUS REPORT
January 23, 1987

Please note the following correction to the January 9 status report:

The date of the Wright-Patterson AFB Presentation was incorrectly recorded as April 13-27. 
The correct dates are April 13-17, 1987.

We do not yet have telephone numbers for you to contact regarding reservations for the review. We will publish them as soon as they become available.

The Team has constructed an entity pool from two printed wiring assembly models, the IGES connectivity entities, the EDIF glossary, and the data model of EDIF produced in the U.K. (The EDIF data model was clarified by comments of Dr. David Chalmers of STC Ltd., who joined the Team on Friday, January 23.) Most of the source list entities were associated with about half as many conceptual model data entities. The entity pool will be expanded next week as the Team reviews the VHDL (VHSIC Hardware Description Language) documents, the IEC (International Electro-Technical Committee) Electrical Component Library Definition, and several other source documents.

The "functional-connectivity" portion of the data model has been greatly modified as a result of the new entity definitions. The division of functional connectivity and physical connectivity has also affected the model structure. The new functional view will be integrated with the "truth table" view as an entity-relationship model. This part of the model will then be set aside until other parts of the model are constructed so that keys (i.e., key attributes of the entities) and their migration can be completed on the whole model.

The Task Team welcomes the interest of the Air Force EIS Program Office and would also welcome any interest by those wishing to join this exciting activity for the second full-time technical modeling session, February 9 to February 27, 1987, at the Cal Poly campus in Pomona, California.

Richard Cockrum 
ECE Department Chairman
STATUS REPORT
6 FEBRUARY 1987

1. The Electrical Function Model was revised this week to show that a Functional Unit Output Signal Requirement may be related to more than one Specified Functional Unit Input State. This is the model of the truth table which states that several different input combinations will produce the same output.

2. We have spent considerable time studying the VHDL documentation with an interest in understanding it and discovering conceptual data entities and attributes which should be incorporated into our model. Our thanks for some topical clarification from Erich Marschner of CLSI, Inc. by telephone today.

We have modeled two separate ideas which we have named Network and Signal. The Network is a name for the idea of functional connections. Signal is a name for a difference in potential between two Networks. We have an idea named Node which represents a place where a function of a Functional Unit may be accessed. A Network is a connected set of Nodes.

VHDL appears to use Signal to represent what we have called Network. For purposes of simulation, in VHDL values (i.e., voltages) can be assigned to Signals. Different values can be assigned to the same Signal name at different times. VHDL has a concept of Port. A Port seems to correspond to our Node. VHDL distinguishes between Formal Port and Actual Port. A Formal Port is a place of access to a Design Entity. When a Design Entity is "instantiated" (used in relation to some other Design Entity), a Formal Port becomes an Actual Port. The Actual Port must be assigned a name (which may be the same as its Formal Port name).

As of this week we have a concept that a Node may be part of more than one Network. For example, when tri-state devices are involved, a device is sometimes functionally connected and sometimes not. This means that Networks are dynamically defined depending upon the state of the devices. When we develop the physical design, we will have a mapping from the logical Networks to the physical connections of devices. At the moment, we are thinking of the physical connectivity as being named a Path. Our present thoughts are that a Path may map to more than one logical Network. This is part of our solution to our intent to make clear distinctions between the functional requirements view and the physical solution view.

VHDL contains the idea of a Bus. An individual signal can be declared to be a Bus, which means that it may have more than one driver. VHDL provides for a user-defined, bus arbitration rule which will define how to determine what is present on the Bus, or the effective connectivity at any particular moment in time.

As of this report the only time requirement provided in our model is the constraint on when an output signal should be present after an input state has been established (Functional Unit Output Signal Propagation Delay Specification). VHDL shows that we probably need to understand and model requirements and specifications as they relate to time.
The conceptual data model is limited to defining the meanings of data and relational integrity constraints among data. It provides a model showing where data belongs after actions of people, machines or computer programs have brought the data into existence. The data model is not intended to capture the rules under which actions must be performed. VHDL has a larger scope and is not limited to defining conceptual data. It also defines some of the rules for actions which result in data and for operations upon that data.

3. In VHDL, we find the use of a "Port" to apply an environmental requirement (temperature). This has caused us to wonder where in the general data model we should find all of the environmental requirements.

Richard Cockrum  
Chairman  
ECE Department
STATUS REPORT
13 FEBRUARY 1987

1. All three model reviews have been established. A "news release" is attached for your consideration, and please feel free to pass a copy along to your favorite editor.

2. There was a discussion about the identification of a Functional Unit. There was an opinion that it probably is a name. We were concerned about the uniqueness of a name. The discussion led to the ideas that a Functional Unit is identified not only by its name but also by the identification of the Enterprise which spawned it. Further discussion proposed that there is another limiting context needed. This is the idea which seems to be represented by "Project", "Product Line", "Product Model" and similar ideas. A concatenation of Enterprise ID, Context ID and Functional Unit Name should be unique. We have drawn a small FEO to illustrate this idea.

3. An idea was introduced that a Functional Unit serves to collect two separate ideas. One idea is that of a Functional View and the other is that of a specific "Functional Design". The Functional Unit may have many Functional Views but zero or one Functional Design. The intersection between Functional Design and Functional View is Function Sub Unit. This produced a lively discussion. We have captured this idea in a FEO.

4. Other rules differing from those in the 2/6/87 model were suggested as follows:
   - A Network is composed of Nodes and zero or one Ports.
   - A Port is a part of zero or one Networks.
   - A Node can participate in zero or one Networks.
   - A Signal is a difference of potential between two Networks and not related directly to Nodes.

5. There was considerable discussion of the effect upon the data model if we are capturing the data of incomplete functional designs. This was left as an unexplored area.

Anyone who would like to provide comments or additional insights is invited to phone the team between 8:30 am and 4:00 pm PST at (714) 869-2551 before 27 February 1987.

Richard Cockrum
Chairman
ECE Department
STATUS REPORT

20 FEBRUARY 1987

1. We have established a very useful notion for determining what data is within the scope of the model. This notion is consistent with and an extension to the PDES Product Data Planning Model.

We have identified three distinct structures of data which evolves over the product lifecycle: requirements, functional design solutions, and physical design solutions (green stuff, blue stuff, and red stuff respectively). The breakdown of design requirements are the controls on the "Design Electrical/Electronic Product" Activity Model for the activity, "Perform E/E Electrical Design." This data includes the demand specifications independent of any particular technology. The functional design solutions are driven by the demand specifications. These are the inputs and outputs of the activity "Perform E/E Functional Design" and include the connectivity and the design parts list. The important distinction between the requirements and the solutions is that the solutions are expressed in units of a particular technology; whereas the requirements are technology-independent. The physical design solutions define the breakdown of the physical characteristics of the design solution to the requirements.

The scope of our model includes all of the blue and red stuff (functional design solutions and physical design solutions). We understand the importance of capturing the green stuff (the demand requirements) in the conceptual model but will tackle this data at a later date. Our first priority is to capture the blue stuff. In whatever time remains, we will look into the red stuff.

2. The structure of the model has been modified to reflect the discussions and resolutions which have occurred during the team meetings. The model is ready for a public review. The entity and attribute glossaries are consistent with our current understanding of the model.

3. We are now putting together the presentation materials for the review sessions and organizing the source material that we have collected. The next step is to determine what we hope to accomplish during the model reviews, and what should be at the completion of the reviews.

Richard Cockrum
Chairman
ECE Department
STATUS REPORT
27 February 1987

We have reached a significant milestone in our efforts. We have come to the end of the initial modeling phase and are ready to present the results of our work for review and validation.

We have made much progress during the six weeks of the full-time effort. This includes the analysis of several data transfer formats for electronic design data, the review of three existing corporate models, and the identification of conceptual entities. The entities were developed into a workable model. We feel this model addresses the central data issues of functional product hierarchy, connectivity, and the input/output/delay relationships. The latter has been checked carefully to insure that the data involved in component "truth-tables" or VHDL "signal assignment" statements can be captured in a design implementation form. That is, the model captures the electrical voltage values which are the actual implementation of the Ts and Fs or 0's and 1's of a truth table. We believe that the same entities of the model will also capture the data which describes the behavior of analog devices.

We will continue the development of the model with several activities. The model is being input to a model database for normalization and documentation. The model will be presented at three public reviews. The reviews will include workshops during which modifications to the model may occur. Following the workshop in Dayton, the team's final information model kit will be sent to the team members, IEEE/DASS, and the Product Definition Exchange Specification (PDES) organization.

The model will be validated and its scope extended through continuing efforts in related projects including the Engineering Information System (EIS), Computer Aided Logistics Support (CALS), and PDES. Additionally, several companies will be developing databases to test the schema in a production environment. The model will be available in the JANUS program input language at the Arizona State University "Integrated Information System Support" Lab. The IEEE/DASS has organized an Electrical Model Working Group, chaired by Mrs. ML Brei, to continue the development and unification of the model. Please keep Mrs. Brei advised of your interests and any related work.

We feel that the conceptual schema for shared product data will be of great value in the development of integrated CAE/CAD/CAM environments, transfer formats, company databases and, the longer range goal, Computer Integrated Manufacturing (CIM). In the long-term, less software will be needed to share data based on a common schema.

Richard H. Cockrum
Chairman
ECE Department
Appendix K

CAL POLY TASK TEAM TRIP REPORT, 5 JANUARY 1987
CAL POLY TASK TEAM SESSION 1
January 5-9, 1987

1. The Cal Poly Task Team met during the week of January 5, 1987 at the California State Polytechnic University in Pomona, California. Professor Richard Cockrum of the Department of Electronics and Computer Engineering is the point of contact (714-869-2511).

2. Curtis Parks (General Dynamics) hosted the session. In addition, the following attended:

   ML Brei (BITE Inc. for the Institute for Defense Analysis)
   Roger Gale (D. Appleton Company)
   Jerry Kane (Westinghouse Electric Corporation, Defense & Electronics)
   John M. Rychlewski (McDonnell Douglas Astronautics Company)
   Jim Savage (D. Appleton Company)

3. The purpose of the week-long session was to receive training in the IDEF1-x methodology. Roger Gale and Jim Savage provided the team with excellent training. See attachment 1 for a list of reference material used during the training.

4. The goal of the Cal Poly Task Team is to create a conceptual data model of electrical and electronic products. The conceptual model will be used for at least two purposes. First, it will be integrated with the conceptual product model under development by the Product Data Exchange Specification (PDES) working groups. The PDES conceptual product model will be the semantic foundation for the specification.

   Second, the IEEE Electronic Modeling Group (EMG) will use the model to evaluate and compare the extent to which the Electronic Design Interchange Format (EDIF) and the VHSIC Hardware Description Language (VHDL), and PDES expresses electronic design data.

   Both efforts will make valuable contributions toward the advancement of CAE integration strategies.

5. The Cal Poly Task Team will begin its first 3-week full-time session on January 19. The second session will begin on February 9. These sessions will be held at the Engineering Building (714-869-2551). Once again, Professor Richard Cockrum is the point of contact.

   Following the completion of the data model, a series of reviews will be held to assess the soundness of the model from the perspective of diverse sectors of the design community. The proposed schedule is as follows:

   10-13 MAR 87 Boston
   23-27 MAR 87 Lawrence Livermore Laboratory
   13-17 APR 87 Wright-Patterson AFB
6. The following was agreed upon at the completion of the week:

1. SCOPE of the information model: the information requirements of the activity model derived from the previous CAL Poly working sessions (all design activities prior to engineering release to manufacturing).

2. RANGE: Printed circuit board/assembly and round wire harness

3. DELIVERABLES:
   A. Data Model: Diagrams, Glossary, Business statements/rules
   B. Technical Issues List
   C. Periodic status reports
   D. Review kits
   E. Final Report - for IEEE publication

4. ACTION ITEMS:
   A. Develop list of Review Kit Respondents.
   B. Contact review hosts.
   C. Identify technical writer (CAL Poly project?) for final report.
   D. Prepare guidelines for review working meetings and host activities.
Appendix L

ELECTRONICS STANDARDS COORDINATION MEETING REPORT, 4 FEBRUARY 1987
The first Electronic Standards Coordination Meeting was held on December 17, 1986 at the Institute for Defense Analysis in Alexandria, Virginia. Bruce Lepisto, Chairman of the CALS Working Group on Specifications and Standards, DoD Weapon Support Improvement & Analysis Office, chaired the meeting. Agenda items follow.

A. OPENING REMARKS. Dr. Frederick Riddell, The Institute for Defense Analysis.

The Institute for Defense Analysis provides a neutral forum addressing the needs of the DoD community. In this capacity, it has contributed to several DoD Computer Aided Logistics Support (CALS) activities.

The success of the CALS program hinges on the identification of a set of standards for the interchange of technical product data in digital form and the definition of the relationships among those standards.

The purpose of this meeting was to begin the process of exploring issues concerning data interchange standards for electronic equipment by:

1) discussing the interaction of the standards in terms of DoD's CALS requirements, and

2) reaching an agreement on an appropriate approach for resolving the standards overlap issue.

B. CALS OVERVIEW. Bruce Lepisto.

The goal of the CALS program is to implement a near paperless environment for the delivery and use of logistic technical information. This requires integrating the design, manufacturing, and logistic support functions by linking together automation tools.
To accomplish this, a management structure consisting of both DoD and industry groups to design, develop, and implement CALS has been put into place; weapon system contract deliverables and functional requirements are being identified; and an aggressive schedule has been set.

Each service released implementation plans in July 1986. In September 1986, the DoD development strategy for CALS was published. The DoD CALS implementation plan will be available in January 1987.

To accomplish a phased implementation strategy, a series of Core Requirements Packages will be produced. The initial requirements will address the use of existing technology and standards to apply CALS capabilities. Thus, during the first phase the focus will be on what can be done today. In the longer term, the emphasis will shift to extensive system redesign.

C. PHASE I CORE REQUIREMENTS. Bruce Lepisto.

The first phase Core Requirements will contain management guidance for implementing CALS programs. This guidance includes standards for data interchange and communication; requirements, contractual terminology and application and user guidance. The following schedule has been set for the development of this package:

87 FEB  Draft Phase I.0 Core Requirements completed. Contains a placeholder for the electronic equipment standards.

87 MAY  Phase I.0 Core Requirements released as DoD policy and distributed to the services and the Defense Logistics Agency (DLA) for action.

87 SEP  Draft Phase I.1 Core Requirements released. This version will contain a definition of where and how the data interchange standards for electronic equipment should be used in DoD weapon system procurements.

+5 yrs  Implementation of Phase II of CALS, involving extensive DoD and industry data system redesign to provide an integrated digital support environment for weapon system design, manufacturing, and logistics.
D. EDIF OVERVIEW. Mike Waters, Chairman of the EDIF Technical Committee.

1. Background.

The Electronic Design Interchange Format, EDIF, facilitates the movement of electronic design data between sophisticated databases in a commercial environment. This provides links between disparate systems and corporate control over information content.

The EDIF development philosophy consisted of five tenets: five years is too late; less talk and more work is required; keep it simple; make it extensible and upwardly compatible; and do not create a design language or database. EDIF is intended for the representation of IC and electronic design data, not mechanical design data.

The EDIF organization was founded on November 13, 1983 at UC Berkeley. At this time, six companies and one university agreed to contribute on-going man-power toward the development of the format.

2. Organization.

a) Steering Committee: makes policy decisions and establishes business relationships between concerned corporations.

b) Technical Committee: coordinates the work of the technical subcommittees and is responsible for the technical content of the specification.

c) Technical Subcommittees: consist of specialists who make recommendations to the Technical Committee.

3. European Interest.

Participation in EDIF activities spans the U.S., Europe and East Asia. User Groups have been formed in the US, the UK, and Germany. There are both US and European technical subcommittees.

4. Affiliations.

a) An agreement to join the EIA/JEDEC will be signed in December, 1986.

b) The EDIF Evaluation and Analysis Group has been formed under the IEEE Design Automation Technical Committee (DATC/DASS).

c) EDIF was recommended for use at the January 1986 Engineering Information System (EIS) Seminar in Arizona.

5. Capabilities/Changes.
EDIF is capable of representing the electrical characteristics necessary for implementation of electronic products. It can express library/cell organization; provide extensive date/version control; describe the cell interface, cell details (contents), and technologies; and represent timing, geometry, and physical objects. Changes for version 2.00 (targeted for early 1987) include a number of extensions, changes, and refinements to the format.

6. Overlap.

EDIF addresses the IC description necessary for fabrication. This includes modeling and behavioral aspects and some printed circuit board descriptive material.

IGES targets the full printed circuit board design function as an extension to its mechanical description (ref. NCGS meeting 30 Jan 86).

VHDL, a high-level functional design language, addresses systems level descriptions/simulation. It is not intended for physical design data. Thus, rather than overlapping with EDIF, it is complementary.

E. IGES OVERVIEW. Brad Smith, IGES Chairman.

1. Background.


The most recent version of the standard, Version 3.0, was published in April 1986. It has been submitted to the ANSI Y14.26 committee and will be published as ANSI standard Y14.26M by the summer 1987.

The IGES 3.0 is about 530 pages long. IGES 4.0 will be released in the spring 1987.

2. Organization.

a) Steering Committee: makes strategy and policy decisions.

b) Technical Planning Committee: plans and coordinates technical activities.
c) Edit Committee: is responsible for the various IGES products.

d) Technical Committees of the General Assembly: focus on special interests within the IGES projects.

3. PDES.

The IGES Organization is also pursuing the development of the Product Data Exchange Specification (PDES). This is an R&D effort, underway for 2 years, addressing a different technology base than the IGES format. IGES is intended for information exchange between databases that must be interpreted by human beings. PDES is a complete database exchange that does not require human interpretation.

The complexity of these projects is enormous. This is due in part to a need for building in flexibility for future growth.

To handle the complexity, PDES will be developed using a 3-layer architecture (which divides the problem into 3 parts: logical, conceptual and physical). This architecture is being realized by using the ICAM Definition (IDEF) and NIAM modeling techniques.

Information models are being developed for specific application areas (mechanical products; electrical products; architecture, engineering, and construction; finite element modeling; and drafting) and constituent technical areas (manufacturing technology; solid modeling; curve and surface modeling; and presentation data).

The results of this work will be a roadmap for building exchange standards which are easy to implement, precise, less ambiguous, and easily testable (i.e. proving the implementation correct and complete).

The PDES initiation activities have been published and a testing document will be ready by April 1987.

PDES is the US contribution to the international Standard for the Exchange of Product Data (STEP) development effort. The goal is to develop a single international standard for complete product data exchange.

4. Electrical Applications Committee: Larry O'Connell, Chairman of the Electrical Applications Committee.

O'Connell reviewed the matrix sent with the invitation package and identified IGES capabilities that meet CALS requirements as outlined by the information categories. Included on the list are: 3-D graphics, full drawing capability, full connectivity, technical publications.
capability. associativity (such as identifying level of spares), and subfigures (to treat discrete units as groups).

IGES Version 4.0 will include the capability to attach attributes for reliability and maintainability considerations.

F. IPC OVERVIEW. Dieter Bergman, IPC Technical Director.

1. Introduction.

The Institute for Printed Circuits (IPC) is a trade organization formed in 1957 by six board manufacturers who were dissatisfied with existing organizations. Currently it has 1400 member companies, 28% of which are regular members, 35% are allied members, 31% are associate members, and 6% are government and technical liaisons. The organization focuses on both national and international concerns.

The IPC standard of interest to the CALS program is the IPC-D-350 series. Originally, IPC-D-350 was developed in 1971 to provide complete manufacturing data to produce unpopulated printed circuit boards. This includes single/double-multilayer boards, conductor definitions, hole information, board data, electrical data, etc. It provides direct conversion through translation for drilling equipment, phototool plotters, direct imaging equipment, testers, etc.

2. Implementation History.

IPC-D-350 was developed throughout 1970-71 and released in 1972. Revision A was completed in 1975 after which the first contract specifying its use was issued. During this time period, joint industry and DoD coordination meetings were held, and ANSI approval (coordinated through ANSI Y14.26) was granted.

Revision B was published in August, 1977 and reaffirmed in October 1985. This update provided more flexibility for implementation, omitted the standard font and land patterns, and in general, was simplified for small company use. It was approved for use by DoD and became a requirement for MIL-STD-275 and MIL-STD-2118. As a result of the DoD endorsement, a 5-year no-change policy was agreed to.

The major user of the standard is the National Security Agency (NSA). Originally, NSA was one of the few organizations with the expertise to receive electronic data and they were willing to work with the vendors. NSA has provided invaluable input to the IPC committee.

The standard has been submitted by the US to IEC 52 (USA)
3. Long Range Objectives.

Future IPC activities are focused on meeting NSA/DoD objectives. This includes producing a complete definition of an electrical assembly from design to manufacture to test to hardcopy.

If necessary, the IPC organization will change the language to meet the users needs. The intent is to produce a single document which is useful to industry and the government.

4. Problems.

As a result of the experience with NSA, the IPC organization has learned that the following may hinder the success and/or usefulness of a standard:

a) too much implementation flexibility,
b) minimum support by CAD system vendors,
c) industry usage abuse,
d) inadequate training/promotion/visibility,
e) experience of tri-service personnel, and
f) the lack of public domain tools such as translators.

G. VHSIC Hardware Description Language (VHDL) OVERVIEW. Dr. John Hines, AFWAL/AAD VHSIC Program Office.

1. The Problem.

The primary problem facing the electronic design community is the tremendous amount of documentation that must be created during the design process. The solution is to streamline the design and documentation of advanced digital systems. Existing hardware description languages are incapable of accomplishing this because their evolution was not planned.

The need for a hardware description language to input design data became very apparent by 1979. This language would:

- provide a human readable design description,
- support the communication of design data among vendors (second sourcing) and between vendors and users (design specifications),
- integrate the activities of designers working at different levels of abstraction, and
- increase the re-usability of hardware designs and descriptions.

In addition to a hardware description language, an intermediate format is required to interface between
standards and languages.

2. Axioms.

a) Languages are for communication.
b) Hardware description languages are languages, not methods.
c) Languages require standard "practices and usage" rules for communication.
d) The model is in the eye of the beholder.
e) Models must communicate with other models (e.g. the designer communicates with the manufacturer).
f) IGES and EDIF are viewed as manufacturing protocol standards.
g) No standards exist for models, it is difficult to get companies to talk to one another.
h) Documentation views require different types of data (the programmer, designer, functional test activity, and reprocurement activity are concerned with different views of the design).

3. Purpose of VHDL.

a) Provides a standard medium of communication for hardware design data.
b) Represents information from diverse hardware application areas.
c) Supports the design and documentation of hardware.
d) Supports the entire hardware lifecycle.


a) June 1981. Developed initial requirements documentation at a workshop in Woodshole, MA. (Prior to 1980, no commercially-available hardware description language existed. Work was predominantly in academia).
b) June 1982. Draft Request For Proposal (RFP) was issued for the development of VHDL and the associated set of tools.
e) August 1986. VHDL released version 7.2.


The vendor provides the component description to the user in a design environment who produces the layout drawings.

Electrical Engineers think in terms of transforms. The primary VHDL model is the DESIGN ENTITY. Input and output
ports, signals, and functions are defined using the black-box approach.


VHDL version 7.2 has been submitted to the IEEE VHDL Standardization and Analysis Group (VASG) under the Design Automation Standards Subcommittee (DASS).

A radical standardization approach was adopted to avoid the mistakes made during the ADA standardization process. The key is to disallow extensive language revisions during balloting. A company was funded to perform the formal analysis of the language issues and to provide formal support to the IEEE committee. To expedite the resolution of issues raised by industry, eight meetings were scheduled and held from March 1986 through October 1986. During these meetings all issues were resolved.

The draft standard will be published by the end of December, 1986. This document will be distributed widely and comments will be solicited. After the appropriate revisions are made, balloting will begin.

7. Participants in the development effort.

a) Major CAD companies: ENDOT, Daisy, H-P, Mentor, Silvar-Lisco, etc.

b) Universities: Stanford, Virginia Tech, Rensselaer Polytech., etc.

c) Major companies: General Dynamics, Boeing, Sperry, IBM, etc

8. Issues.

The primary concern is language validation. There is no precedent for validating simulators. NBS has been requested to provide metrology (development of the validation tools) and mensuration (administering the validation tests for the VHDL environment) services.

H. LOGISTICS INFORMATION MODEL MATRIX. Don Hall.

The purpose of the Logistics Information Model Matrix is to create a means of unambiguously identifying the extent to which existing data interchange standards for electronic equipment meet DoD logistic application needs. Appendix 7 contains the objectives of the matrix, ground rules for development, an initial version of the matrix, examples of logistics applications, and suggested development steps.
Users from various application areas will be asked to review the matrix as it evolves. To develop short and long-term strategies, the matrix will be examined for holes and redundancies. Appropriate review groups include: the testing community, the RAMCAD working group, and the diagnostics working group.

I. OPEN DISCUSSION.

Is the matrix approach a reasonable way for OSD (the user of the information) to view the problem?

Reactions:

1. The matrix, as a management tool, is a convenient way to determine:
   a) which standards cover the required data elements, and
   b) whether or not all required data elements can be represented by at least one of the standards.

2. The matrix needs much fine tuning and some reconfiguration. Noticable problems with the matrix include:
   a) The Tester Independent Software Support System (TISSS) is not represented by the matrix. Testability, on-line maintenance, etc. is not addressed.
   b) The term "schematic", although well-known by many members of different communities, has too many definitions. Thus, it is an imprecise and even dangerous term.
   c) A glossary is needed.
   d) A text story describing the development of some ficticious electronic product should be written to understand the matrix (see the Case History under the Recommendations section).
   e) Several data element lists may be needed.
   f) The size of the list is not a great concern, however, an environment dimension may be required. Aspects of this dimension include:
      1) performance of a design unit and
      2) observed, statistical measures of its defined parts.
   g) Cabling and harnessing should be a separate category.
   h) Manufacturing requirements dictate a categorization of
digital data.

3. The matrix is not intended to solve all of the problems facing the electronic design community. Its focus is on logistic applications, although it shares many information requirements in common with design.

4. The matrix is a laundry list. This is not a bad start but the solution requires full-scale data modeling efforts. Logistics representatives should participate in the California State Polytechnic University (CAL Poly) task team for data modeling which begins in January 1987.

5. It may be appropriate to present the matrix at the Design Automation Conference, June 1987; in Miami, Florida. This will draw more participants and trigger additional reviews.

6. Existing standards should be reviewed to test the completeness of the matrix. This was done in the course of preparing the language requirements document for VHDL.

7. The information generated by ITDOES should be helpful.

8. The development of the matrix is feasible in the proposed timetable if interim sessions, mailings, and revisions are properly managed.

9. OSD has tasked the NBS to coordinate the development of the matrix. Much work is already being done by standards and industry associations which could be incorporated into the matrix. There is limited funding available from DoD, however, to piece together these efforts. Thus, DoD should encourage the continuation of the voluntary activities.

10. The matrix could be viewed as a subset of the EIS. The EIS program is concerned with the design information problem and will be investigating the interface standards and the mappings between them. For instance, the mapping between system design and manufacturing is accomplished with VHDL->EDIF or VHDL->IGES.

11. After the matrix is finished, mapping from one language to another becomes the critical technical problem. Information models will be required to examine the relationships between the standards. This may best be accomplished in a university setting.

In addition to the matrix, we will need examples of how each standard represents a particular type of data.

Various groups are in the process of defining relationships among data exchange standards. For instance, the VHDL program will be defining a formal mapping between EDIF and
VEDL as part of the final documentation.

J. SCHEDULE.

The schedule proposed at the meeting has been revised to reflect further input. The following represents the latest proposed dates:

17 DEC 86 Matrix, Initial version
13 JAN 87 Matrix, Interim version complete. Distributed to the Electronic Standards Coordination Committee for review.
15 FEB 87 Matrix version 2 complete. Compiled from results of the inputs from the standards groups.
03 MAR 87 Workshops begin.
16 MAR 87 Progress Review.
30 MAR 87 Workshops.
14 APR 87 Workshops.
01 MAY 87 Matrix version 3 complete.
03 MAY 87 Final workshop.
11 MAY 87 Progress Review.
29 JUN 87 Matrix version 4 presented at DAC. Workshops.
24 JUL 87 Workshop finale.
03 AUG 87 Final Review meeting.
28 SEP 87 Phase I.1 Core Requirements released.

K. RECOMMENDATIONS.

1. A case study describing the acquisition process of an electronic product from the CALS perspective should be developed. (See attachment.)

2. DoD should leverage the work that is underway by the various standards organizations (i.e. the CAL Poly data modeling activity).

L. ACTION ITEMS.

1. Distribute the revised matrix by January 13 to the Electronic Standards Coordination Committee members. (OSD)

2. Review, revise, and return comments on the matrix, version 2 to OSD, ASAP. (Everyone)

3. Prepare the electronic product case history. (B. Winner)

4. Distribute the matrix and associated documentation to the members of the concerned organizations. (Everyone)

5. Send materials to be incorporated into the matrix to OSD. (Everyone)
6. Send additional ideas concerning the matrix and schedule to OSD. (Everyone)

7. Prepare a definitive schedule for the workshops and progress reviews. (OSD)

M. ATTACHMENTS.

1. "The Life History of an Electronic Product from a CALS Perspective"
2. Meeting Agenda
3. Attendee List
4. Mailing List
6. DoD Initiatives in Computer Aided Logistic Support
7. Logistics Information Model for Electronic Equipment
8. "EDIF Version 200 Takes on Production Environment"
9. EDIF in Europe
10. Call For Participation: Standards Task Team Information Model Development
11. Vu-graph presentation: EDIF
12. Vu-graph presentation: IPC
TO:  F. Riddell, R. Gunkel
FROM: ML Brei
SUBJ: NOTES: The Life History of an Electronic Product
DATE: January 2, 1987

The Life History of an Electronic Product from the CALS Perspective

A. BACKGROUND.

The CALS Electronic Standards Coordination Committee has recommended that a case study describing the acquisition process of a typical electronic product be developed. This work will be done by the Institute for Defense Analysis, CSED group, under funding by the VHSIC Program Office for Engineering Information System activities.

This case study will provide a contextual framework for creating and understanding the Logistics Information Model Matrix. It will serve as a reference point to test the correctness and completeness of the matrix as the matrix is conceived. The terminology defined in the case study will be used to interpret the matrix.

B. OBJECTIVES.

The case study should:

1. Track the development of an electronic product (consisting of digital, analog, and electro-mechanical components) through:
   a) conceptual design
   b) engineering analysis
   c) detailed design and development
   d) production
   e) testing
   f) delivery
   g) field support
   h) re-design

2. Define internally-consistent terminology for:
   a) the life cycle phases (i.e. the process)
   b) the functions performed and who performs them
   c) contractor and defense relationships
   d) applicable mil-specs
   e) data required to support the prime and sub-contractors

3. Describe all data exchanges required
C. DEVELOPMENT STRATEGY.

1. Prepare the strawman document (approx. 15 pages).
   Target completion date: February 15, 1986.
   a) Describe an abstract notional system.
   b) Identify sources of information (existing descriptions of information flow, military standards and specifications, etc.)
   c) Extract applicable information from the information sources.
   d) Prepare results.

2. Distribute strawman document to OSD and Electronic Standards Coordination group for review and refinement.

3. Distribute the revised case study document to the user groups developing the matrix.
AGENDA
December 17, 1986

Introduction:

0900 Opening Remarks F. Riddell
0915 CALS Purpose and Objectives B. Lepisto

Status, domain and development philosophy of each standard (10 minutes each):

0930 EDIF R. Smith
0940 IGES B. Smith
0950 IPC D. Bergman
1000 VHDL J. Hines
1010 Break (15 minutes)

Discussion of the issues:

1025 Overview of the DoD Requirements Matrix D. Hall
1100 Discussion B. Lepisto (moderator)
1200 Lunch (1 hour)
1300 Continuation of Discussion B. Lepisto
1500 Plan of Action and Issues B. Lepisto
1700 Adjourn

L-17
### Attendee List

<table>
<thead>
<tr>
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<th>Organization</th>
<th>Phone</th>
</tr>
</thead>
<tbody>
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<td>Ron Waxman</td>
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MEMORANDUM FOR THE DOD CALS STEERING GROUP

SUBJECT: Development Strategy for CALS

One of the primary objectives of CALS is the development of a unified DoD interface with industry for the exchange of technical information in digital form. The attached paper outlines a phased strategy for achieving this unified interface. It incorporates your comments on the development of a "core" package of common DoD requirements and standards for CALS applications, which can be tailored and extended by the Services in specific contract implementations. This broadly defined strategy should be incorporated in Service and DLA CALS implementation planning now, and we should continue our cooperative efforts to work out the details.

We are planning a series of working sessions to discuss the content of this strategy and to lay the groundwork for the Phase I core package. As previously announced, the first such CALS architecture planning session is scheduled for 7 October 1986 at National Bureau of Standards (0900-1400 in the AMRF conference room). I would appreciate your forwarding the attached paper for review by the appropriate implementing offices, and for seeing that their inputs are provided at the 7 October meeting and subsequent sessions.

Our goal should be to have all comments on implementation of this strategy resolved by 7 November for incorporation in updated Service and DLA CALS implementation plans and in the summary DoD CALS plan that we have targeted for public release in December.

Russell R. Shorey
Chairman, DoD CALS Steering Group

Attachment
CALS Development Strategy

Overview

The overall objective of CALS is to integrate and improve design, manufacturing, and logistics functions through the efficient application of computer technology. Implicit in this objective is a substantial shift from current paper intensive processes to a highly automated mode of operation. The major CALS challenge is to develop compatible information system architectures in DoD and industry that can be rapidly implemented without incurring excessive costs. To ensure compatibility, the Services need a common DOD CALS "core" specification as a point of departure for their system designs and applications. This paper broadly outlines a strategy to meet that challenge and to provide the direction to achieve the CALS goal of a unified DoD interface with industry for digital data exchange.

The proposed development strategy segments CALS evolution into two phases, with central development of a "core" requirements package for each phase. Phase I will focus on a few major logistic applications, and will use available technology and standards to implement digital data exchange between existing and emerging automated systems in DoD and industry by 1988. Phase I will also define the minimum initial functional requirements for integrating R&M into the computer aided engineering and design process. Phase II will rely on strong industry involvement for a broad based system redesign to implement more advanced technology and more capable data exchange standards, and to support a wider range of logistic applications throughout a weapon system's life cycle.

Phase I

The primary Phase I objective is to develop, within six months, initial "core" CALS requirements packages for the common DoD elements of CALS applications. These requirements will be tailored by the Services and implemented in contracts with industry (both weapons system contracts and automated system contracts). These common requirements must include the functional requirements which describe data processing, interactions, and updating capabilities; and the technical interface standards for exchanging data among contractors, and between contractors and DOD.

Phase I requirements will be commensurate with available technology and data interchange standards. For example, Phase I may require the delivery of technical manuals in digital form to
nodes in the Service distribution system for page image display or "on demand" printing, but the capability for paperless interactive display to end users may be deferred to Phase II. Existing data exchange standards, such as those in the draft MIL-STD-xxxxx on Automated Interchange of Technical Information, will form a part of the Phase I core.

Phase I will initially focus on three key logistic applications, which encompass most of the elements currently envisioned for a CALS architecture. These are:

1. Spares reprocurement (including access to engineering drawings and other needed data)

2. Development and delivery of technical publications (including updating and corrections)

3. Development and application of Logistics Support Analysis data (including online access to contractor data systems).

Additionally, Phase I will define the minimum requirements for integrating R&M into the Computer Aided Design/Engineering (CAD/CAE) process now being implemented in industry. These initial requirements are expected to address the interfacing of existing R&M design tools with CAD data bases, and providing R&M analysts online access to the same data base that design engineers use.

Phase II

The Phase II "core" CALS requirements package and Service extensions will take advantage of advanced system integration technology to integrate engineering, design, manufacturing and the development of logistics data, and will cover the full spectrum of life cycle design, manufacturing and logistic applications. For example, the Phase II requirements may include such features as guaranteed consistency of logistic data products to match weapon system configuration, available online to a variety of users. Phase II will also take full advantage of data exchange technologies who difficulties are currently being worked out (e.g. exchange of engineering drawings in vector form).

In the area of design for supportability, the Phase II package would include common functional requirements ranging from the systems engineering process needed to allocate and manage support-related design characteristics to defining requirements for field feedback loops to assess, correct and prevent design related supportability problems. This will include integrated design and engineering analysis tools, such as computer aided
thermal analysis, computer aided failure modes and effects analysis, computer aided dependency modeling, computer assisted parts selection, etc.

Management

Developing CALS requirements that can be accepted by all the parties involved clearly requires cooperation with industry. Industry will be a major investor in any CALS system and additionally has unique experience and expertise. An industry CALS consortium taking advantage of the lessons learned from the MAP/TOP users group, the Corporation for Open Systems and the Software Productivity Consortium, is the recommended approach to getting the required full time industry involvement. The CALS industry consortium would include representatives from the full range of industries that will be impacted by CALS. This includes prime DOD contractors, subcontractors, software houses, computer manufacturers, CAE/CAD/CAM vendors, etc. (Shipbuilding may be a large enough area to sponsor its own consortium to develop unique system applications beyond the "core".) This consortium must have the resources and expertise to rapidly develop alternative cost effective industry implementation approaches complying with the DOD CALS "core" requirements packages and Service extensions. It could also provide verification and validation services.

The CALS industry consortium's primary Phase I task will be to develop the industry "core" implementing specifications to ensure industry systems will be compatible with the Phase I DOD CALS requirements and with one another (for prime-prime and vendor-prime exchange). To implement more advanced technology and data exchange standards, the industry CALS consortium, in cooperation with appropriate industry groups, should play a major role in developing Phase II specifications and should provide the primary interface between industry and DOD in this area. The Phase II implementing specifications would be in response to a coordinated Service and Agency requirements statement.

In parallel with efforts to start an industry consortium, DoD needs to get started on development of the Phase I core requirements package. The initial Phase I package will be prepared jointly by the DoD CALS Office and NBS (with support from D. Appleton Co.), in close coordination with the Services and the NSIA industry task force. The focus of this initial effort will be on defining the intersection of common DoD requirements in the Phase I applications, and identifying the standards and functional capabilities that contractor data systems must support. The Services will be the principal source of input for defining these Phase I core requirements. The Services will extend the core package in depth and scope in developing their own implementing specifications. NBS support will include assistance in developing and implementing
appropriate interface standards and access protocols as part of both the Phase I and Phase II core packages.

Current Service CALS implementation projects, such as the automation of data repositories and the automation of technical orders, will provide valuable inputs for Phase I specifications. Planned Service demonstration efforts and R&D programs should be targeted to validate the Phase I requirements and to support the development of Phase II CALS requirements by demonstrating the feasibility of advanced technologies and desired functional capabilities. Additionally, DoD's role in developing requirements for integrating R&M into the mainstream of the CAD design process should be strengthened by the high level involvement of the Service engineering communities.

The advantage of the phased approach to defining core CALS requirement packages is the ability to evolve CALS systems in an orderly way. The definition of the "core" and its depth of detail will need to be refined by trial and error with full involvement and leadership of the Services and Agencies. With the "core" defined initially within a few months, the Services can proceed directly in their system design efforts to address their own specific needs rather than successively reinvent the central architecture. Thus the Service design studies should be phased with the core development.

Since a number of elements of the Phase I core are already known, Service planning for test beds to gain practical experience with data exchange standards and protocols can proceed without delay, as can functional demonstrations to validate user interfaces and user data system designs.

Schedule

<table>
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<tr>
<th>Task</th>
<th>Responsibility</th>
<th>First Issuance</th>
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<tbody>
<tr>
<td>1. Review NBS Program and Phase I &quot;Core&quot; Applications</td>
<td>Industry Task Force</td>
<td>Dec 86</td>
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<tr>
<td>2. Phase I &quot;Core&quot; Requirements Package (Draft)</td>
<td>OSD CALS Office, Service Support</td>
<td>Feb 87</td>
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<tr>
<td>3. Initial Service Extensions of Phase I Core Package</td>
<td>Services, DLA</td>
<td>May 87</td>
</tr>
<tr>
<td>4. Industry CALS Consortium Chartered</td>
<td>NSIA Task Force Chairman</td>
<td>Jan 87</td>
</tr>
<tr>
<td>5. Industry-proposed Phase II Core Requirements, DoD Interfaces</td>
<td>Consortium</td>
<td>Jun 88</td>
</tr>
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CALS POLICY INITIATIVE
(DEPSECDEF MEMORANDUM)

OBJECTIVES

• ACCELERATE INTEGRATION OF R&M DESIGN TOOLS INTO CONTRACTOR CAD/CAE SYSTEMS

• AUTOMATE CONTRACTOR PROCESSES FOR GENERATING LOGISTIC TECHNICAL INFORMATION

• RAPIDLY INCREASE DOD CAPABILITY TO RECEIVE, DISTRIBUTE AND USE TECH INFO IN DIGITAL FORM

— BY 1990, NEW MAJOR WEAPON SYSTEMS WILL ACQUIRE TECHNICAL INFORMATION IN DIGITAL FORM
CALS IMPLEMENTATION PLANS

SERVICE, DLA PLANS (JULY 86)

- FOCUS ON:
  - ADP MODERNIZATION
  - TECHNOLOGY DEMONSTRATIONS, PROTOTYPES
  - ARCHITECTURES FOR INTEGRATION

- OVER 75 CALS PROJECTS IDENTIFIED IN 9 CATEGORIES

- PLANS ARE STILL EVOLVING, BEING COORDINATED

DOD CALS PLAN (DEC 86)

- FOCUS ON:
  - UNIFIED DOD INTERFACE WITH INDUSTRY
  - COMPATIBILITY OF SYSTEMS WITHIN DOD

- WILL SUMMARIZE SERVICE AND DLA EFFORTS
TARGET CAPABILITIES

- ONLINE ACCESS TO PRIOR DESIGNS
  - DRAWINGS AND SPECIFICATIONS
  - ENGINEERING CHANGES
  - PRODUCTION EXPERIENCE
  - FIELD RELIABILITY AND MAINTAINABILITY DATA

- ALGORITHMS RELATING DESIGN PARAMETERS TO R&M, PRODUCIBILITY

- AUTOMATED GENERATION OF DESIGN ALTERNATIVES

- SIMULATION OF THE DESIGN IN MAINTENANCE ENVIRONS
  - ACCESS, CLEARANCES, HUMAN FACTORS

- ONLINE MANUFACTURING PROCESS PLANNING AND SIMULATION

- INTEGRATION OF AUTOMATED ENGINEERING ANALYSES
  - TESTABILITY DESIGN AND FAULT TREE ANALYSIS
  - RELIABILITY ANALYSIS AND PREDICTION
  - FINITE ELEMENT MODELING
  - THERMAL ANALYSIS
  - DEVELOPMENT OF MAINTENANCE REQUIREMENTS
WEAPON SYSTEM CONTRACT
— 1990’s

DELIVERABLES

• PRODUCT DEFINITION DATA (ELECTRONIC FORMAT)
  — ENGINEERING DRAWINGS
  — 3-D PRODUCT MODELS

• TECHNICAL MANUALS
  — DIGITAL TO PAPER (AUTOMATED PUBLISHING)
  — DIGITAL TO DIGITAL (EG, INTERACTIVE MAINTENANCE AIDS)

• LOGISTIC SUPPORT ANALYSIS RECORD DATA

• TRAINING MATERIALS

• ILS MANAGEMENT DATA
WEAPON SYSTEM CONTRACT
— 1990’s

SPECIFIED FUNCTIONAL REQUIREMENTS

- INTEGRATED DESIGN, MANUFACTURING, LOGISTICS DATA BASE
  - NEAR REAL TIME CONFIGURATION UPDATES
  - SPECIFIED GOVERNMENT ACCESS
  - DATA BASE TRANSPORTABILITY

- ONLINE R&M DESIGN TOOLS IN CAD/CAE ENVIRONMENT

- AUTOMATED GENERATION OF LOGISTIC DATA PRODUCTS
  - NO UNNECESSARY DUPLICATION OF PREPARATION EFFORT
  - PAPERLESS DELIVERY CAPABILITY
ACQUISITION STRATEGY

- PHASED IMPLEMENTATION
  - ADP MODERNIZATION (DOD, INDUSTRY)
  - TECHNOLOGY DEMONSTRATIONS, PROTOTYPES
  - LEAD WEAPONS SYSTEM PROGRAMS
  - ROUTINE CONTRACTUAL IMPLEMENTATION

- ESTABLISH UNIFIED DOD-INDUSTRY INTERFACE
  - DEVELOP "CORE" OF INTERFACE STDS, FUNCTIONAL SPECS
  - SERVICES USE AS COMMON POINT OF DEPARTURE IN CONTRACTS
APPROACH TO DOD-WIDE INTEGRATION

CALS FRAMEWORK (DEC 86)

PHASE 1
CORE REQUIREMENTS

PHASE 2
CORE REQUIREMENTS

SERVICE/DLA PROCUREMENT PRACTICES

WEAPON SYSTEM DATA PROCUREMENTS

DATA SYSTEM PROCUREMENTS
CALS PHASE I "CORE"

- LIMITED TO A FEW MAJOR APPLICATIONS, CURRENT TECHNOLOGY
  - SPARES PROCUREMENT, MAINTENANCE, LSA

- REQUIREMENTS PACKAGE WILL INCLUDE:
  - STDS FOR DATA INTERCHANGE (E.G. MIL-STD-1840+)
  - STDS FOR COMMUNICATION (E.G. GOVT OSI SPEC, DDN)
  - TAILORED MIL-STD REQUIREMENTS (E.G. MIL-100/1000, 38784)
  - SAMPLE CONTRACT LANGUAGE (E.G. RAMCAD, ONLINE LSA)
  - APPLICATION AND USE GUIDANCE FOR PM’s

- WILL BE TAILORED BY SERVICES, IMPLEMENTED IN CALS R&D WEAPON SYSTEM DEMOS
LOGISTICS INFORMATION MODEL
FOR
ELECTRONIC EQUIPMENT
OBJECTIVES

1. Determine the information types needed to support logistics applications.

2. Identify information types that are available from engineering design process, and particularly from automated part of that process.

3. Determine applicability of existing standards both for automated information transfer and paper definition.
LOGISTICS INFORMATION MODEL

LOGISTICS APPLICATIONS

INFORMATION TYPES

EQUIPMENT LEVELS OF INDENTURE
SEVERAL GROUND RULES

. Biased logistics application viewpoint (i.e., generally top down)

. Analog and digital applicability

. Minimize conceptual differences between levels

. Goal is to collapse matrix as much as possible

. Identify and capture primary information that is inherent in the design process
PRODUCT DESCRIPTION

SYSTEM VIEW
1.1 SCHEMATIC SYMBOLOGY
1.2 CONFIGURATION/NETLIST
1.3 ORIENTATION STRUCTURE

SPECIFICATION VIEW
2.1 FUNCTIONAL
2.1.1 PERFORMANCE
2.1.2 LOGIC
2.1.3 ALGORITHMIC

2.2 NO. FUNCTIONAL
2.2.1 TEST REQUIREMENTS
2.2.2 TEST VECTORS
2.2.3 ALGORITHMIC

MECHANICAL VIEW
3.1 PACKAGE DRAWINGS
3.2 PACKAGE INTERFACES
3.3 INSTALLATION DATA

PARTS VIEW
4.1 MODEL DESCRIPTION
4.2 DATA SHEET ITEMS (MIL-H-38510)
4.3 THERMAL CHARACTERISTICS
4.4 RELIABILITY CHARACTERISTICS
4.5 SAFETY INFORMATION
4.6 OPERATING RANGE/CONDITIONS/LIMITATIONS

MANUFACTURING AND FABRICATION VIEW
5.1 ASSEMBLY DRAWINGS
5.2 ASSEMBLY NOTES
5.3 LAYOUT DRAWINGS/PROCESS MASKS
5.4 PATTERN GENERATION/HYMERICAL CONTROL DATA
5.5 PROCESS DESCRIPTION
5.6 DESIGN RULES
5.7 MATERIALS

EMBEDDED SOFTWARE VIEW
6.1 SOFTWARE/FRMWARE SPECIFICATION
6.2 EMBEDDED SOFTWARE PROGRAM LISTING
6.3 NCOVLA PROGRAMMING CHARTS
EXAMPLES OF
LOGISTICS APPLICATIONS

- Spares reprocurement (form fit/function or build to print)
- Automated special purpose test design (hardware, software)
- Logistic support analyses (i.e., spares quantity estimates, maintenance manpower skills estimates)
- Trouble shooting documentation
ELECTRONICS
INFORMATION MODEL DEVELOPMENT STEPS

- Meet with standards groups to identify electronic information types that have standards or where standards are being developed

- Meet with applications groups to identify information type needs

- Sort out primary information types from derived

- Publish initial electronics information model Sept 1987
QUESTIONS

- Approach
- Participation
- Schedule
EDIF Version 200 takes on production environment

The newly revised Electronic Design Interchange Format polishes the old standard and tries to meet the challenges of the production environment head-on.

Say goodbye to Version 110 of the Electronic Design Interchange Format: a soon-to-be-released Version 200 of the EDIF is tackling housecleaning chores as well as conquering some new territories. Vowing to clear up ambiguities in the document itself, the EDIF Technical Committee has been making structural, syntactical and semantical changes. In this emerging version, even some minor, seemingly unimportant changes were made to anticipate future needs. Besides this primping and polishing, the 200 release provides the foundation for upward compatibility between EDIF editions, and perhaps most importantly, stakes out the demanding, day-to-day design issues of the production environment.

The most obvious changes are the restructuring and rewriting of the EDIF document. The entire specification has been rewritten by a single author to ensure a more comprehensive, cohesive document than is usually possible when several writers are involved. As before, a committee generated the technical content, but one author was responsible for pulling all the facts together. In addition, many independent users, who are currently working with EDIF or will be involved with future extensions, had the opportunity to comment on the revision. Their reviews, coupled with those of a full-time technical editor and several subcommittees, helped clear up obscure or confusing sections of the 110 version. As a result of these efforts, the syntax of the EDIF text was extensively reworked.

Most of these changes are attempts to make the syntax upwardly compatible, but the committee addressed context sensitivity and other problems as well. Context sensitivity arises when a single keyword is used for more than one function and the semantic interpretation of the object depends on the location of the keyword in the file. Because the problem of multiple usages is often extremely hard to resolve without ambiguity, they’ve been removed. Of course, using a keyword (such as Rename) in two or more places for the same function doesn’t create problems and occurs frequently.

A major structural problem in Version 110, however, is that the names of ports share the same namespace as signal groups: consequently, it’s impossible to define a port named “A” and a signal named “A” as two different objects. As part of the
solution, the keyword Define was removed. A more
systematic object-naming scheme, and a universal
rule, called Define-before-use, replaces the original
keyword.

In an object-naming scheme, many of the key-
words are already related to actual or abstract
design entities such as an IC part. Since the design
object has a definite and unique reference name
within the design, this name is reflected within the
EDIF file. A formal method has been devised to
point to the name unambiguously from anywhere
in the file. This naming of objects is commonly
used in data bases and description languages as well
as in the 110 version. The 200 release, however, im-
proves this procedure, adding more regularity and
consistency.

Any keyword with a named identifier is defined
to create (Namedef) or to reference a name
(Nameref). The creation of a name also gives rise to
a new (hidden) namespace so that the name can be
referenced from outside its own space as in previous
EDIF versions.

Meanwhile, Define-before-use anticipates and
resolves many potential problems. One of its useful
functions is that it eliminates the possibility of
creating either instance or name reference loops.

Since the names are all defined at a higher level of
the hierarchy, this nondefault reference mechanism
doesn't prevent users from including graph-type
cross references.

As part of the general cleanup, a standard order-
ing of arguments has been adopted and symbolic
constants have been either removed or isolated
within a special keyword. The committee also
defined a new property mechanism and developed
a generic identifier that renames or displays an ob-
ject name.

Semantic changes
Looking at revisions to EDIF semantics, views such
as Masklayout and Symbolic were untouched,
whereas Net List and Schematic saw major addi-
tions and modifications. Although the Behavior,
Document and Stranger views have no addition as
yet, some parts have been removed on a triall basis.
New views, focusing on some new features, include
Pcblayout, which targets the layout problems of
printed circuit boards. It's similar to a Masklayout
view aimed at integrated circuits. EDIF 200 also
boasts a view with "dumb" or annotative graphics,
such as logos, page borders and copyright notices,
called Graphic.

Another major revision is the introduction of
multiple-page schematics as a page construct in the
Schematic view. Using this modified view, an off-
page connector can be viewed as a port-like object,
which can be referenced only within the contents of
the cell. Because the name can be referenced by
every page within the contents, all page connectors
can be joined with the same name in the cell. En-
gineers will also be able to handle reference designa-
tors. This feature is commonly used in the design of
printed circuit boards.

Committee members restructured the Net List
view even more than the schematic section. Remov-
ing Signalgroup, they then added a true net con-
cept, which includes the ability to define a
bus-and-bundle object. With the new net concept,
Earlier EDIF version. One of the major issues concerning production readiness. This is especially important with a format such as EDIF, which must change and grow as the underlying technology evolves. Version 200 is expected to allow limited upward compatibility in the near future. The plan is to designate certain keywords and groups of keywords as upward compatible or frozen. While much of EDIF Version 200 appears to meet the necessary criteria, the version must be thoroughly tested in actual use before this can be proven with any confidence.

Upward compatibility can be interpreted in a number of ways. For EDIF it means that—subject to certain restrictions—software for future EDIF versions can read and correctly interpret design data of older EDIF versions. Easing the transition from one version to another, this level of upward compatibility provides a stable base to explore and exchange research-oriented data.

Of more interest to industrial users, however, is design flexibility. With an upwardly-compatible standard, these users need the hardware and software of the earlier design for future revisions. Instead, modern design tools can revise the archived edition.

A number of rules must be followed by all parties to ensure that both complete and accurate interpretation of the design information will occur. Several of the most important restrictions apply to the software that writes the EDIF file. User-defined extensions, such as Userdata or User properties, can't be used. Since their semantic definition is set entirely by agreement between third parties, these extensions or properties may be considered obsolete at any time.

Care must also be taken to ensure that semantic and syntactic extensions preserve the validity of the earlier EDIF version. One of the most obvious rules is that revisions can't delete keywords that are currently defined. On the other hand, it would not be desirable to have so many keywords that a high percentage rarely serve a purpose.

In response to these potential problems, the revisionists altered the structure of the older 110 as well as the 200. Some limits are mostly stylistic; syntax for keywords, for example, must be consistent throughout the text and conform to the underlying structural model, or meta-syntax, so that systematic analyses can be performed during review. By far, most of the syntax changes for Version 200 fall into this category.

Another class of changes involves fixed or required fields. They must now appear in the following order: name define, name reference(s), required fields in fixed positions and optional structures, which may appear in any sequence. To maintain upward compatibility, only optional fields can be added to any previously defined construct. Similarly, a field that is currently optional can't later become mandatory.

Fortunately, however, adding optional fields isn't difficult. And tacking on required fields after a structure has been defined is rarely necessary. When such an addition is needed, it's caused by some fundamental change in the underlying semantics of the construct and should be handled by adding a new construct. Upward compatibility, by making it impossible to simply change an old construct, just forces users to analyze the situation more carefully.

Implications of ordering

Coming to terms with the semantic implications of ordering has more subtle traps. In this case, additional or changed technology can require more semantics. Unfortunately, these semantics can't be added without damaging the existing format. For this reason, the list of optional fields is always a single string with more keywords added to make any interpretation syntactically explicit regardless of ordering. Sometimes, however, keywords are defined that contain only one or two objects with a semantic interpretation that is obvious to current technology without the keyword.

For engineers who develop interface software for EDIF, upward compatibility provides other advantages. Since the software that created an EDIF file is usable for a longer period of time, much of the work involved with revising an interface to a new version is spared. The software that reads the file will have to be modified for the new revision, however, since information contained in new keywords would be lost and the user would have no way to determine its importance.

While the changes are quite extensive, some care has been taken to minimize the overall impact on existing code. The most extensive modifications occur, in fact, at a very low level of structuring (ordering, for example). As a result, the majority of the changes should be possible without extensive software revisions.

computer design: November 15, 1984
The lesson of the Swiss cheese makers

This is a story about some cheese makers who created a method to exchange the specs of their cheeses. The cheeses came in two shapes: square and flat. Some had round holes, some had oval holes and some had no holes at all. To describe these features, the cheese makers developed the Cheese Definition Interchange Protocol, popularly known by the partial acronym CheeseDIP. Based on a Lisp syntax it looked something like:

\[
\text{CheeseDIP} \::= \text{[cheese][holes]}
\]

\[
\text{Cheese} :: \text{SQUARE/FLAT}
\]

\[
\text{Holes} :: \text{ROUND/OVAL}
\]

With this syntax, any number of cheeses could be specified in any combination of legal shapes, with any number of holes, it even was possible to combine round and oval holes for special orders. But the syntax overlooks one obvious point: The square and flat characteristics make sense only for the shape of cheeses, not holes.

When someone invented a process that produced square holes, CheeseDIP had to be extended: \(\text{Holes} ::= \text{ROUND/OVAL/SQUARE}\). Almost at once an order was received for a cheese that looked like this: \((\text{CheeseDIP} \text{(Flat ...)} \text{(Square ...)} \text{(Round...)}\)

At great expense, a single flat cheese was made with both square and round holes (a novel variation never tried before), as specified by the customer’s CAD system. Only then did it discovered that the customer had really wanted two quite ordinary and inexpensive cheeses—a flat cheese and a square cheese with round holes!

Unfortunately, it’s not possible to include square holes at this point because it won’t be recognized by the older version of CheeseDIP. The strange keyword SQUAREhole could be used, but this would quickly lead to a huge number of strange keywords defined with identical semantics. Most would be used in only one specific application or not at all. To introduce keywords for cheese and holes or impose some other form of ordering would make older files, which were written without these new rules, obsolete.

The moral of the story is that even though a standard may have a well-defined set of contained objects and may suit current technology perfectly, anticipating the needs of future technologies is more difficult. EDIF, therefore, must avoid any similarly implied assumptions and maintain a close correspondence between keywords and objects—despite the fact that current technology doesn’t require such fine distinction.

In addition, the use of any order-dependent list imposes rigidity upon a structure that can hide deeper problems. To the casual user, this introduces many extra keywords, which serve only to contain one or two other keywords. The other possible consequence is a random ordering of objects that can be confusing and, in any event, serve no purpose in the context of current technology.

By Paul Stanford, a senior software engineer and Texas Instruments’ representative to the EDIF Technical Committee.

Version 200 is certainly not the end of EDIF development. Rather, it’s the end of the beginning. Each technical subcommittee has prepared proposals that must now be tested with real designs before inclusion in the next version of EDIF. Currently, there are proposals concerning behavioral modeling, physical design rules, procedural extensions and process-dependent descriptions. In keeping with EDIF’s development philosophy, this testing will be conducted by those organizations that need the features badly enough to expend the effort and take the risks.

EDIF looks ahead

The future plans from subcommittees are in various stages of development and review. The ongoing testing and reviewing of proposals slated for trial use is one of the major priorities. Most of the proposals in the trial-use document will be incorporated in the next EDIF release. This includes the behavioral proposal, which attempts to provide transportable models and to produce accurate results on a large number of simulators. Also included is the physical design-rule proposal, which will provide the means to move automated design-rule checking between design-verification software.

Once the current proposals for physical design rules are finished, the subcommittee expects to address the problems of electrical design rules. This will include rules for the maximum current density of ICs and limits on voltage levels.

Aside from the efforts of these groups, a new subcommittee will examine the problems of printed circuit board layout. The earliest work in EDIF was oriented toward the problems of IC technology. The new committee will investigate the handling of design data, and to a lesser extent, the treatment of manufacturing and maintenance information.
How do I get started?

To learn more about Version 200, write to the EDIF User Group, 2222 S Dobson Rd, Bldg 5, Mesa AZ 95202. No telephone calls please. Workshops and tutorials concerning the standard are another source of information. Some are offered during the Design Automation Conference and the International Conference on Computer Aided Design. These workshops are one of the best ways to hear about the latest developments and activities and to talk with some of the subcommittee members.

Another option is to become a member of one of these groups. By participating in a subcommittee, you can keep abreast of the most recent information, learn more about implementation problems and influence the features and development of EDIF. Most of the subcommittees meet monthly or bimonthly at locations convenient to their membership.

Another group is examining the problems associated with the EDIF representation of schematic drawings, starting with validation and testing of the current EDIF schematic capability. At the same time, a multinational subcommittee, made up of participants from both the United States and European countries, is examining the problems involved in the transfer of test information. This is expected to cover both interfaces to automated testers as well as more complex issues such as test generation and procedural testing.

Please rate the value of this article to you by circling the appropriate number in the "Editorial Score Box" on the Inquiry Card.

High 264 Average 265 Low 266
## 1. EDIF IN EUROPE

### INTEREST

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This request is for you, a colleague, or your employee to contribute 4 man-weeks of technical expertise to a team effort toward a common information model for electrical products. The expertise needed by the team is the computer applications engineer who has been involved in support of design, analysis or manufacturing of your integrated circuit, printed wiring board or harness products.

As a person involved in computer aided integration of electrical product development, you can appreciate the size of the task. There are many vendor systems, several data transfer formats, and your company concept of a design/tooling data storage organization. The members of the task team expect to benefit from the collective, intensive, full-time identification and documentation of the related information involved in our data systems. With the common information model as a road-map, appropriate structuring or mapping to your own physical data structure will require significantly shorter project completion schedule. Further, cooperation with the applicable neutral transfer formats will establish known information capabilities and encoding guidelines.

The attached form indicates the dates involved and can be used to reserve a place on the team. During the January 5 through February 27, 1987 schedule, only 12 technical expert positions are offered to keep the team size appropriate to effective work. The team is responsible to the IEEE Design Automation Standards Subcommittee, and the NBS Product Data Exchange Specification organizations. Thus the meetings of the team are open if you wish to attend informally. Note also that one week is reserved for training in the modeling technology (IDEF1X). All team meetings will be at the Engineering Building and at Kellogg West Conference Center on the campus. Lodging is available at Kellogg West and nearby hotels.

Time is critical for the organization of this important activity; please identify the appropriate area of your organization and person to best advise and return knowledge of our common information model.

Curtis H. Fisher
for the Cal Poly Task Team
To: Marcia Iannone  
Standards Task Team  
California State Polytechnic University  
Dept. of Electronics and Computers Engineering  
3801 West Temple Avenue  
Pomona, CA 91768-4065

Please include the following technical specialist in your consideration for Task Team members. We understand that as a sponsoring organization, we are responsible for continuing salary for 4 weeks (total) for our accepted team member.* We further agree to release any sponsored member's work completed while on the Task Team, which work shall be considered public domain and publishable by the IEEE.

Technical Specialist_________________________ Manager_________________________

Organization Address_______________________ Address (if different)_____________________

Telephone_______________________ Telephone_______________________

Date_____ Signed________________________ Date_____ Signed________________________

---

Yes, include me in your January 5-9, 1987 Tools Training.

I prefer the January 19 through February 6 information modeling session.

I prefer the February 9 through 27 information modeling session.

In addition to participation, reviews are scheduled to present the information model and receive industry comments. For review interest only, fill in your name and address as technical or manager, and check the appropriate dates:

____ Boston area, March 10-13 (4 days), review and workshop.
____ San Francisco bay area, March 23-27 (5 days), review and workshop.
____ Wright-Patterson AFB, April 13-17 (5 days) presentation and physical database mapping workshop.

*Funds may be available to offset travel and lodging costs. For information call Professor Richard Cockrum, (714) 869-2511.
IPC

- Trade Association
- Formed in 1957 by six printed board manufacturers.
- 1,400 member companies--1986
  --Regular - 28%
  --Allied - 35%
  --Associate - 31%
  --Government & Tech. Liaison - 6%
- International Scope
  --Americas - 71%
  --Europe - 13%
  --Australasia - 14%
  --Other - 2%
- All standards/specifications sent for approval to all IPC official representatives.

PROBLEMS

- Too much implementation flexibility.
- Minimal support by CAD system vendors.
- Industry usage abuse
  --DoD contract horror stories
  --Equipment/not data.
- Inadequate IPC training programs.
- Experience of tri-Service personnel.
- Public domain translator.
LONG RANGE OBJECTIVES

Complete definition of electronic assembly.
Design - Manufacturing - Test - Hard Copy

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L-52
IMPLEMENTATION HISTORY

- Revision A released 1975.
  --First contract issued
  --Industry/DoD coordination meetings
  --ANSI approval

- Revision B started
  --Allowed more flexibility
  --Removed standard font
  --Removed standard land patterns
  --Simplified for small company use

- Coordinated through ANSI Y14.26 Committee.

- Approved for use by DoD
  --Required by MIL-STD-275
  --Required by MIL-STD-2118

- Five-year no-change policy

- Major user - NSA
  --Contract tailoring
  --Input to IPC Committees

- Submitted by US to IEC
  --52(U.S.A.) 122

- Coordination with ICER.
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<td>Mr. Philip L. Major</td>
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<td>Dr. William J. Schultis</td>
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<td>Dr. Victor A. Utgoff</td>
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<td>Dr. Jeffrey H. Grotte</td>
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<td>Dr. Frederick R. Riddell</td>
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<td>Mr. William E. Cralley</td>
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